

Tutorials on thermal conduction experiments

Thermal instrumentation and measurements for micro and nano systems using electrical and optical methods



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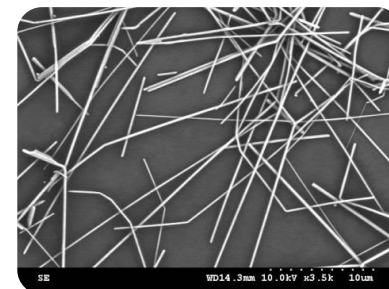
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1. Motivations and prerequisites: physics of electron and phonon heat transfer
2. A page of history: the starting point of thermal measurements in the XVIIth century
3. Thermometry down to the nanoscale: electrical experiments and others
4. DC and AC electrical techniques (3 omega PP, IP, nanowire)
5. Application of the techniques to the nanoscale
6. Nanofabrication of sensors for thermal measurements
7. Near field experiment of thermal conduction
8. Optical methods:
 1. Raman thermometry
 2. Time dependent thermorefectance experiments

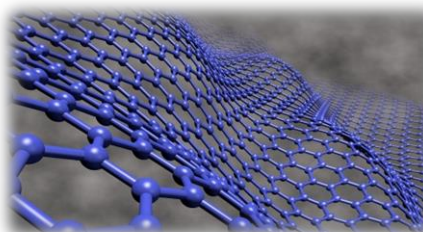
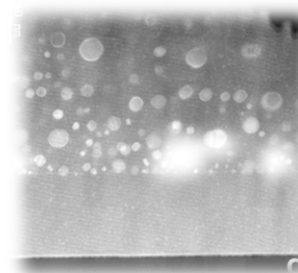
Motivations and prerequisites

- Fundamentals of heat transport at the nanoscale
- Electronic transport
- Phononic transport
- (Photonic transport)=> see Radiative transfer
- Effect of low dimensions on the thermal transport



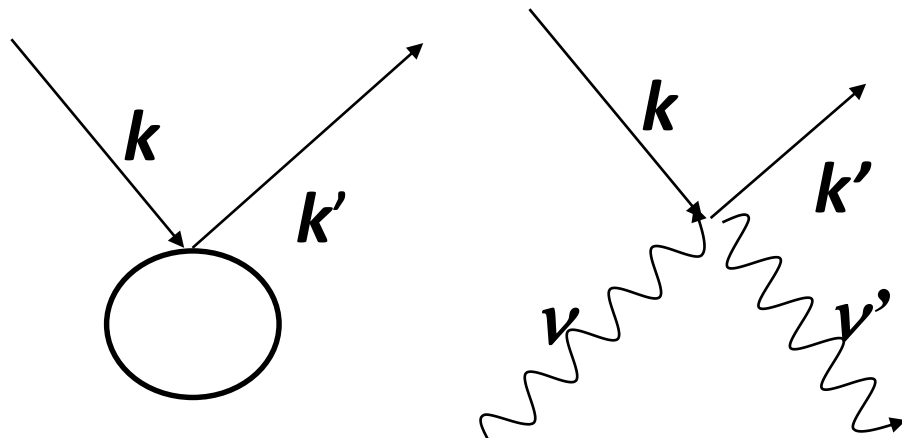
Nanoscale  Small Energy/Power

- Growing need of developing sensitive experimental tools
- Sensitive Tools
- Versatile tools
- Adapted to low dimensions



- Electronic heat transport :
 - Specificities
 - Important length (mean free path, Fermi wave length)
 - Characteristic energy $k_B T$ versus E_F
- Phononic heat transport :
 - Specificities
 - Important length (mean free path, dominant phonon wave length)
 - Characteristic energy $k_B T$ versus $\hbar\omega$

Mean free path



Phonon elastic scattering (impurity)

$$|k| = |k'|$$

Inelastic scattering

$$|k| \neq |k'| \text{ and } |v| \neq |v'|$$

Wavelength

$$E_F = \hbar k_F$$

$$\lambda_{Dom} = \frac{h v_s}{4.25 k_B T}$$

$\Lambda_{e-} \sim \text{nm}$

• Mean free path

$\lambda_F \sim 0.1 \text{ nm}$

• Relevant wave length

T

• Temperature dependence (K, C)

diffusive

• Transport

fermions

• Statistic Fermi-Dirac distribution

Drude model

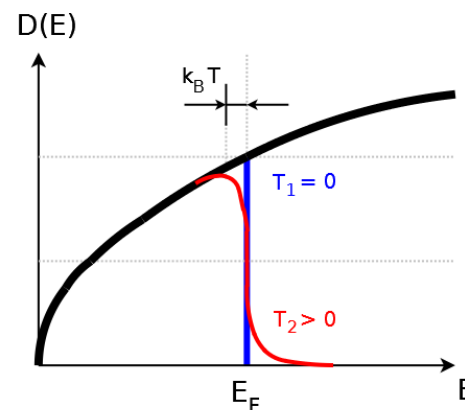
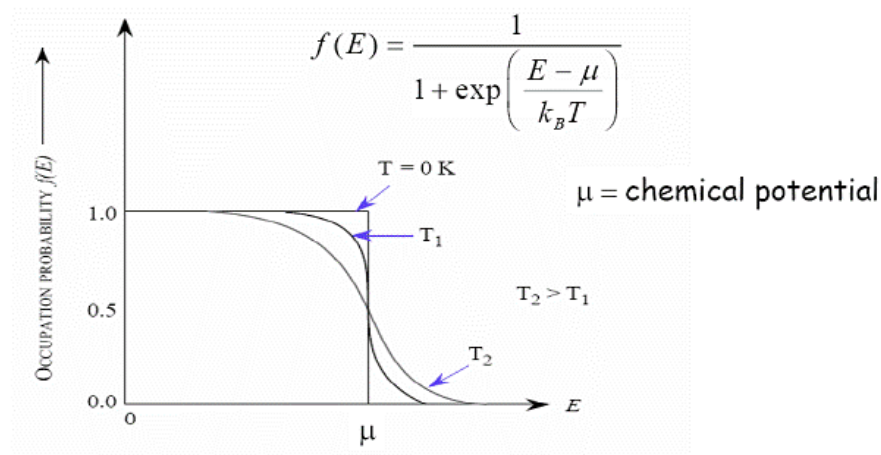
$$\sigma_{e-} = \frac{\tau}{3} e^2 v_F^2 D(E_F)$$

Boltzmann equation $k_{e-} = \frac{\pi^2}{6} k_B^2 v_F^2 \tau D(E_F) T$

Wiedemann Franz law

$$\frac{k_{e-}}{\sigma_{e-} T} = \frac{1}{3} \frac{\pi^2 k_B^2}{e^2}$$

$$k_B T \ll E_F$$



• Mean free path

At 1K
 $\Lambda_{ph} \sim \text{cm}$

At 1K
 $\Lambda_{ph} \sim 500\text{nm}$

• Relevant wave length

$\lambda_{ph} \sim 100\text{nm}$

$\lambda_{ph} \sim 1\text{nm}$

• Temperature dependence
(K, C)

T^3

NA

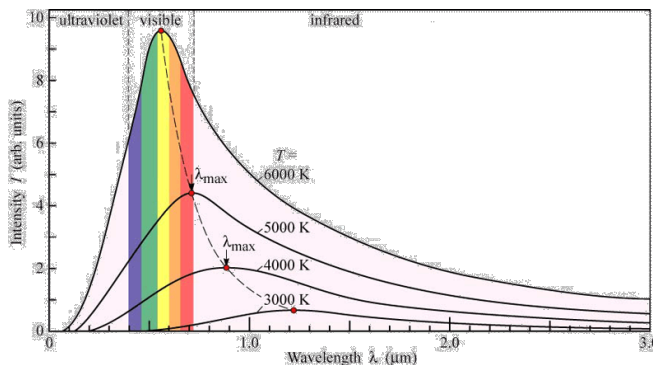
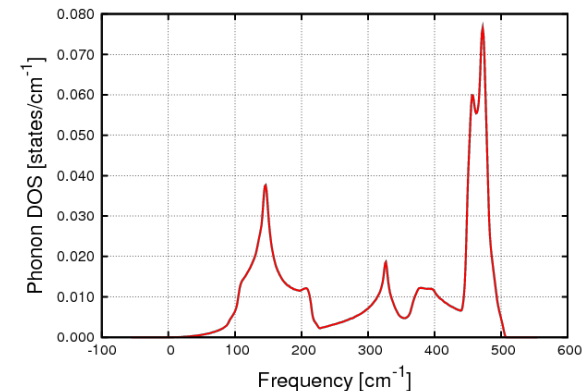
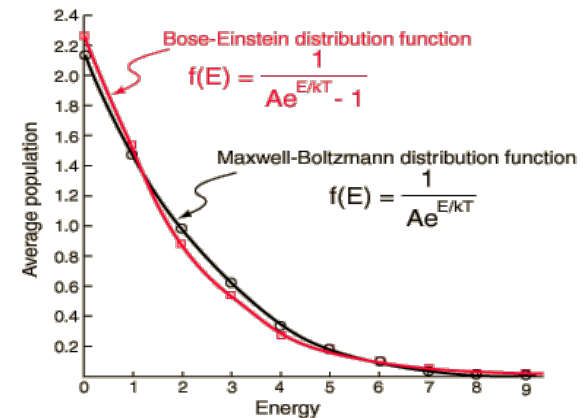
• Transport

Diffusive/ballistic

• Statistic Fermi-Dirac
distribution

bosons

In silicon

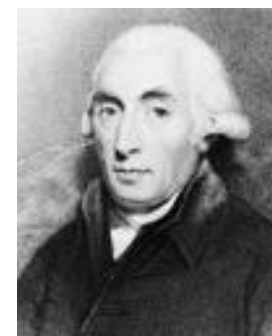


$$\lambda_{Dom} = \frac{hv_s}{4.25k_B T}$$

A page of history

The origin of the C/K concept

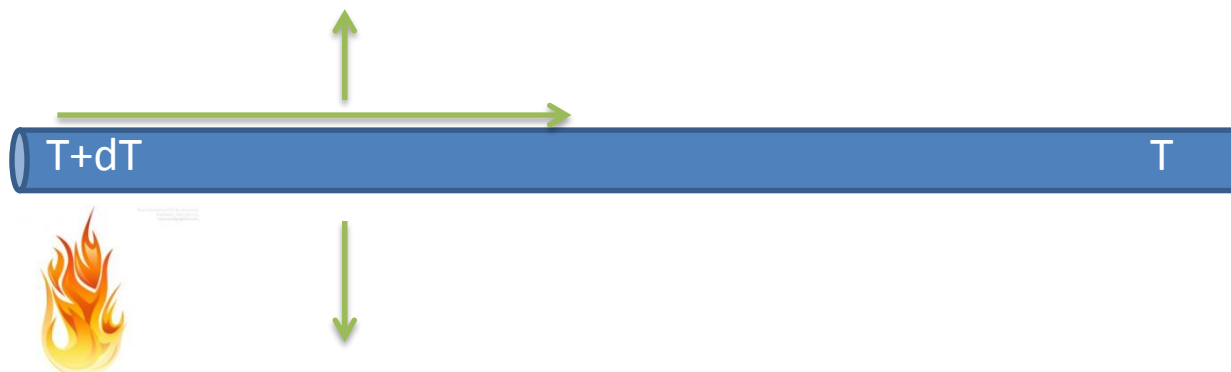
- Early days : Guillaume Amontons (1663–1705): heat flow along the temperature gradient (no thermometer)
- Heat, matter and temperature: Latent heat, Joseph Black (1728-1799)
- First measurements: Jean-Henri Lambert (1728–77) published in 1779 : convection, geometry

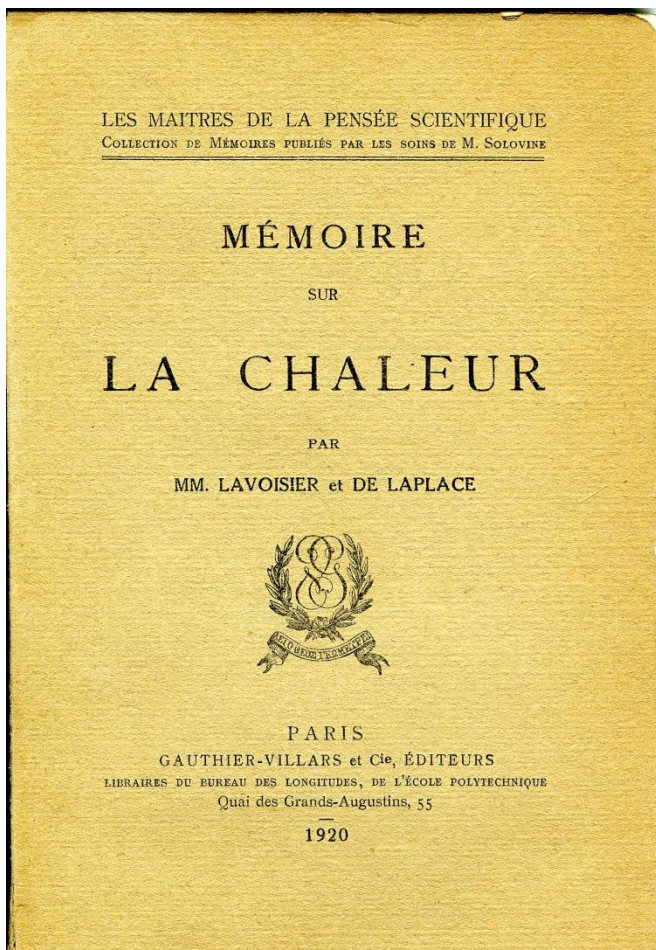


Joseph Black



Jean-Henri Lambert





“Les Physiciens sont partagés sur la nature de la chaleur”

Nouveaux concepts : chaleur libre, capacité de chaleur, chaleur spécifique

“Plusieurs d’entre eux la regarde comme un fluide répandu dans la nature”...

“D’autres physiciens pensent que la chaleur n’est que le résultat des mouvements insensibles des molécules de la matière.”

Lavoisier et Laplace (Mémoire sur la chaleur 1780).



Pierre Simon de Laplace



Antoine Laurent Lavoisier

- Treatise on calorimetry published in 1782
- First experiment of heat capacity
- Ice calorimeter (temperature reference)



L (latent heat ice/water
at $T = 0^\circ\text{C}$)

$$= 334 \text{ J/g} \approx 80 \text{ cal/g}$$

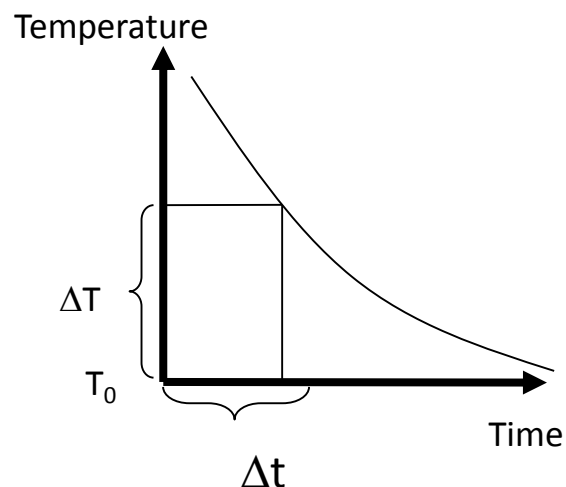
L (latent heat
water/water vapour at
 $T = 100^\circ\text{C}$) = $2260 \text{ J/g} \approx$
 539 cal/g

- Benjamin Franklin (1706-1790) compared thermal conductivity of different metals
- Jan Ingen-Housz (1730-1799)
- Count Rumford (1753-1814) insulating materials
- Joseph Fourier (1768-1830)



Joseph Fourier

2 experiments: steady state (K,h), transient (C,h>>K)



$$\tau = \frac{C}{K}$$

Time dependent experiments:

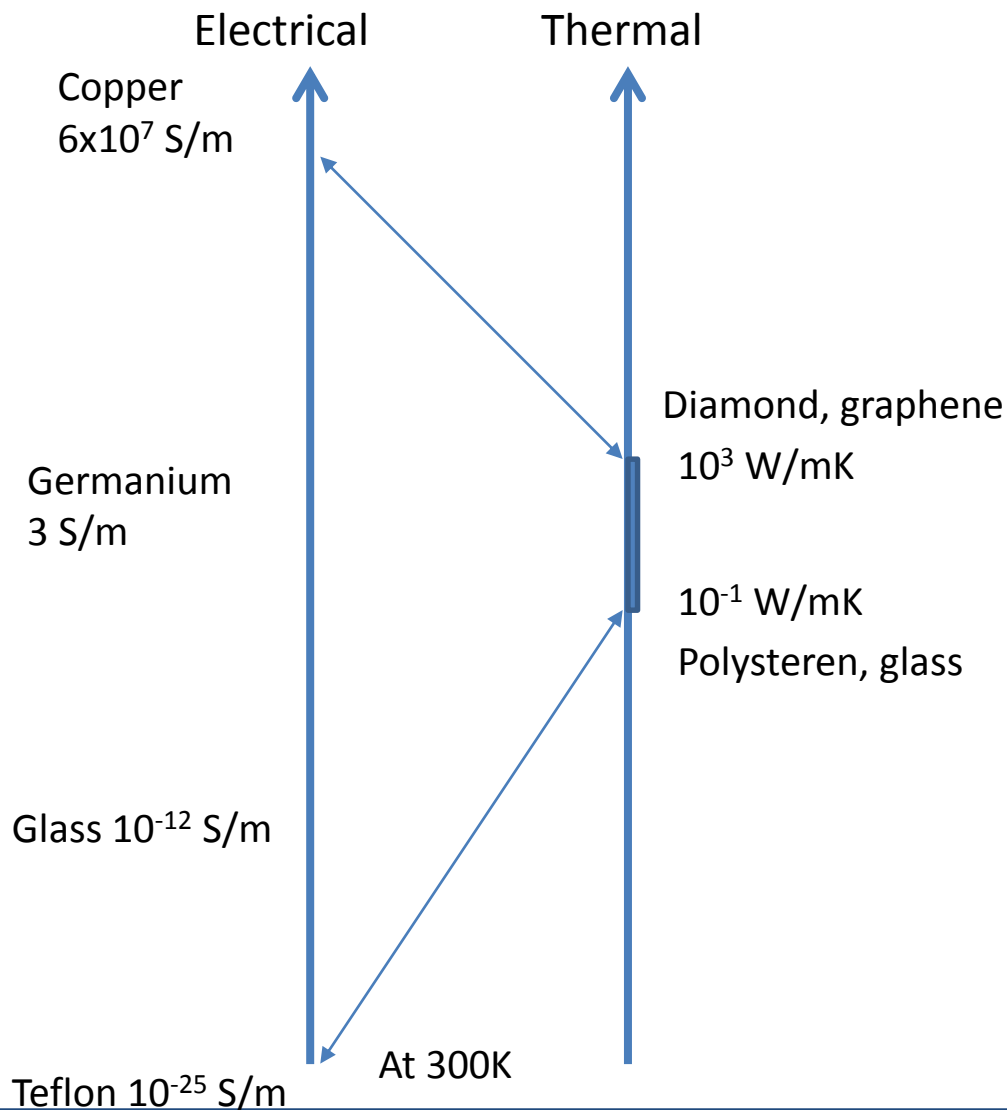
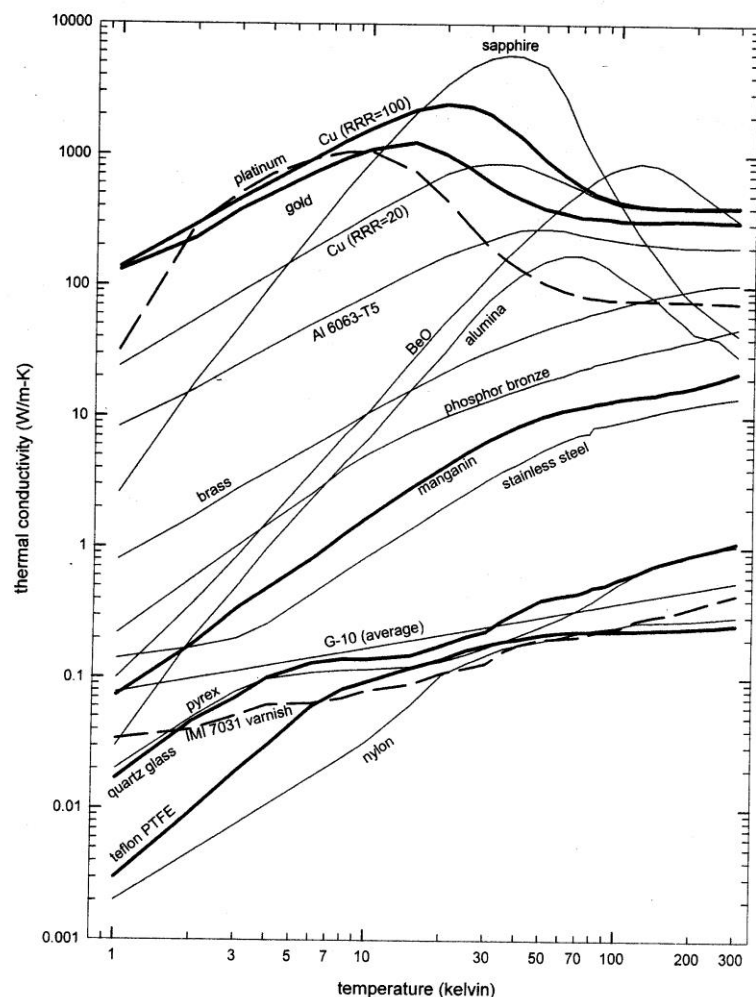


Thermal conductivity through the 19th century
T. N. Narasimhan

Physics Today **63**, 36

(2010)

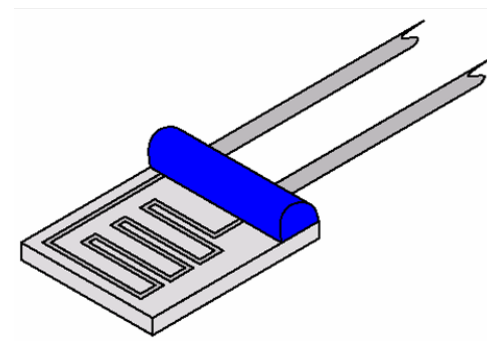
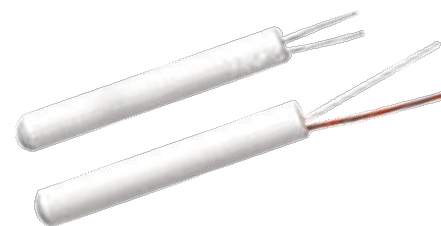
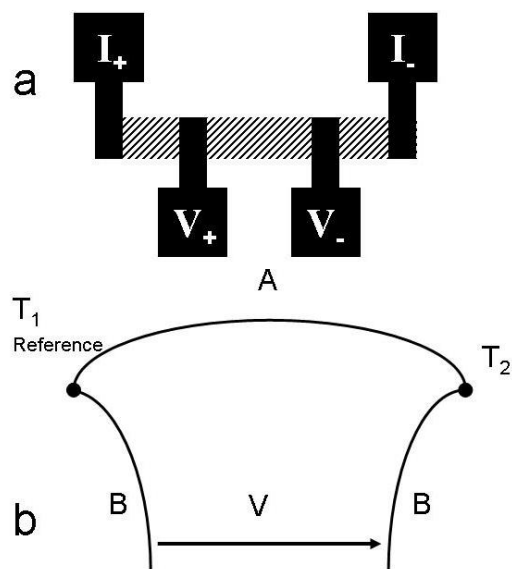
From 1807 to 1811, Joseph Fourier conducted experiments and devised mathematical techniques that together yielded the first estimate of a material's thermal conductivity. His methodology has influenced all subsequent work.



Thermometry down to the nanoscale: electrical experiments

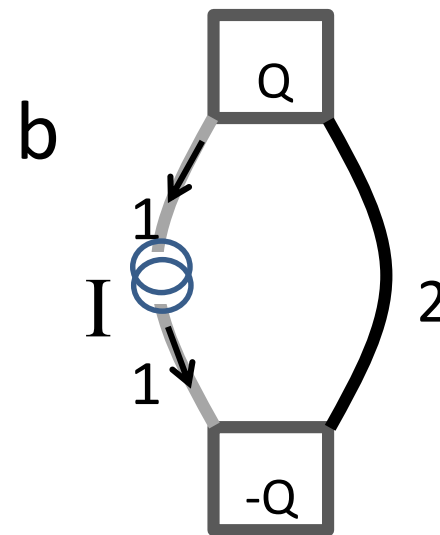
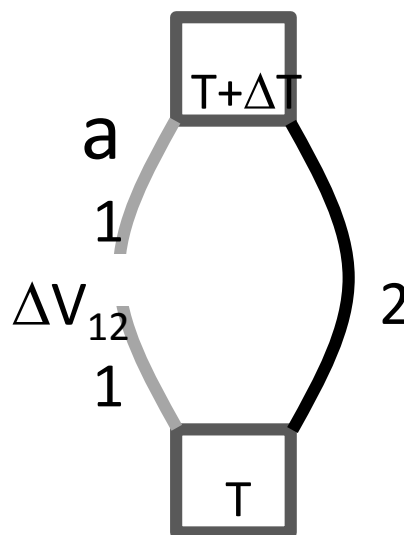
- Sensitivity of experiment: temperature coefficient
- Resistive thermometry (thin films)
- Thermocouple
- 4 wire measurement: separate the current and voltage leads
- Not primary thermometer, need calibration

$$\alpha = \frac{1}{\Psi} \frac{\partial \Psi}{\partial T}$$

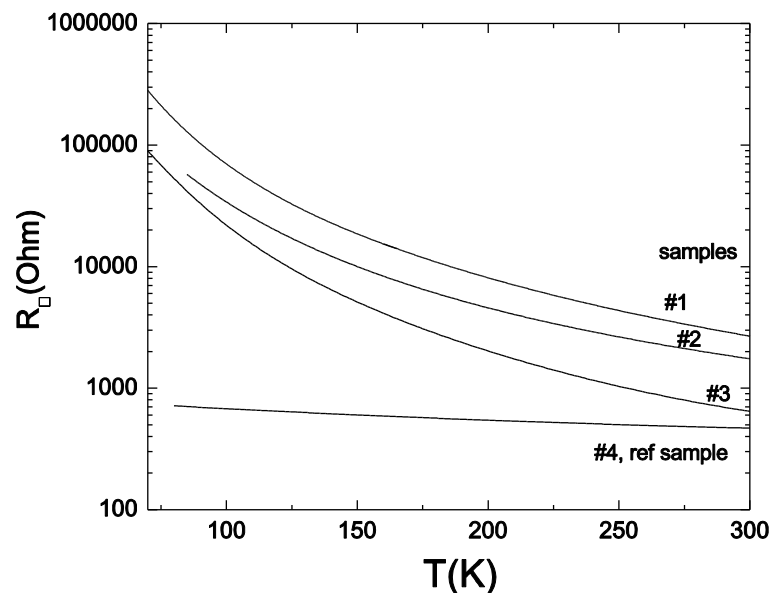
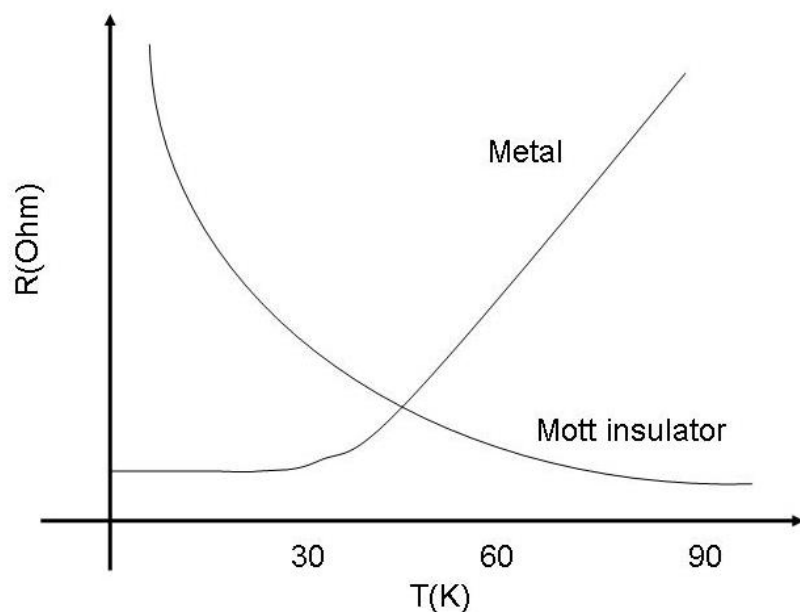


- Involve two materials (1 and 2)
- $\Delta V = 200 \mu\text{V/K}$
- CrNi/AlNi
- Can be lithographed and down scaled
- Au/Cr

Metal	Seebeck Coefficient ($\mu\text{V/K}$)
Al	-1.66
Au	1.94
Cr	21.8
Ni	-19.5



- Metal (Pt, Au, Ni) Temp=40K-1500K
- Semiconductor (Ge, Si) 0K-50K
- Mott-Anderson insulator (Metal to insulator transition: NbN, NbSi, AuGe) 0K-400K



For NbN thermometry Bourgeois et al., Review of Scientific Instrument **77**, 126108 (2006)

- Platinum: versatile, low impedance, thin films, can be downscaled, for temperature above 50K
- Germanium thermometer: very sensitive, macroscopic
- NbN or NbSi: very sensitive, versatile, high impedance, thin films only, can be downscaled, wide temperature range (0-400/500K)

$$\alpha = \frac{1}{\Psi} \frac{\partial \Psi}{\partial T}$$

Thermometer	High temp	Low temp	α at room T	α at 1K	Scalability at the nanometer	Impedance
Platinum	✓	✗	2×10^{-3}	✗	✓	100
Germanium	✗	✓	✗	-10	✗	1000
NbN, NbSi	✓	✓	-1×10^{-2}	-1	✓	1000

Calibration needed !!

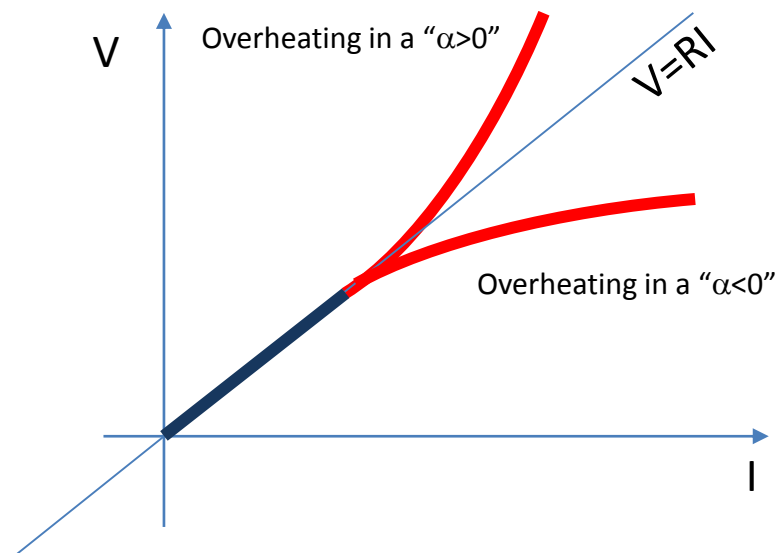
- DC measurement: current source and voltmeter
- DC Offset
- Low temperature

$$\frac{V(I_+) - V(I_-)}{2}$$

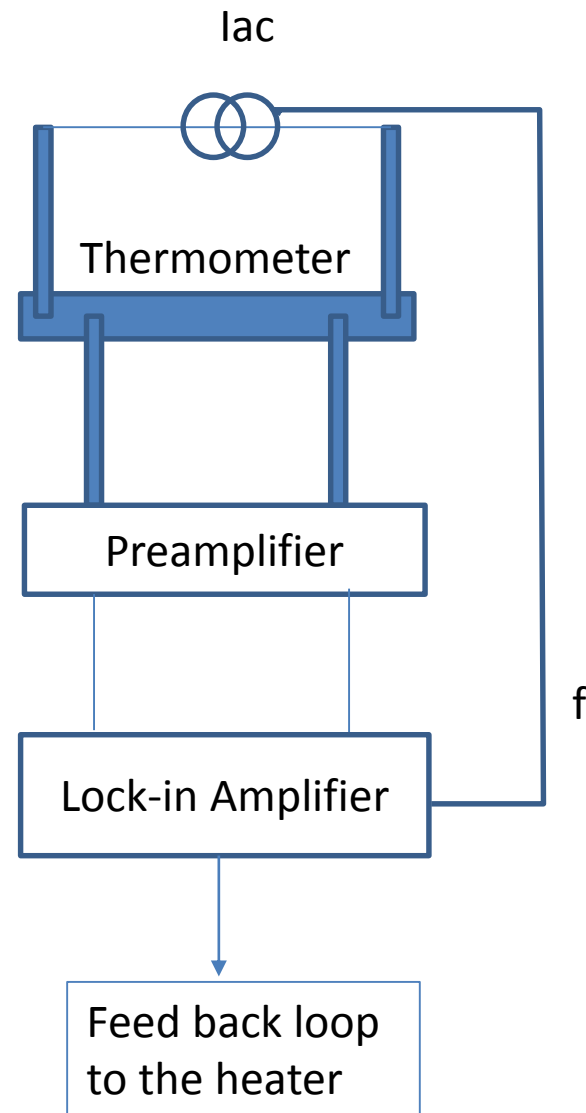
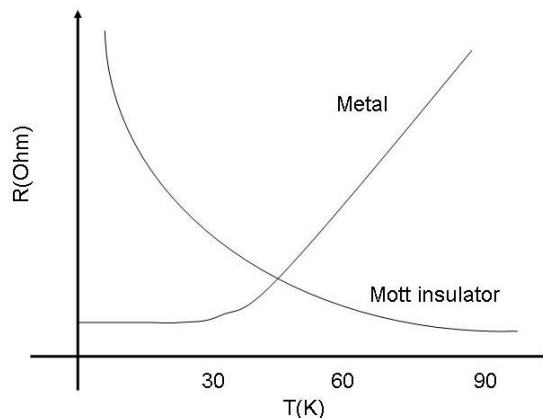
- AC measurements (lock-in Amplifier)
- Experimental set-up more evaluated
- 3 omega method, ac calorimetry (2ω)

Error coming from overheating of the thermometer

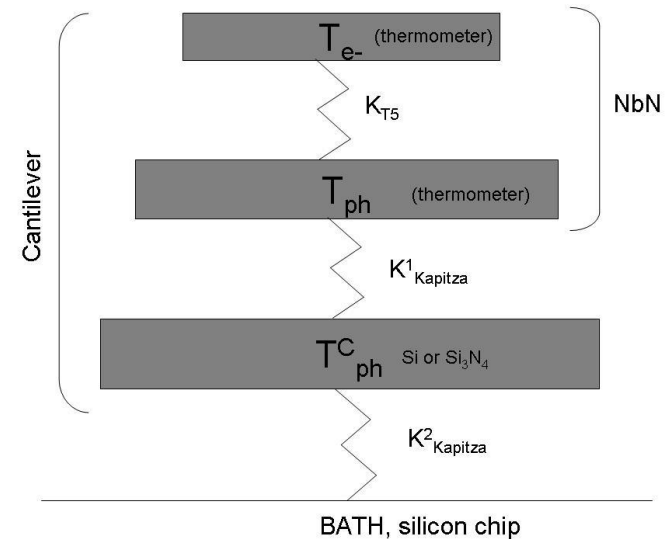
$$P=RI^2 \text{ or } P=V^2/R$$



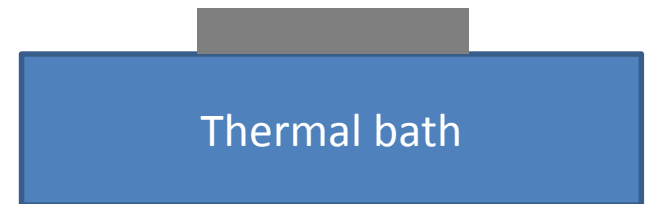
- Resistive thermometer
 - If $\alpha > 0$ (Platinum)
Regulation with voltage $P = V^2/R$
 - Regulation in current (avalanche)
 - If $\alpha < 0$ (germanium)
Regulation with current $P = RI^2$
 - Regulation in voltage (avalanche)



- Sensitive measurement of the temperature
- Temperature measurement as close as possible to the system
- Decoupling: short time scale or low temperature
- Kapitza resistance
- Acoustic Mismatch Model (AMM) and Diffusive Mismatch Model (DMM)



$$K_{Kapit}^1 = \frac{T^3}{12} \text{ W/K}^4 \text{ cm}^2$$



See Swartz and Pohl *Rev. Mod Phys* **61**, 605 (1989)

- Measurement of the electron temperature
- Under low electric field

$$T_{e^-} - T_{ph} = \frac{P_{e^-}}{K_{e^-/ph}} = \tau_{e^-/ph} \frac{V^2}{RC_{e^-}}$$

- High electric field

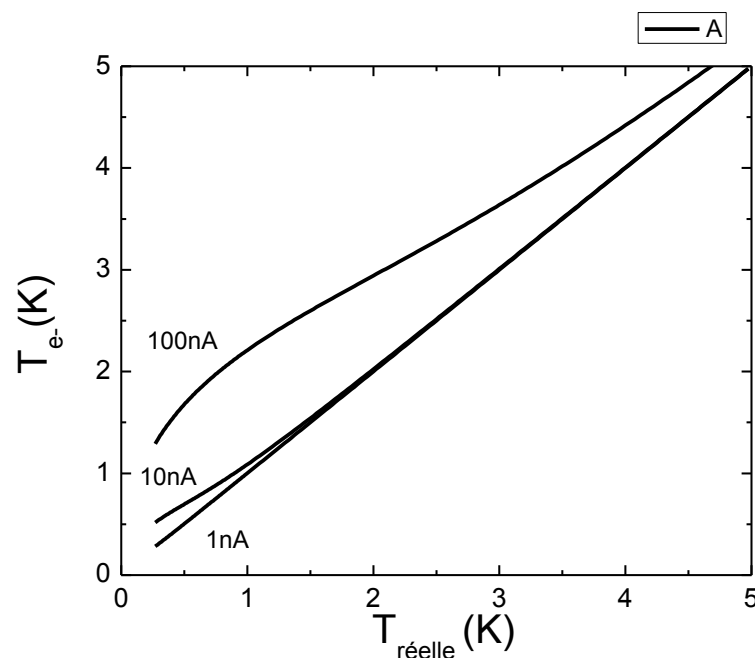
$$T_{e^-}^n - T_{ph}^n = \frac{P_{e^-}}{V g_{e^-/ph}}$$

- Work with high impedance thermometer

e^- -phonon coupling constant ($g_{e^-/ph}$)
 $1000 \text{ W/K}^5 \text{ cm}^3$

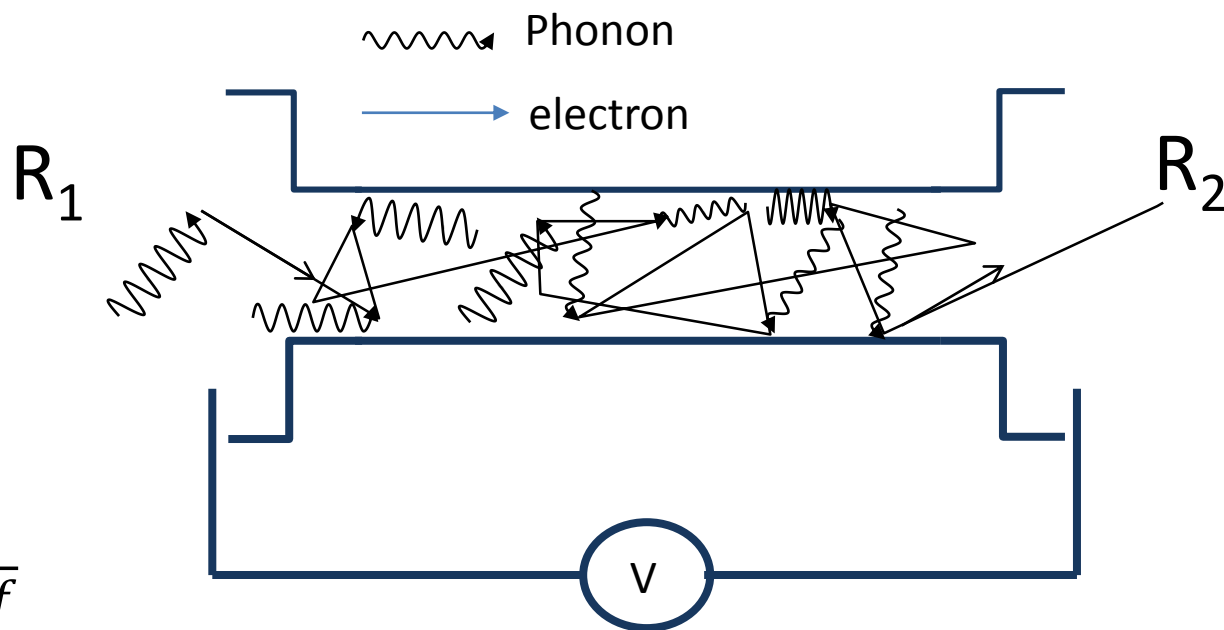
Exercise: thermometer of 50nm, 100nm large, 10mm long
 $R=200 \text{ k}\Omega$, $I_{ac}=1 \text{ nA}$, $T=0.5 \text{ K}$, $\Delta T=??$

Answer 4mK



Example : silicon nanowire

- **Noise thermometry** ("The noise is the signal" Rolf Landauer
Nature **392**, 658-659 (16 April 1998))
- Universal thermometry !!



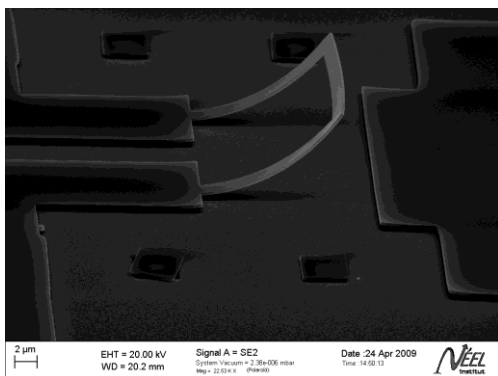
$$V \left(\frac{\text{Volt}}{\sqrt{\text{Hz}}} \right) = \sqrt{4k_B T R \Delta f}$$

$$\alpha \sim \frac{1}{T}$$



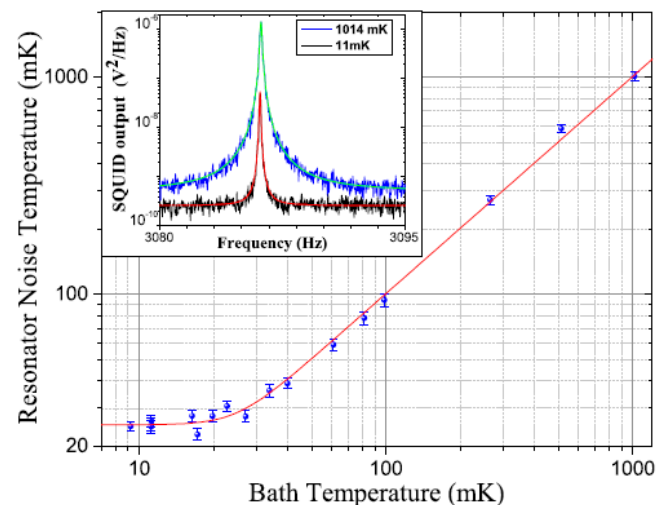
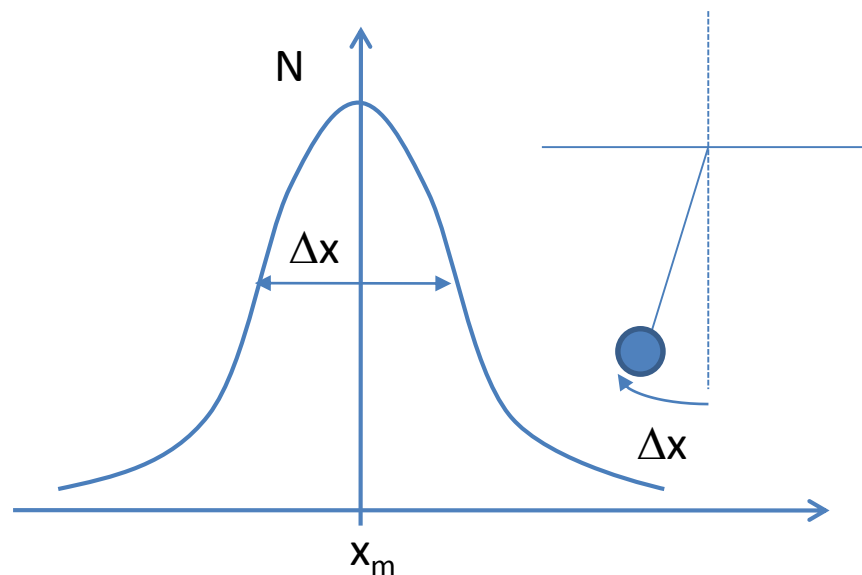
Low temperature

- Measurement of thermal noise
- Vibration of a cantilever : NEMS
- No thermometer needed, universal thermometry $\text{FWHM} \sim k_B T$
- Macroscopic measurement of the global temperature of a beam
- Phonon thermometer !!



$$\frac{1}{2} k \langle \Delta x^2 \rangle = \frac{1}{2} k_B T$$

$$\langle \Delta x^2 \rangle = \frac{k_B T}{m \omega_0^2}$$



APPLIED PHYSICS LETTERS 98, 133105 (2011)

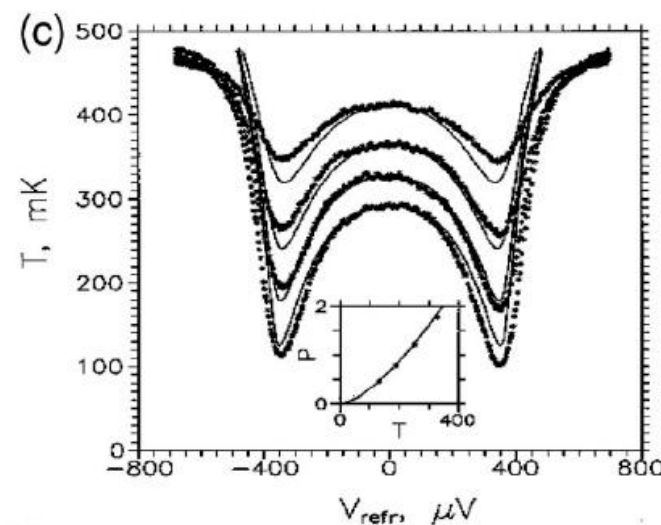
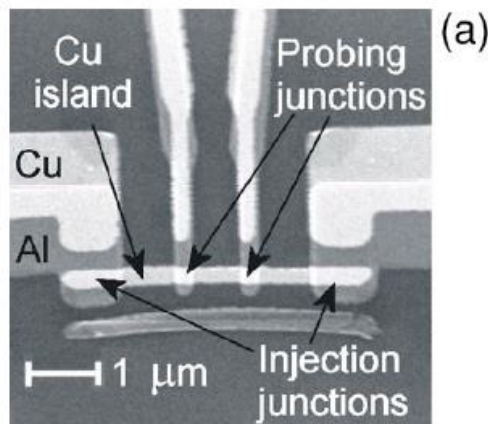
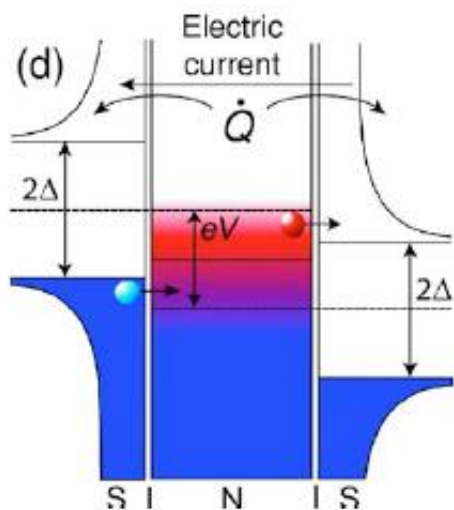
REVIEWS OF MODERN PHYSICS, VOLUME 78, JANUARY 2006

Opportunities for mesoscopics in thermometry and refrigeration: Physics and applications

Francesco Giazotto*

*Low Temperature Laboratory, Helsinki University of Technology, P.O. Box 2200,
FIN-02015 HUT, Finland*

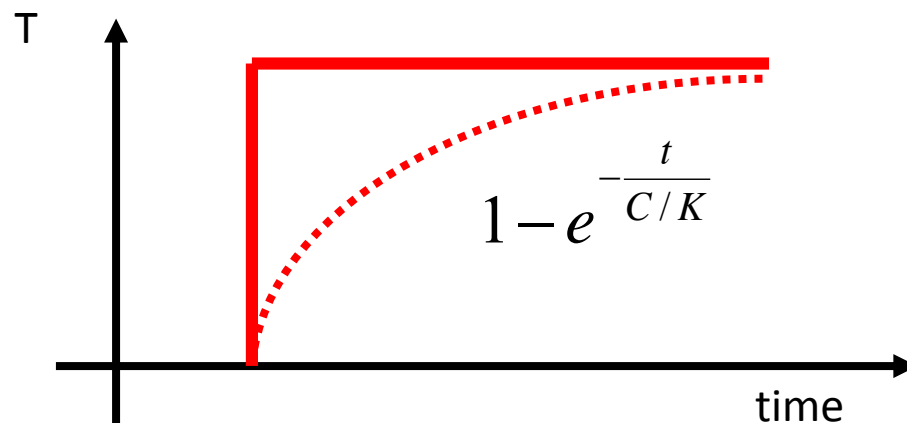
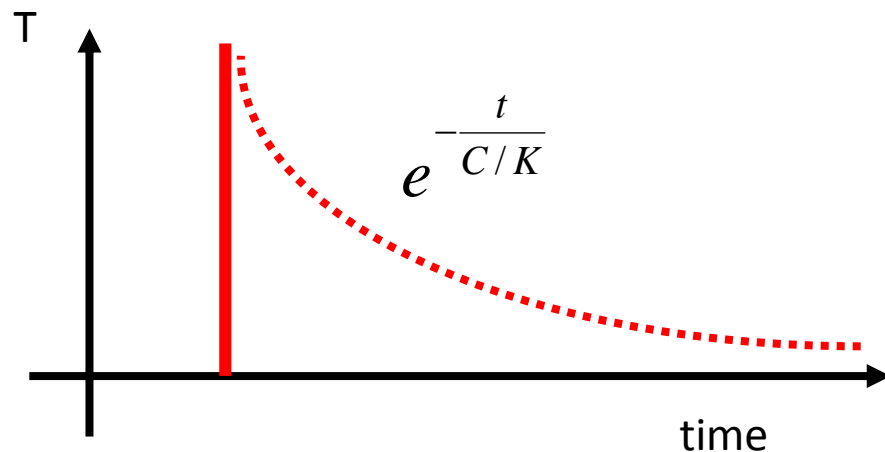
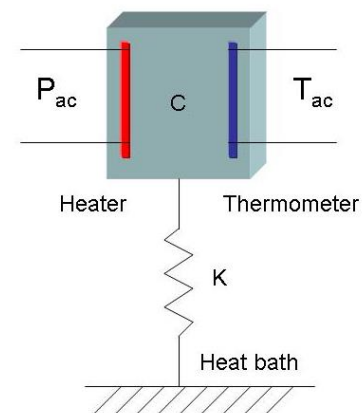
and NEST CNR-INFM and Scuola Normale Superiore, I-56126 Pisa, Italy



C/K

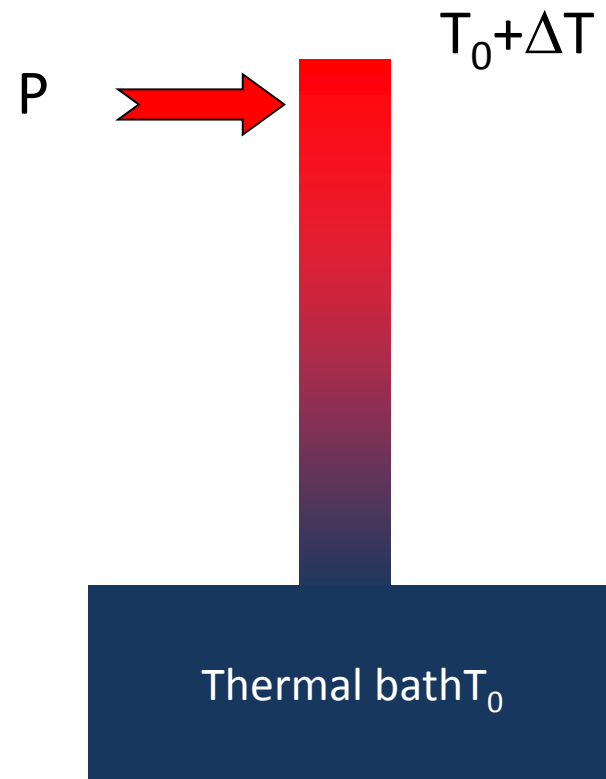


- Heat Pulse: exponential decrease of the temperature
- Heat step function: measurement of the thermalization of the system
- $\tau = C/K$
- Two properties can be measured C and K



- Known power
- Measure of ΔT
- K is a mean value integrated over ΔT
- Dynamic measurement by modulating P
- Nanowire ??
- Connection to heat bath and to the thermometer
- Thermal contact

$$K = \frac{P}{\Delta T}$$

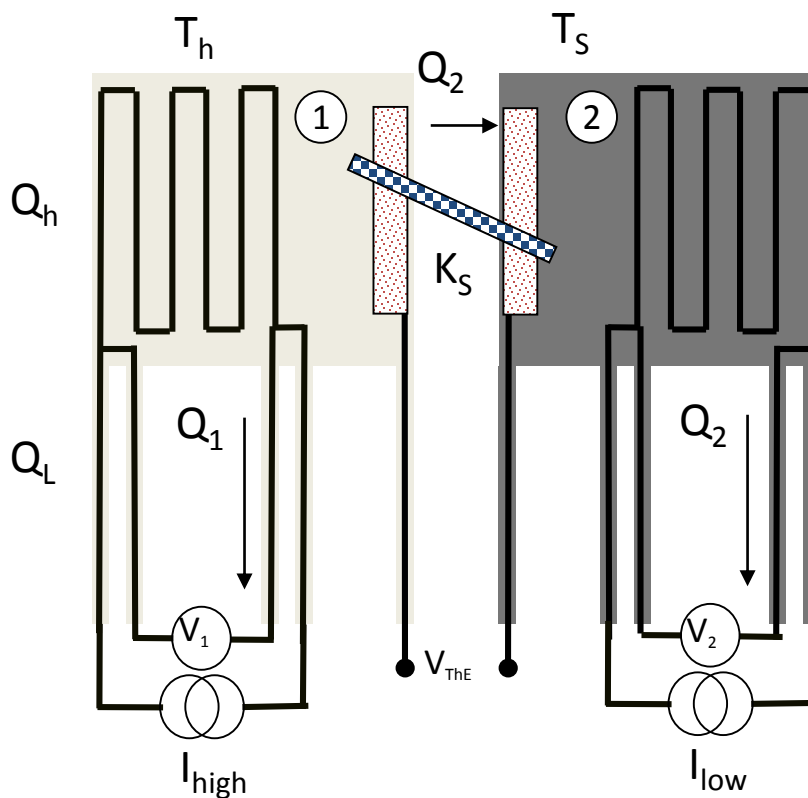
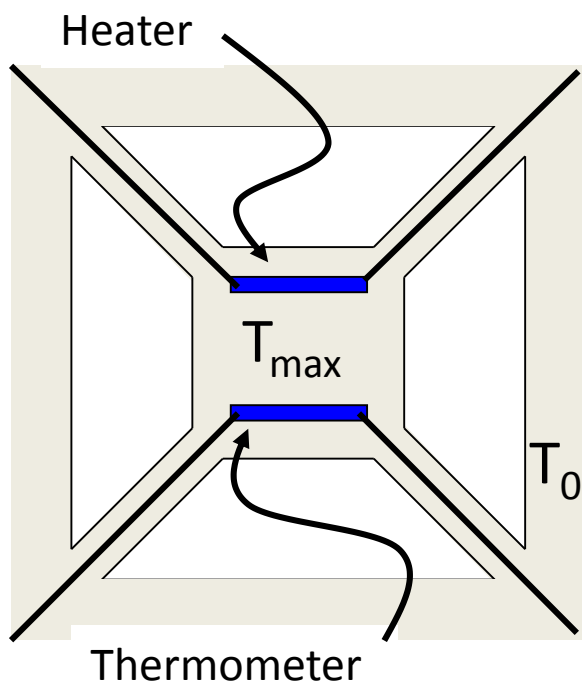


Nanowires

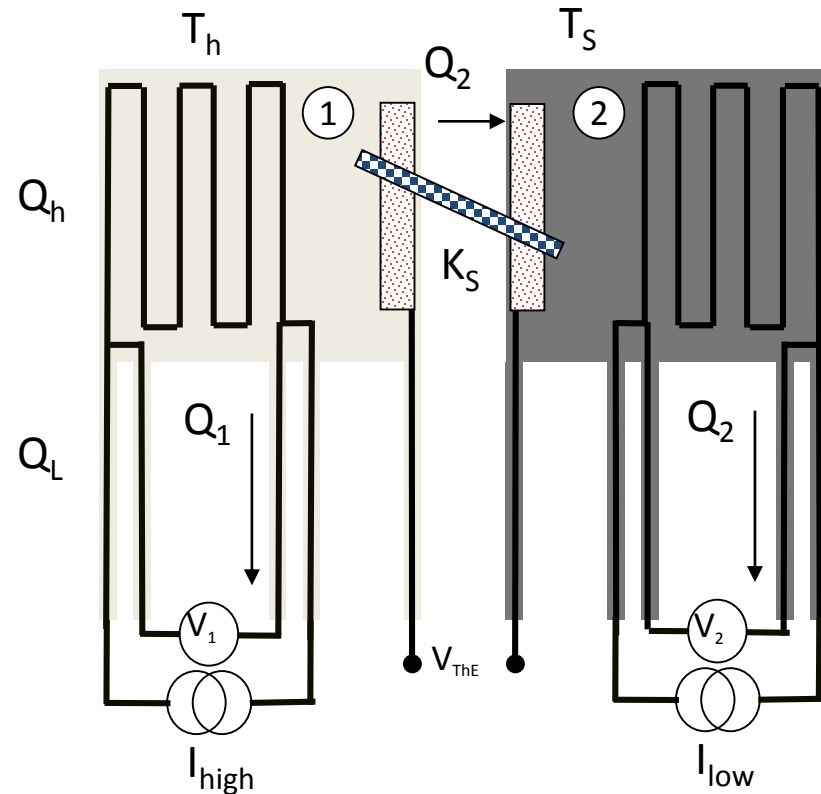
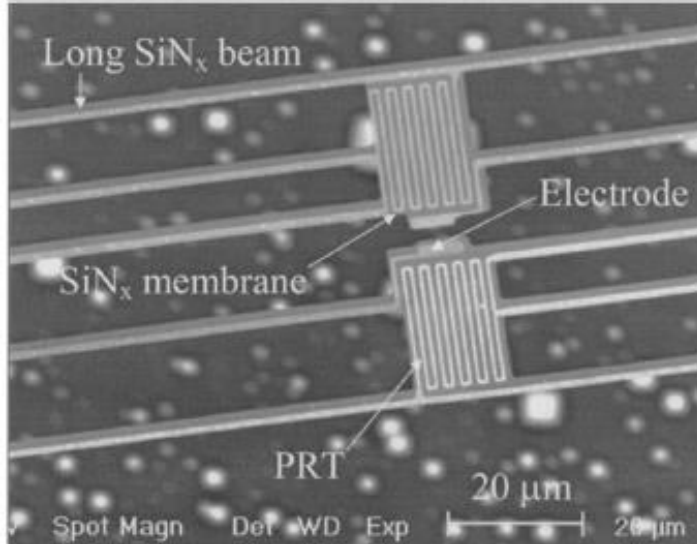
Thin films

Membranes

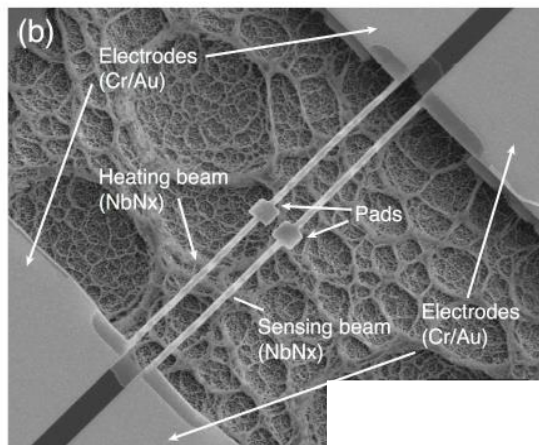
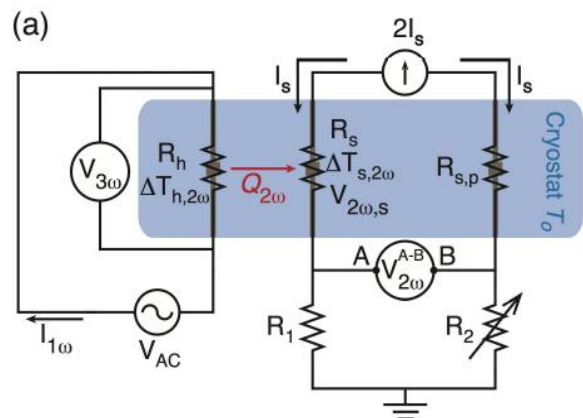
- Method based on a temperature gradient
- Between the membrane and a thermal bath
- Between two membranes



- Measure of K and C and of the thermoelectric power
- Platinum thermometry
- Adapted to self grown nano-objects
- Major difficulty: the thermal contact between the nanowire and the heat bath
- Thermal model needed



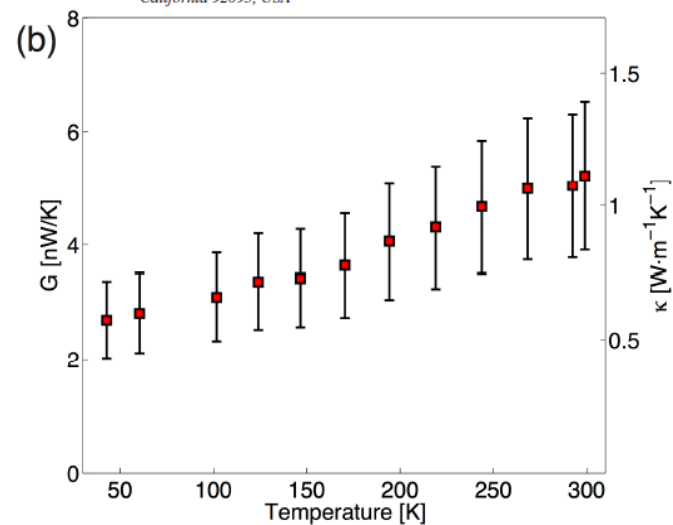
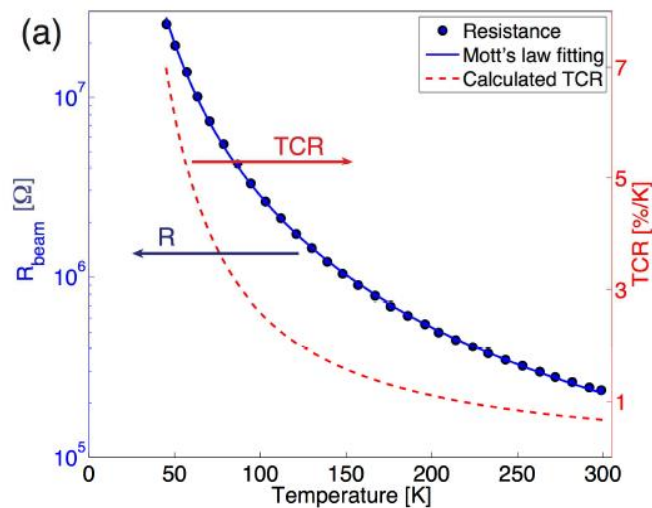
L. Shi,, P. Kim, A. Majumdar, Journal of Heat Transfer **125**, 881 (2003)



REVIEW OF SCIENTIFIC INSTRUMENTS **85**, 094903 (2014)

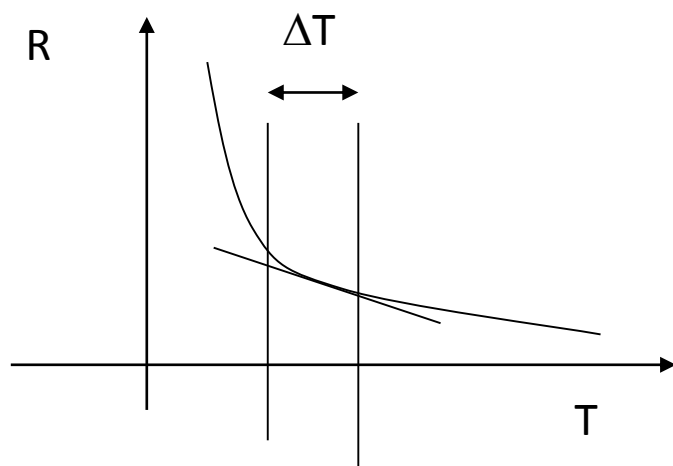
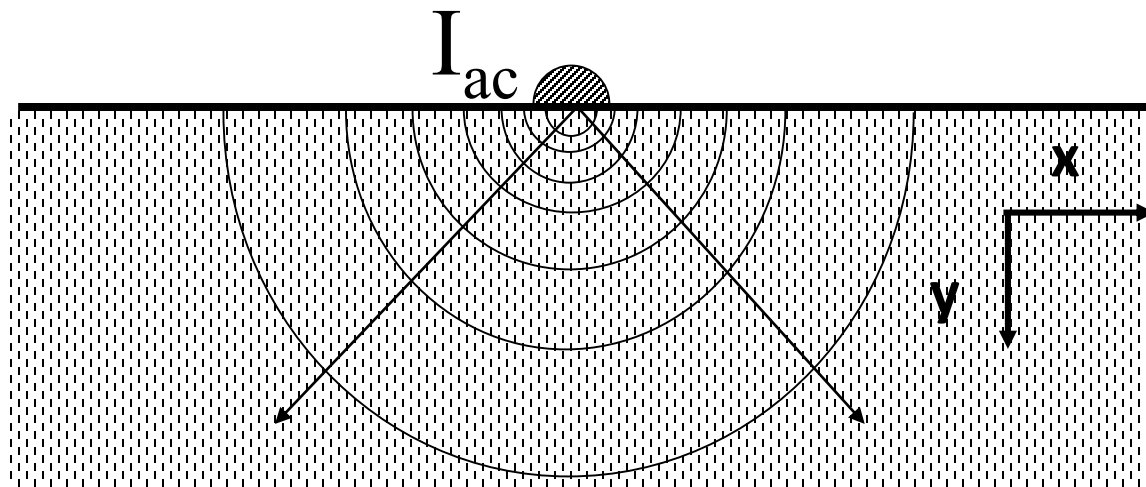
Sub-picowatt resolution calorimetry with niobium nitride thin-film thermometer

Edward Dechaumphai and Renkun Chen^{a)}
 Department of Mechanical and Aerospace Engineering, University of California, San Diego, La Jolla, California 92093, USA



Thin films

- Heater=thermometer
- Thermal conductance measurement at low frequency (Cahill RSI 1990)
- Heat capacity measurement at high frequency) Birge & Nagel (RSI 58, 1464 (1987))



- $I_{ac} \sim 1\omega$ (Ohmic component)
- $T_{ac} \sim I^2 \sim 2\omega$
- $R \sim T \sim 2\omega$
- $V_{3\omega} \sim I_{ac} R \sim 3\omega$

D. G. Cahill, Rev. Sci. Instrum. **61**, 802 (1990)

J.-Y. Duquesne, Phys. Rev. B. **79**, 153304 (2009)

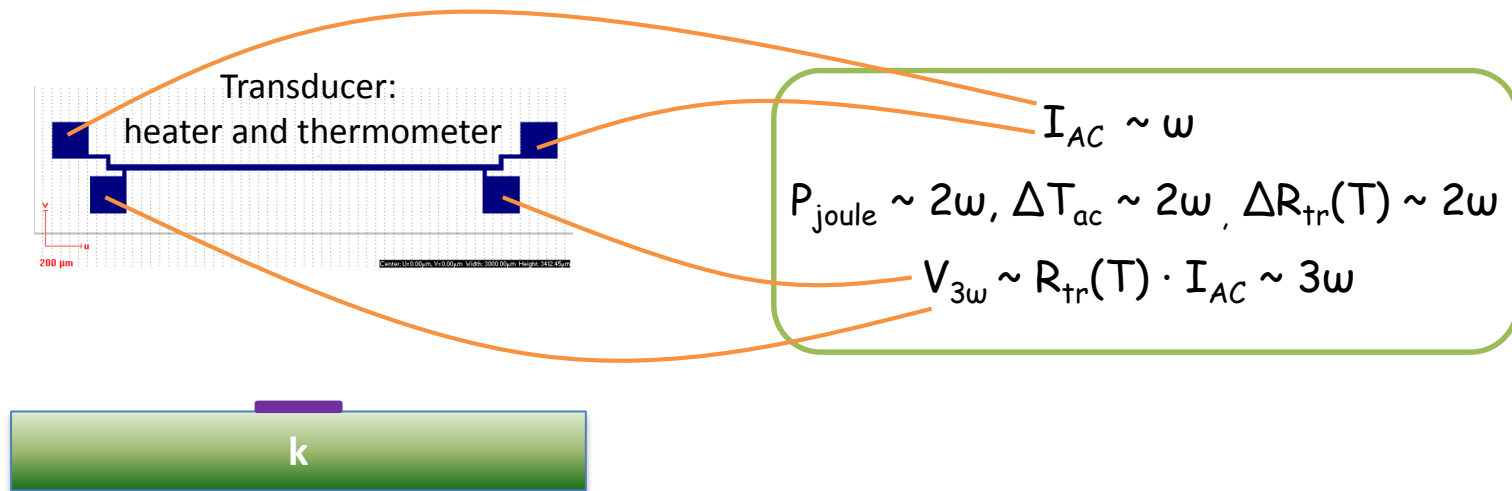
Yanqing Liu, OB, J. Phys. Conf. Series (2014)

- Focus on electrical based measurement
- Problems related to measurement using continuous signal
- Preamplification of the signal before measurement
- AC thermal measurements: proposed since 1910 by O. Corbino
- Measure by lock-in amplifier
- Differential geometry



Orso Mario Corbino (1876-1937)

O.M. Corbino, Phys. Z. **11**, 413 (1910), *ibid.* **12**, 292 (1911)



Thermal penetration depth:

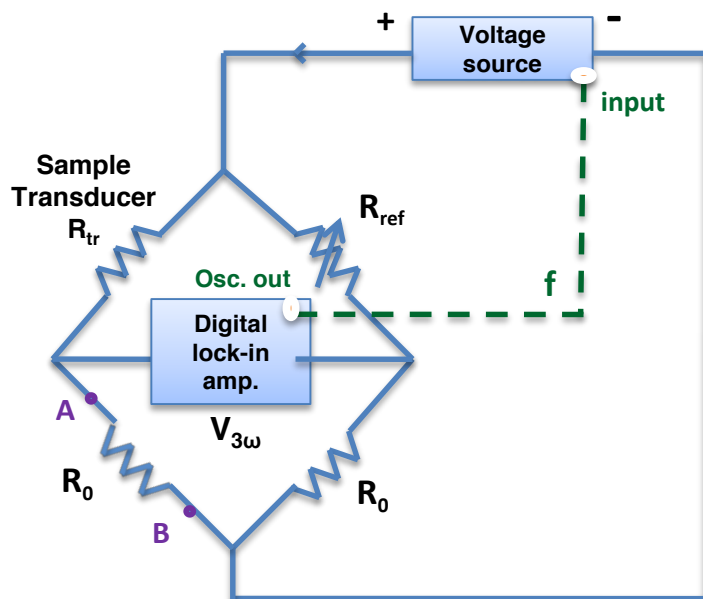
$$\mu = \sqrt{\frac{D}{\omega_{th}}} \quad \left(\begin{array}{l} D: \text{thermal diffusivity} \\ \omega_{th} = 4 \cdot \pi \cdot f_e \end{array} \right)$$

Low frequency regime: $\mu \gg 2b$

High frequency regime: $\mu \ll 2b$

$V_{3\omega}(\omega)$ in low frequency regime $\rightarrow k$

Wheatstone bridge (biased by a voltage source)



$$k = \frac{\alpha \cdot R_{tr}^2 \cdot I^3}{4 \cdot \pi \cdot l} \left(\frac{dV_{3\omega_{inph.}}}{d \ln \omega} \right)^{-1} \cdot \frac{R_0}{R_{ref} + R_0}$$

$$I = \frac{V_{AB}}{R_0} \quad (R_0 = 120 \, \Omega)$$

(Y. Liu, Jacques RICHARD, OB, TPS, Institut Néel)

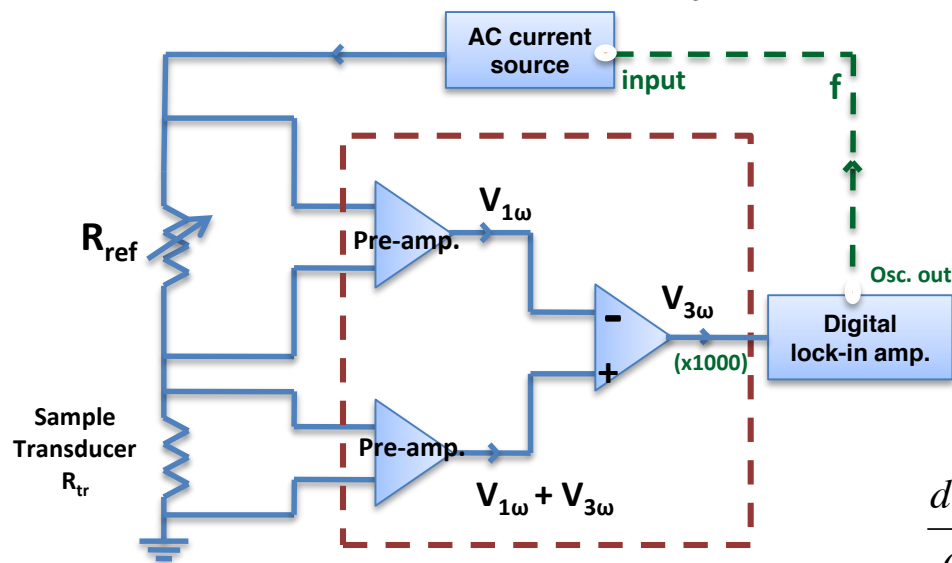
Differential bridge (biased by a current source)

$$V_{\text{measured}} = V_{1\omega} + V_{3\omega}$$

$$\frac{V_{3\omega}}{V_{\omega}} \sim \frac{1}{1000}$$



R_{ref} : - independent of f_e
 - Subtraction of $V_{1\omega}$ improving the ratio of $\frac{V_{3\omega}}{V_{\omega}}$
 - $\frac{\Delta R}{R} \sim 10^{-3}$
 f_e : 100 ~ 1000 Hz



Home made device
 (Néel electronic service, Jean-luc Mocellin)

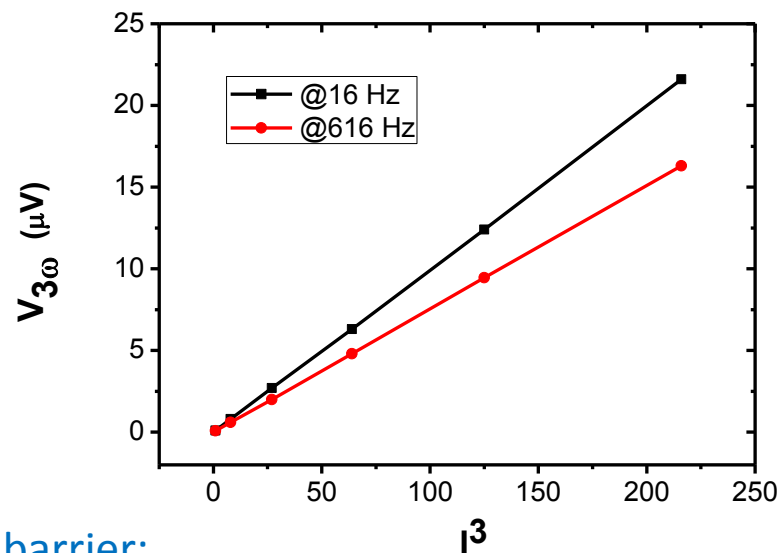
$$k = \frac{\alpha \cdot R_{tr}^2 \cdot I^3}{4 \cdot \pi \cdot l} \left(\frac{dV_{3\omega_{inph.}}}{d \ln \omega} \right)^{-1}$$

$\frac{dV_{3\omega_{inph.}}}{d \ln \omega}$: slope from the lineaire fit of $V_{3\omega_{inph.}}(\ln \omega)$

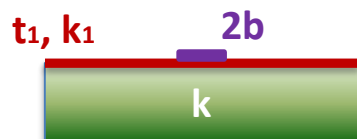
(Y. Liu *et al.*, J. Phys. Conf. Series, 2014)

✓ Verification of current range:

$$V_{3\omega} = a \cdot I^3$$



✓ Contribution of the thin films thermal barrier:



$$t_1 \ll 2b$$

- one-dimensional thermal transport across the film
- Heat flux conserved through the thin film



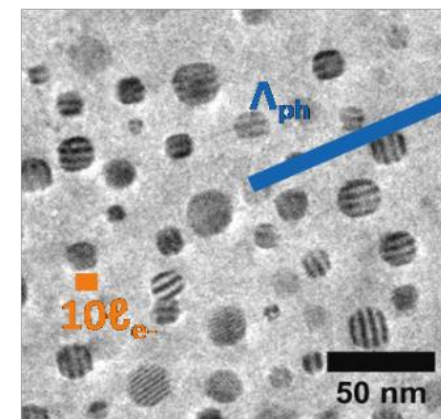
A thermal resistance barrier independent of f_e

A shift in real part of ΔT

$$\Delta T = \frac{P_l}{\pi \cdot k_0} \left(-\frac{1}{2} \ln \frac{\omega}{\Omega} + \eta - i \frac{\pi}{4} \right) + \frac{P_l \cdot R'}{2b}$$



T (K)	300 K
k_{Si} (Wm ⁻¹ K ⁻¹)	130
$k_{Ge:Mn}$ (Wm ⁻¹ K ⁻¹)	3.3

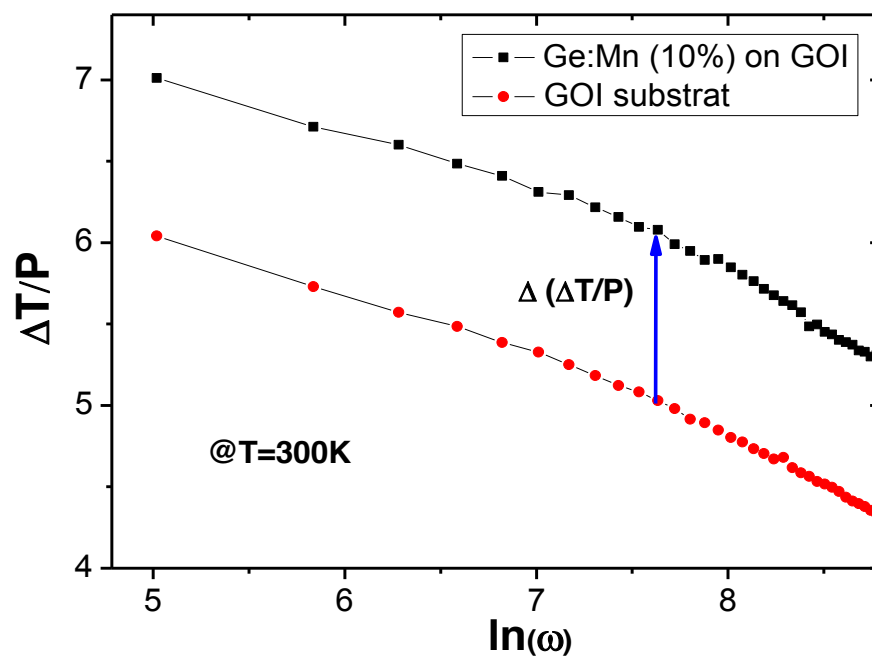


@300K

$$k_{Ge} = 60 \text{ Wm}^{-1}\text{K}^{-1}$$

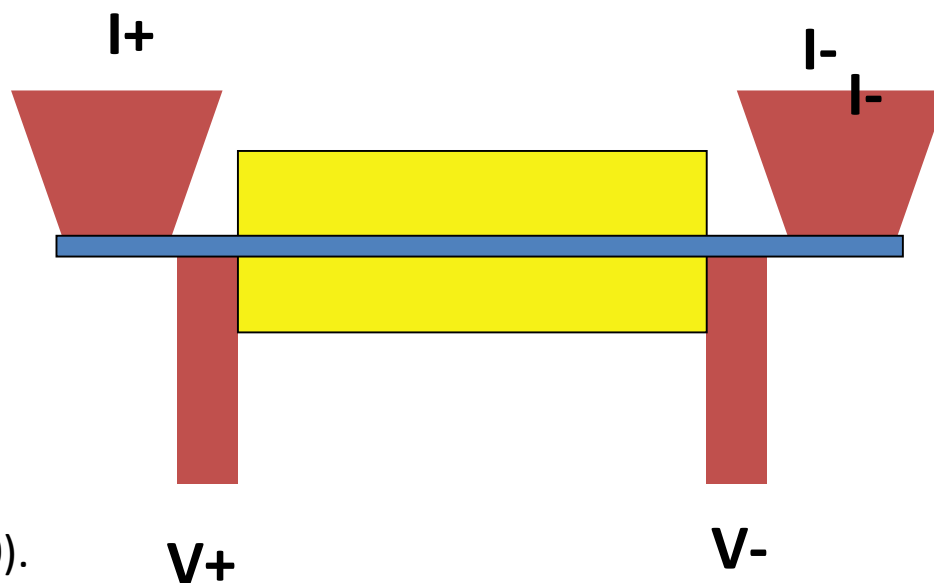
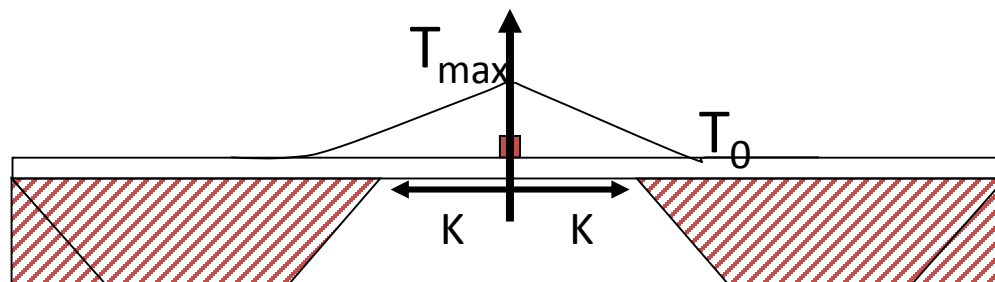
$$k_{Ge:Mn} = 3.3 \text{ Wm}^{-1}\text{K}^{-1}$$

Reduction by a factor of 20



Membranes

- In plan thermal conductance measurement
- DC current
- Silicon nitride membrane



F. Völklein, Thin solid Films **188**, 27 (1990).

3ω method

Metal line heated with $I_{AC} = f(\omega) = A \sin(\omega t)$

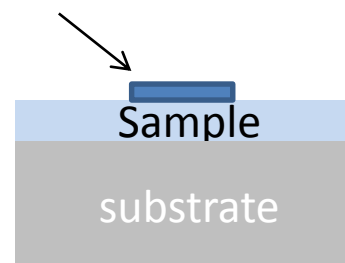
-> Dissipated power: $R I_{AC}^2 = f(2\omega)$

-> Resistance variation = $f(2\omega)$

-> Voltage variation = $f(2\omega) \cdot f(\omega)$

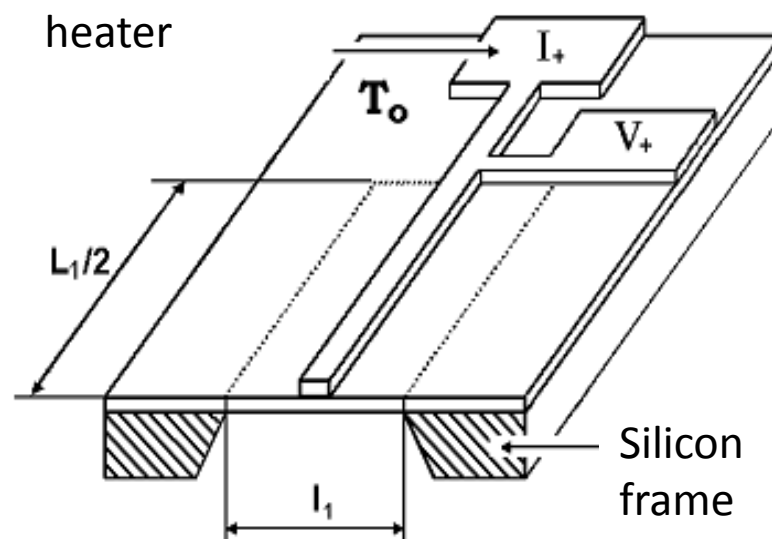
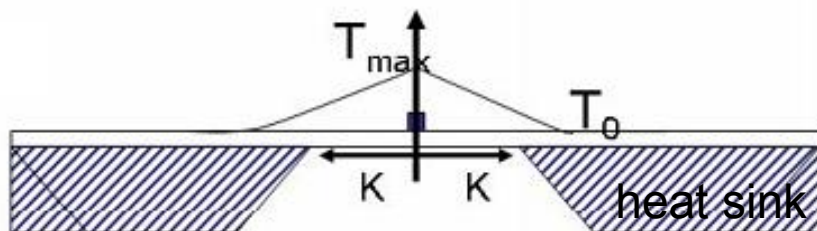
-> Measured voltage: ohmic part $V(\omega)$ + thermal part $V(3\omega)$

thermometer/heater



Völklein method

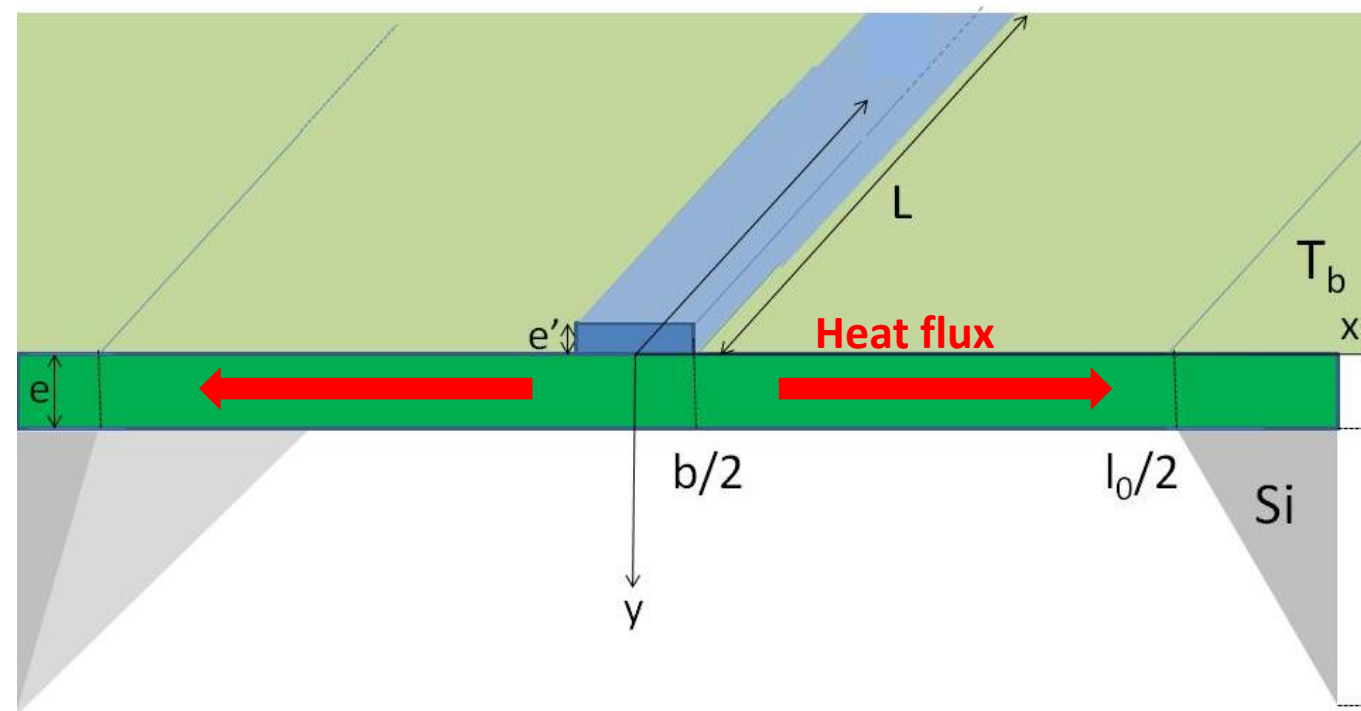
-Direct current



Heat balance: measurement of the thermal conductance in the plane

3ω / Völklein method: 3ω on membrane

$$V(3\omega) = f(K, C)$$



$e = 100/400 \text{ nm}$
 $e' = \sim 50 \text{ nm}$
 $b = \sim 20 \text{ }\mu\text{m}$
 $L = \sim 1 \text{ mm}$
 $l_0 = 150/500 \text{ }\mu\text{m}$

A. Jain and K. E. Goodson, Journal of Heat Transfer **130**, 102402 (2008).

A. Sikora, H. Ftouni, J. Richard., and O. B, Rev. Sci. Instrum. **84**, 029901 (2013)

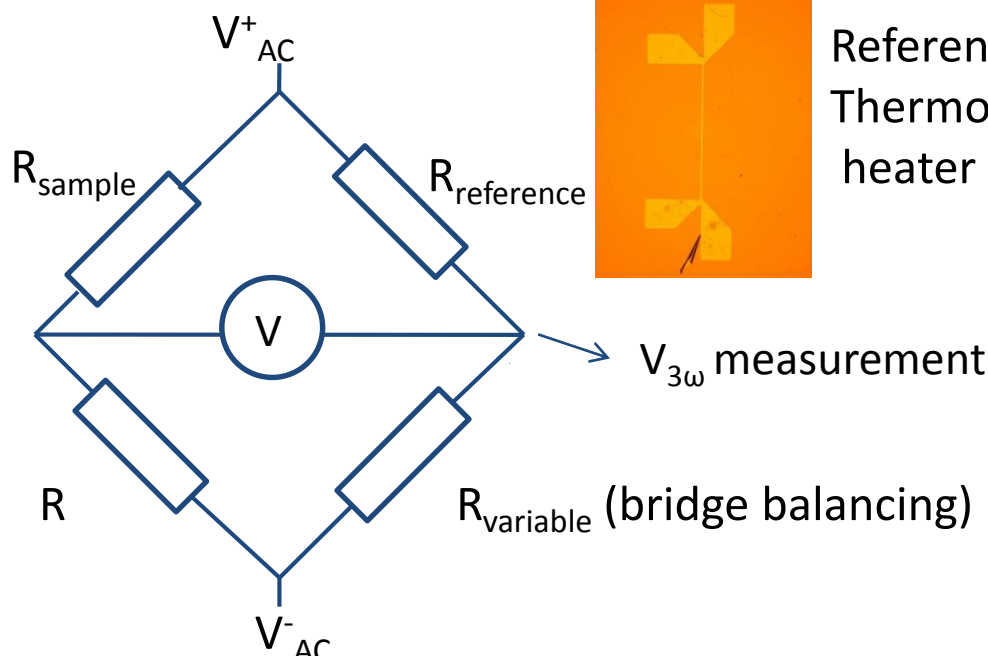
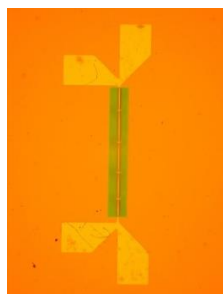
F. Völklein, H. Reith, and A. Meier, Phys. Status Solidi A **210**, 106–118 (2013)

Problem: $V(\omega) \gg V(3\omega)$, $V(3\omega)/V(\omega) \approx 3 \times 10^{-4}$



Minimisation of $V(\omega)$ voltage thanks to a **Wheatstone bridge**

Membrane +
NbN
Thermometer/
heater

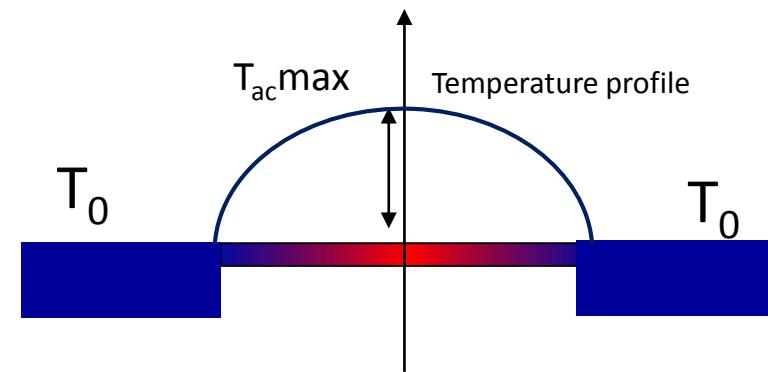
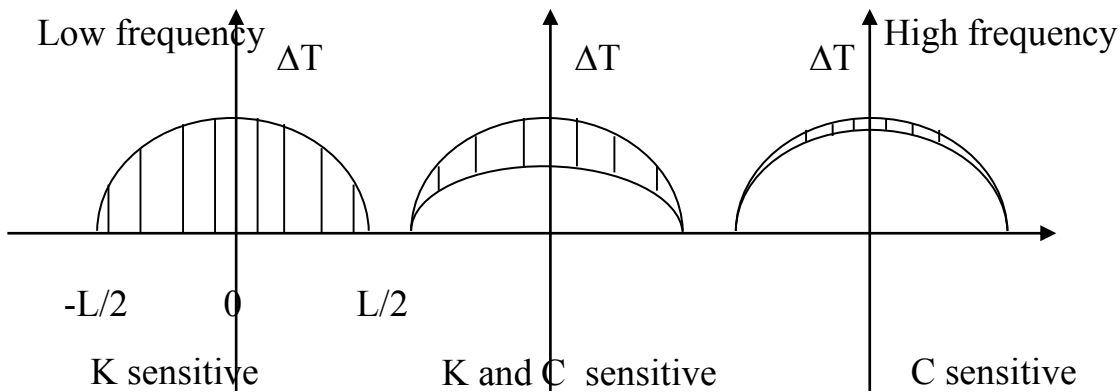


Reference:
Thermometer/
heater NbN



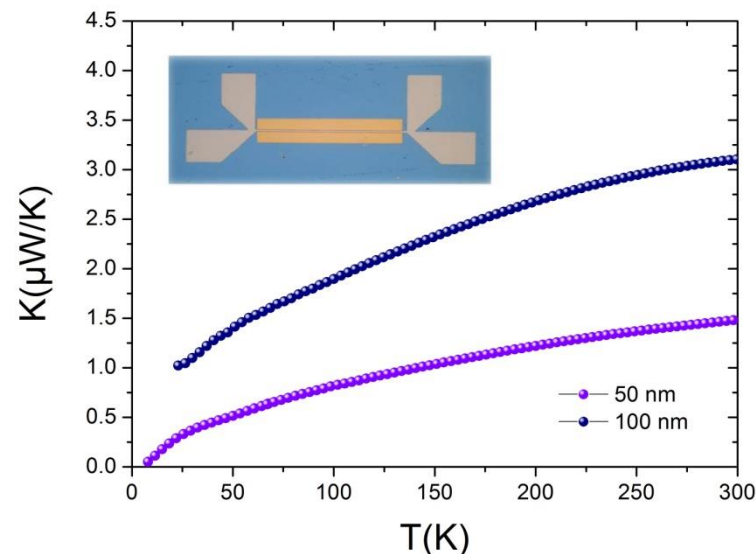
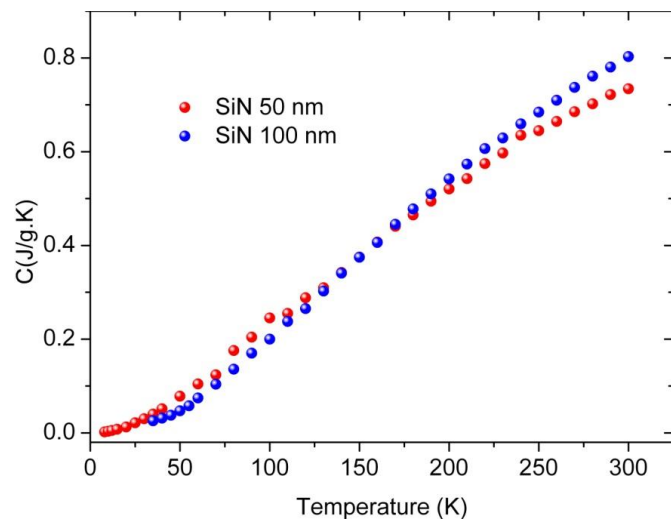
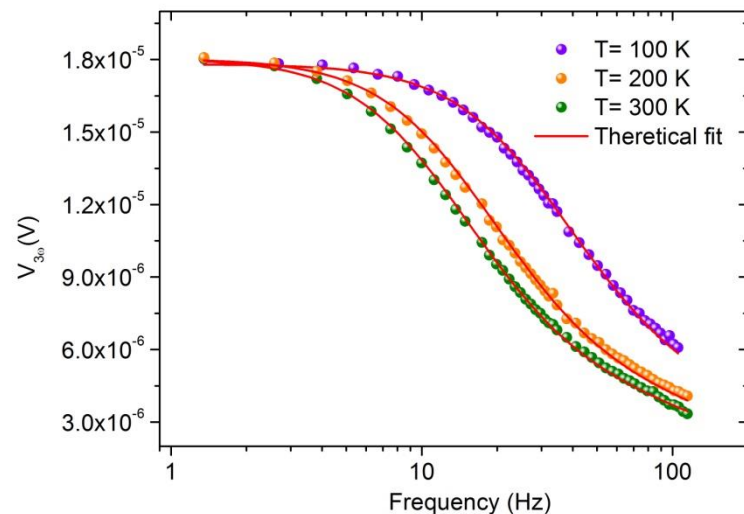
After balancing: $V(3\omega)/V(\omega) \approx 0.4$ (2V)

$$\rho C_P \frac{\partial}{\partial t} T(x,t) - k \frac{\partial^2}{\partial x^2} T(x,t) = \frac{I_0^2 \sin^2(\omega t)}{LS} \left[R + \left(\frac{dR}{dT} \right)_{T_0} (\Delta T(x,t)) \right]$$



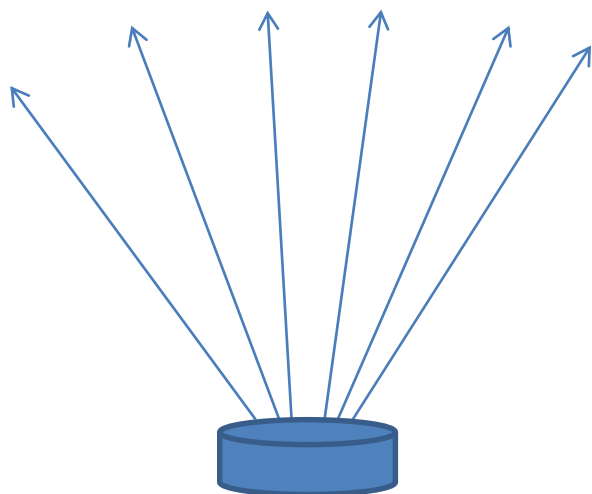
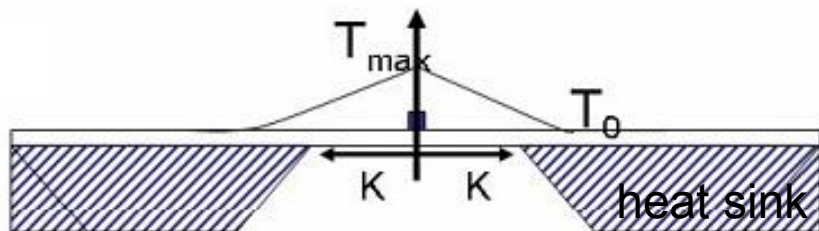
$$V_{3\omega} = \frac{4I_0^3 R^2 \alpha}{\pi^4 K (\sqrt{1 + (2\omega\gamma)^2})^2} \Rightarrow K = \frac{4I_0^3 R^2 \alpha}{\pi^4 V_{3\omega}}$$

O. Bourgeois, Th. Fournier and J. Chaussy, J. Appl. Phys, **101**, 016104 (2007)

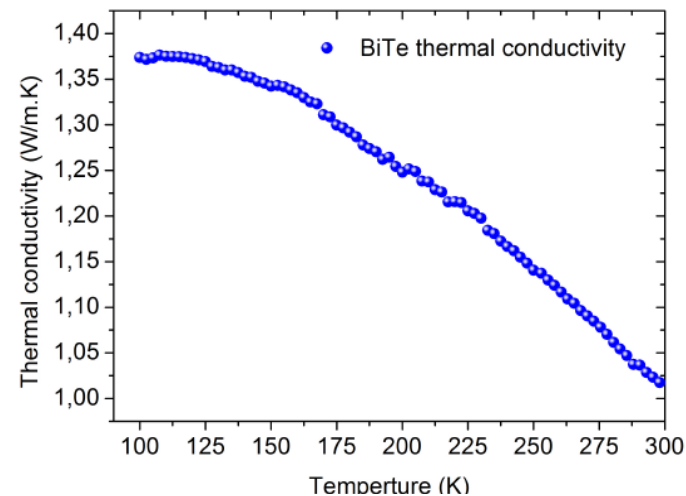


Hossein Ftouni, Dimitri Tainoff, Jacques Richard, Kunal Lulla, Jean Guidi, Eddy Collin, and O.B., Rev. Sci. Instrum. **84**, 094902 (2013).

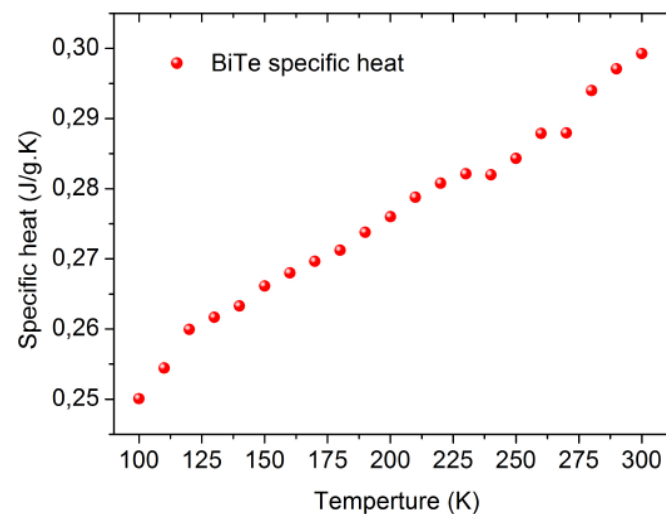
Thesis of Hossein Ftouni (I. Néel, 2013)



Thesis Hossein Ftouni (Néel I. sup. O.B.)



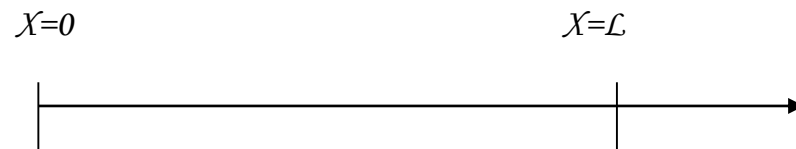
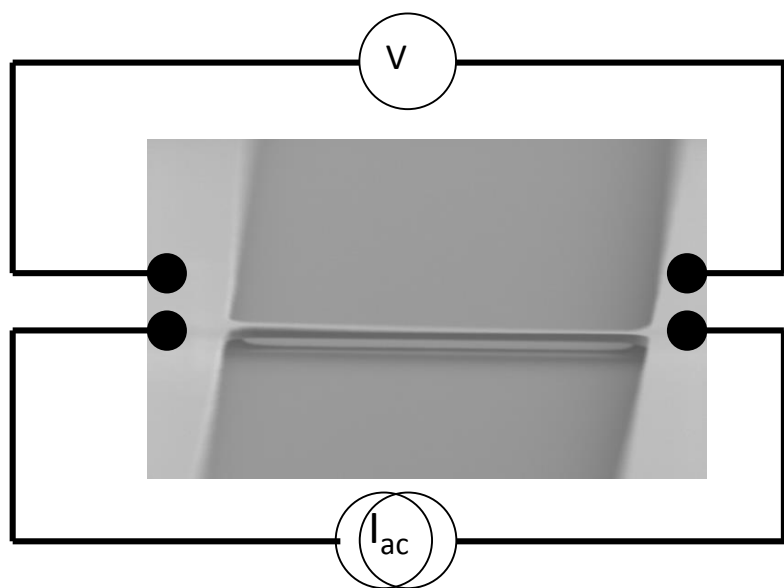
Thermal conductivity of 200 nm thick Bi_2Te_3 film as a function of temperature






5.3: Specific heat of 200 nm thick Bi_2Te_3 film as a function of temperature.

3 omega at the nanoscale

- Proposed by Lu et coll.
- Adapted for suspended nanowires
- Low frequency limit

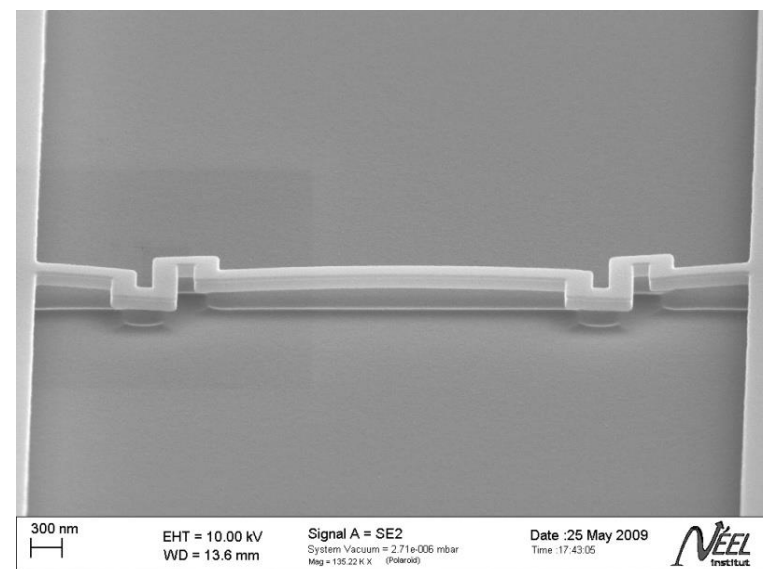
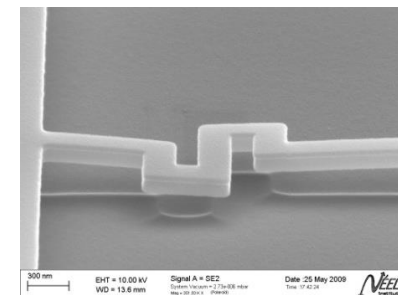
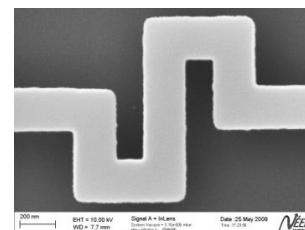


-  thermometer (transducer) Joule Heating
-  nanowire (suspended)
-  substrate

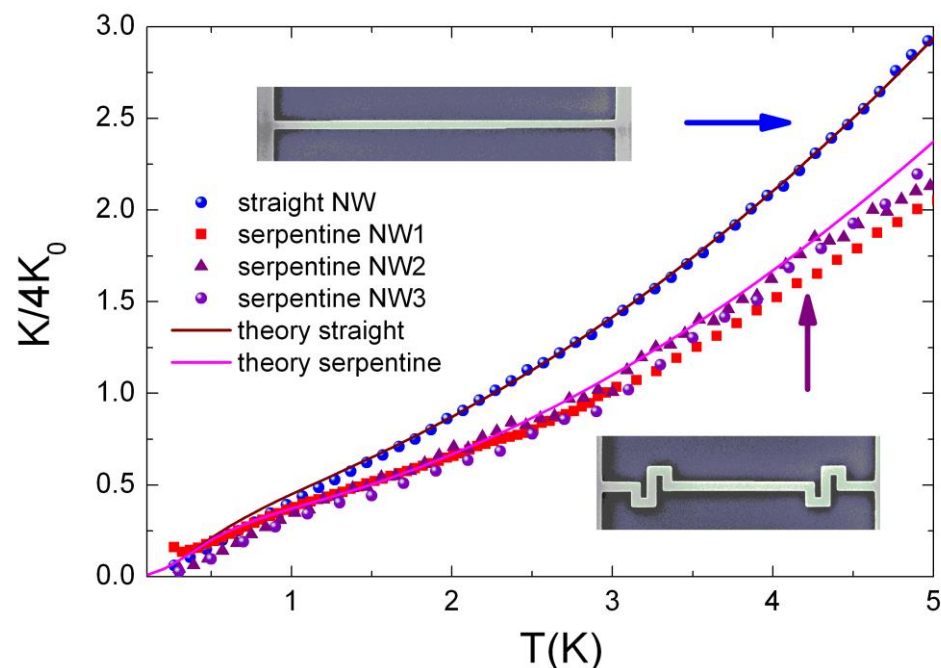
Lu L, Yi W and Zhang DL 2001 *Rev. Sci. Instrum.* **72** 2996

O. B., Th. Fournier and J. Chaussy, *J. Appl. Phys.*, **101**, 016104 (2007)

- Introducing of a serpentine nanostructure in the suspended nanowire (5 μ m long)
- Length scale 200nm
- Blocking only the ballistic phonons
- Reduce the thermal conductance



- Reduction of up to 40% of the thermal conductance
- Model this system by transmission function analysis
- Very good agreement between the model and the data
- Concerning ballistic phonons the reduction is of the order of 80%

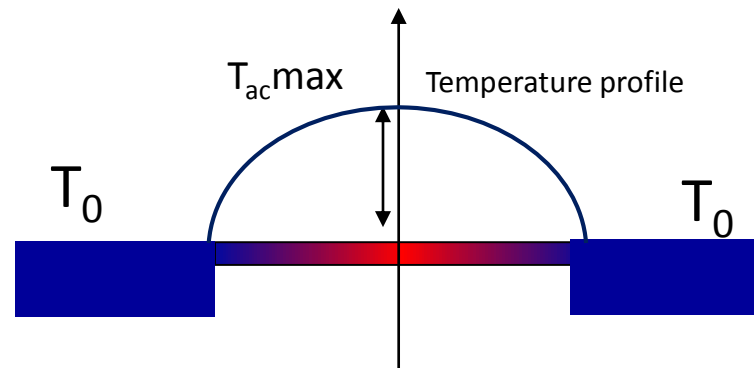


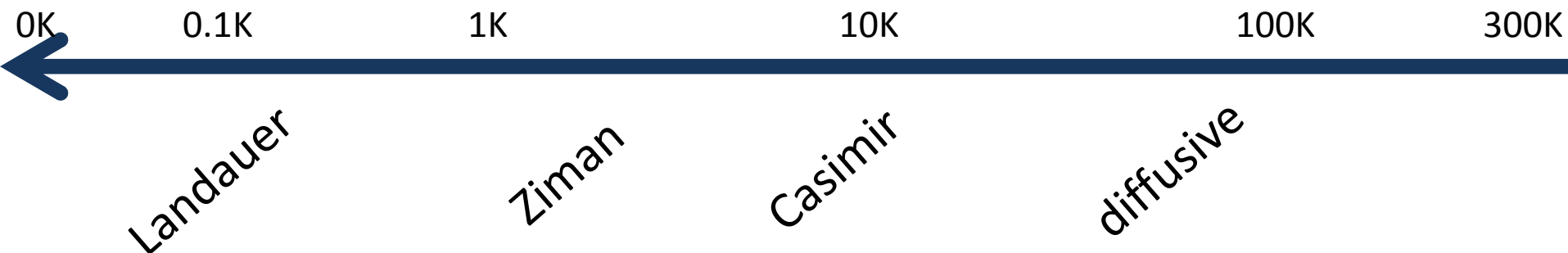
J-S. Heron, T. Fournier, N. Mingo, and O. B., Nano Letters, **9**, 1861 (2009)

J-S. Heron, C. Bera, T. Fournier, N. Mingo, and O. B., Phys Rev B **82**, 155458 (2010)

C. Blanc, A. Rajabpour, S. Volz, O. B, Appl. Phys. Lett. **103**, 013104 (2013).

$$\rho C_P \frac{\partial}{\partial t} T(x,t) - k \frac{\partial^2}{\partial x^2} T(x,t) = \frac{I_0^2 \sin^2(\omega t)}{LS} \left[R + \left(\frac{dR}{dT} \right)_{T_0} (\Delta T(x,t)) \right]$$





Silicon nanowire of diameter: 100nm

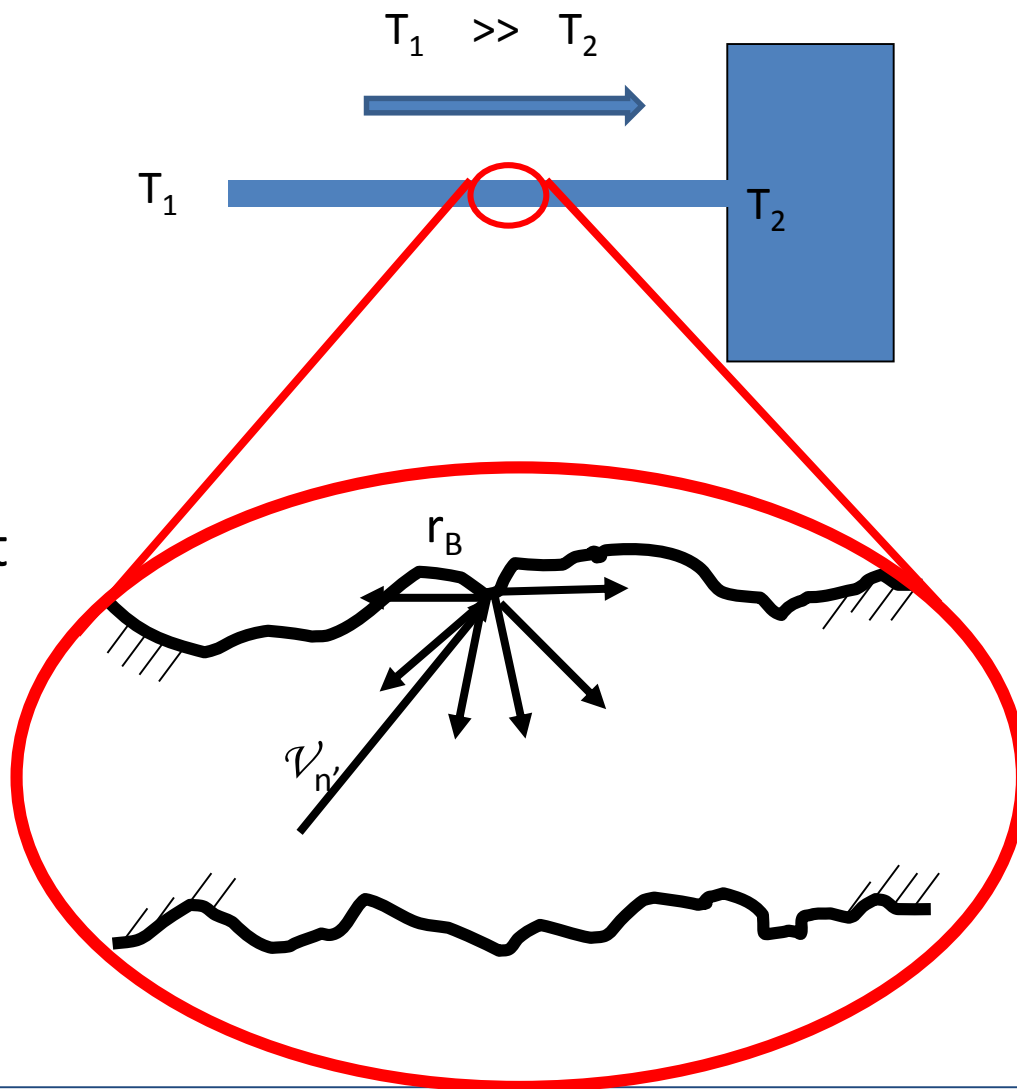
$\lambda_{\text{dom}}(T) < \Lambda_{\text{ph}}(T) < L$	Diffusive regime	Maxwell Boltzmann : $k = \frac{\nu_s}{3} \int c(\omega) \Lambda(\omega) d\omega$
$\lambda_{\text{dom}}(T) < L \sim \Lambda_{\text{Cas}} < \Lambda_{\text{ph-bulk}}(T)$	Casimir regime	Casimir model $K_{\text{Cas}} = \beta \Lambda_{\text{Cas}} T^3$
$\lambda_{\text{dom}}(T) \sim L < \Lambda_{\text{Ziman}}(T)$	Ziman regime	Ziman model $\Lambda_{\text{Ziman}} = \frac{1+p}{1-p} \Lambda_{\text{Cas}}$
$L < \lambda_{\text{dom}}(T) < \Lambda_{\text{ph}}(T)$	Ballistic regime	Landauer : $T = \frac{1}{1 + \Lambda_{\text{eff}} / L}$

Finite size effect: Casimir theory for phonon transport

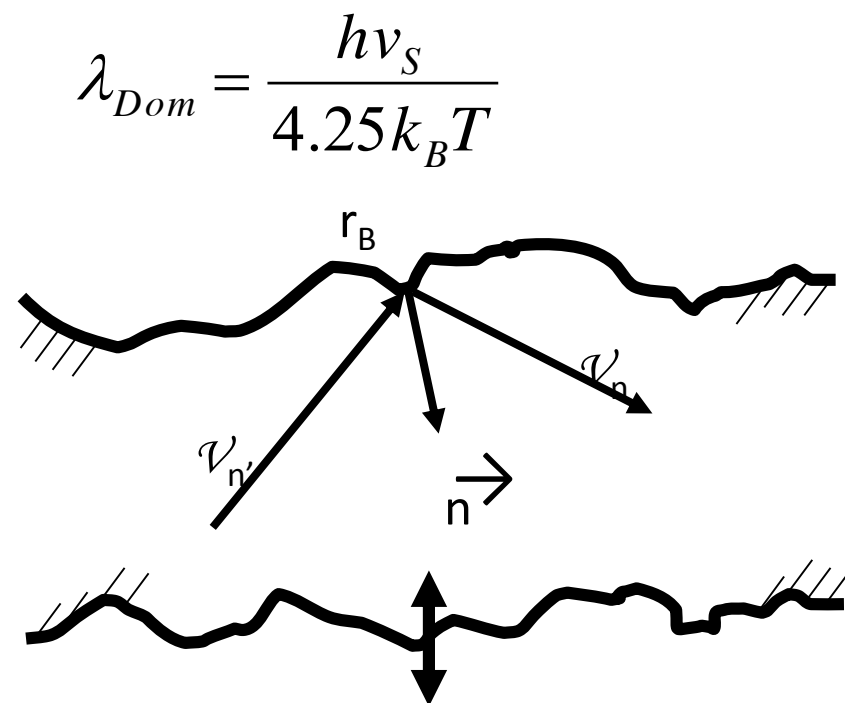
- Mean free path Λ_{ph}
- $\Lambda_{Cas} = D$ (Diameter of the nanowire)
- Boundary scattering: black body radiation for phonons
- Still diffusive
- Comment on the specific heat (kinetic equation)

$$K(T) = 3.2 \times 10^3 \left(\frac{2\pi^2 k_B^4}{5\hbar^3 v_s^3} \right)^{(2/3)} \frac{S \Lambda_{Cas}}{L} T^3$$

Breakdown of the concept of thermal conductivity



- At low temperature, the dominant phonon wave length is increasing:
- Probability of specular reflection $p(\lambda_{\text{dom}})$ depending on λ_{dom} (phenomenological parameter)
- $p(\lambda_{\text{dom}})=0$ (perfectly rough surface)
 $\lambda_{\text{dom}} \ll \eta_0$ Casimir model
- $p(\lambda_{\text{dom}})=1$ (perfectly smooth surface)
 $\lambda_{\text{dom}} \gg \eta_0$



η_0 is the root mean square of the asperity

- Ziman-Casimir model

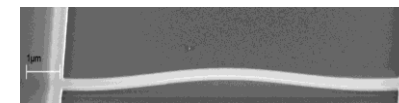
$$\Lambda_{ph} = \frac{1+p}{1-p} \Lambda_{Cas} \quad \text{where } p \text{ probability of specular reflection}$$

If $p=0$ transport is diffusive (Casimir), if $p=1$ ballistic transport

$$p(\lambda) = \int P(\eta) e^{\frac{-16\pi^3 \eta^2}{\lambda_{dom}^2}} d\eta \quad \text{Probability distribution of asperity} \quad P(\eta) = \frac{1}{\eta_0} e^{-\eta/\eta_0}$$

$$K(T) = 1.35 \times 10^{-5} \left(\frac{2 - e^{-4\pi \lambda_{dom}(T)/\eta_0}}{e^{-4\pi \lambda_{dom}(T)/\eta_0}} \right) \Lambda_{Cas} T^3$$

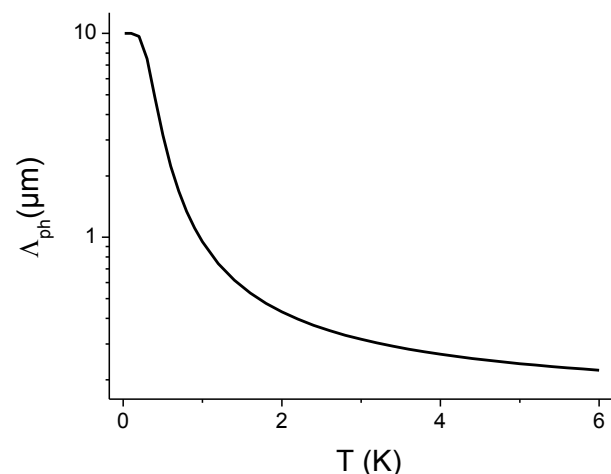
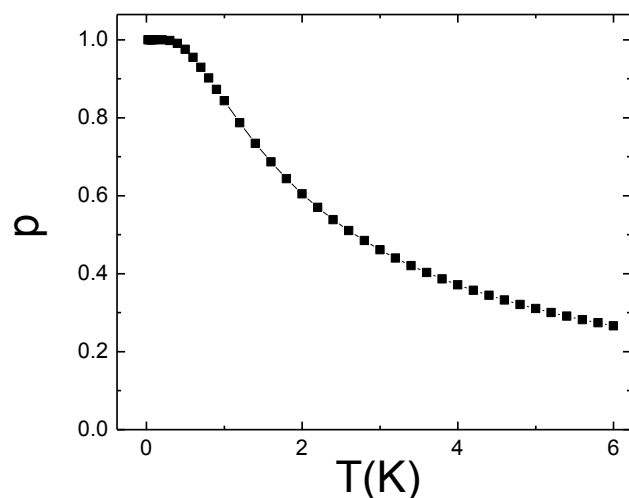
$$K = 3.2 \times 10^{-3} \left(\frac{2\pi^2 k_B^4}{5\hbar^3 v_s^3} \right)^{2/3} \frac{S\Lambda_{eff}}{L} T^3$$



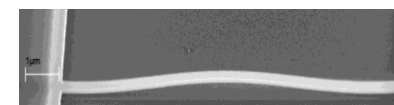
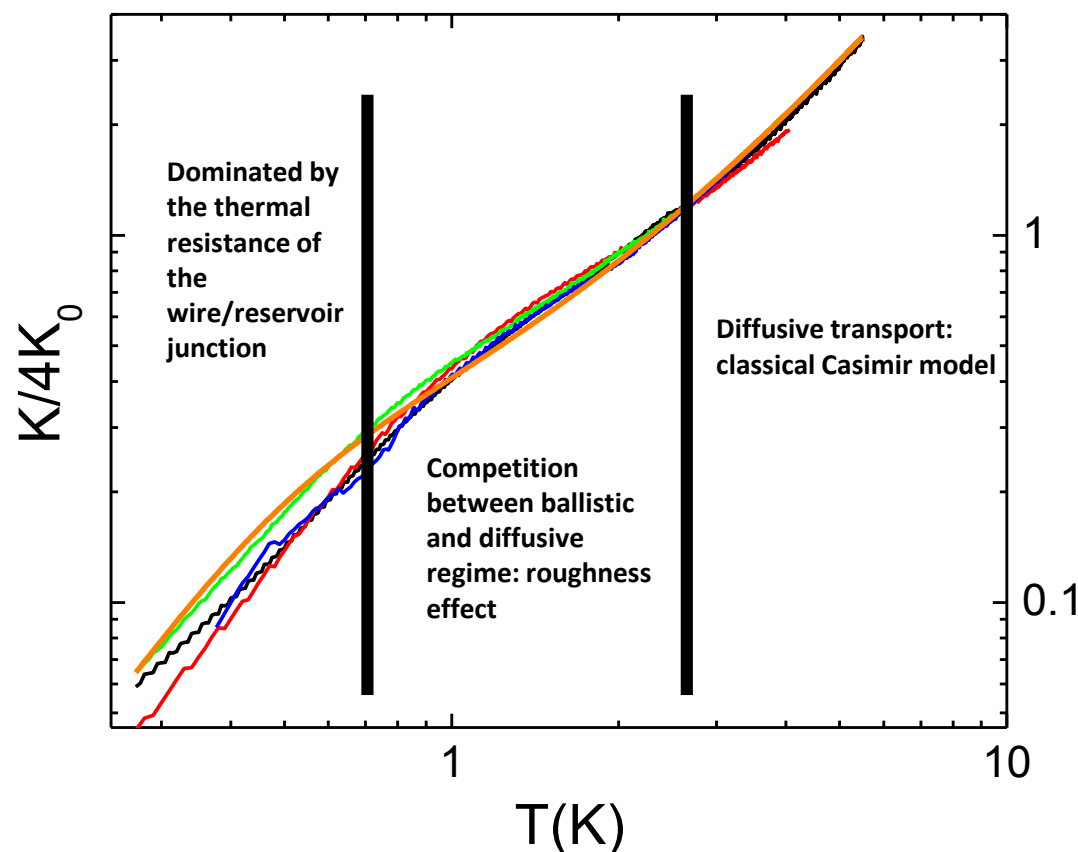
$$\lambda_{Dom} = \frac{\hbar v_s}{4.25 k_B T}$$

$$\Lambda_{eff} = \frac{1+p}{1-p} \Lambda_{Cas}$$

$$\Lambda_{ph}^{-1} = \Lambda_{eff}^{-1} + L^{-1}$$



J.-S. Heron, T. Fournier, N. Mingo and O. Bourgeois, Nano Letters **9**, 1861 (2009).



Fitting parameter:

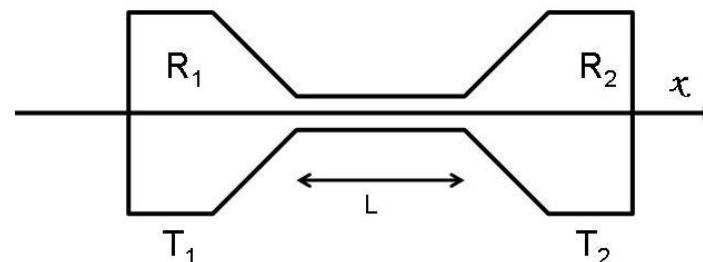
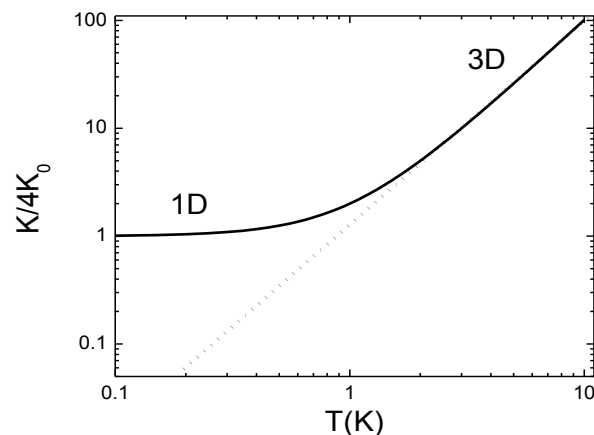
- Roughness $h=4\text{nm}$
- Speed of sound 9000m/s
- Contribution of the contact (Chang, C.; Geller, M. *Phys. Rev. B* **2005**, *71*, 125304.)

J.-S. Heron, T. Fournier, N. Mingo and O. B, Nano Letters **9**, 1861 (2009).

- $\Lambda \gg d$ (temperature defined over a volume Λ^3)
- $\lambda_{\text{dom}} \gg d$
- 4 acoustic phonon modes

$$K_0 = \frac{4\pi^2 k_B^2 T}{3h}$$

- Conduction channel (Similar to the Landauer model of electrical conductance)
- Not dependant on the materials
- Valid whatever the heat carrier statistic
- Pendry, Maynard: flow of entropy or information



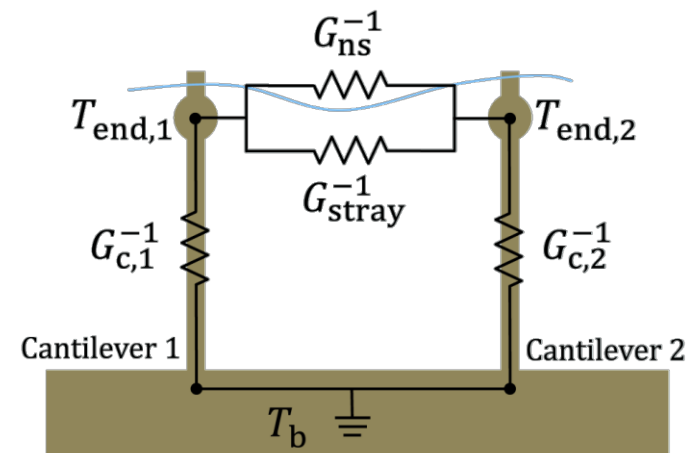
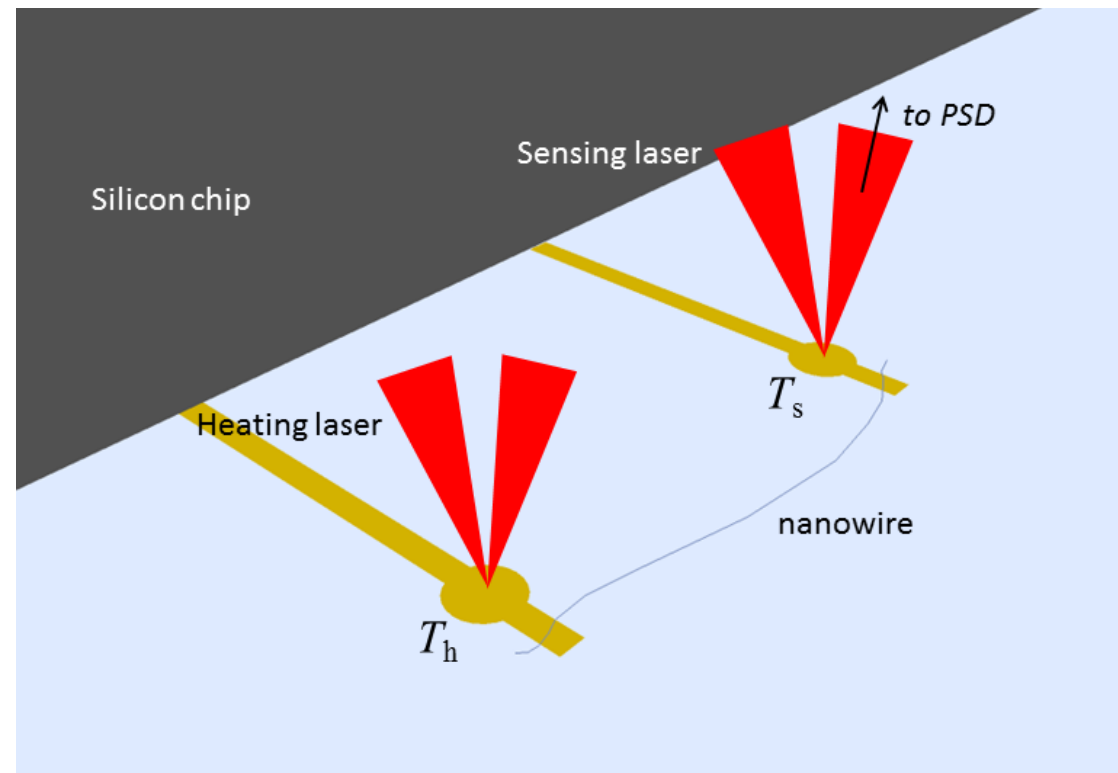
J.B. Pendry, J. Phys. **16**, 2161 (1983)

R. Maynard and E. Akkermans, Phys. Rev. B **32**, 5440 (1985)

L.G.C. Rego and G. Kirczenow, Phys. Rev. Lett. **81** 232 (1998)

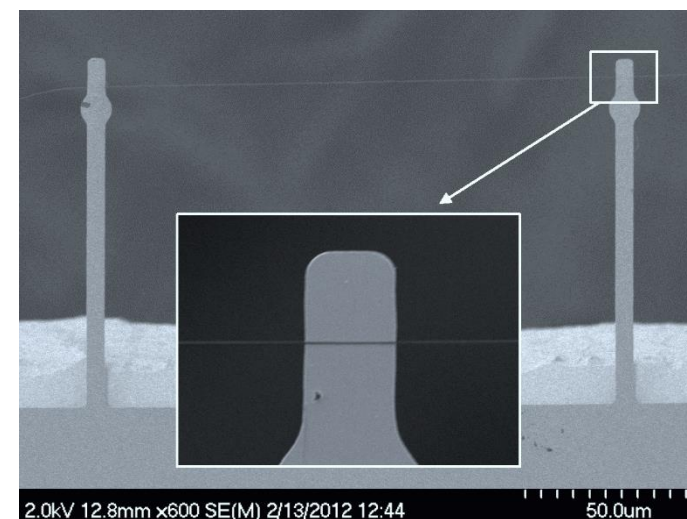
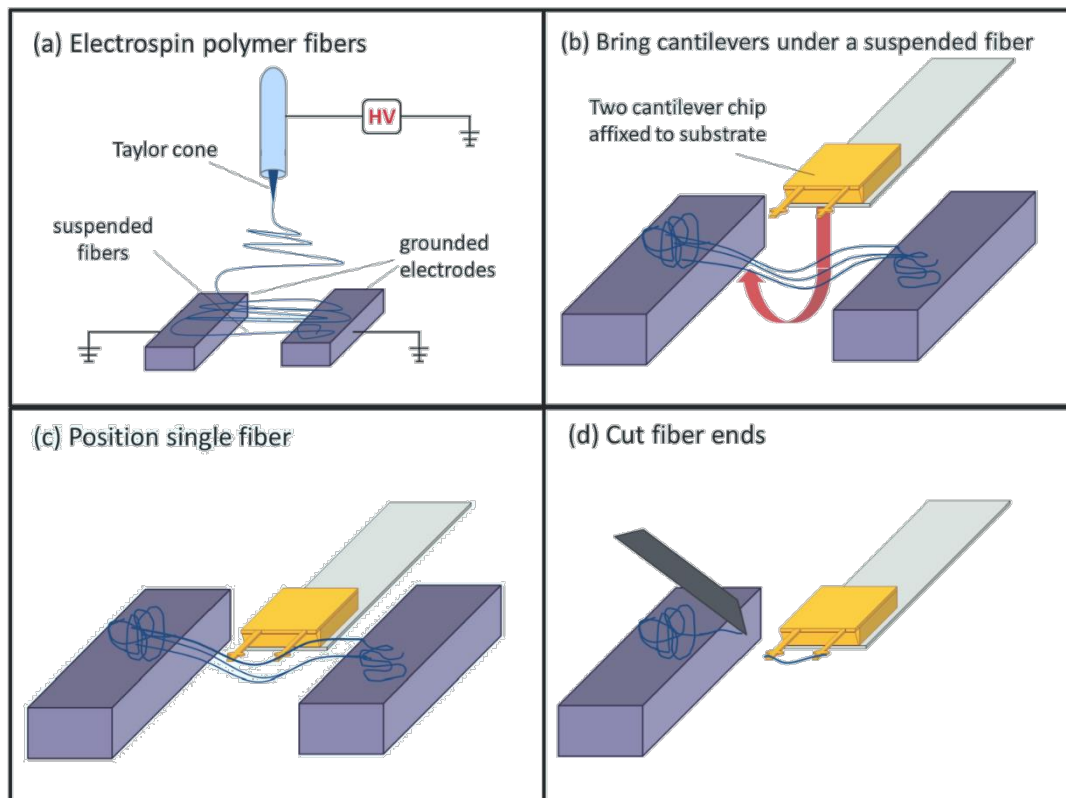
Mechanical technique based on bimetal cantilever: an old thermometry



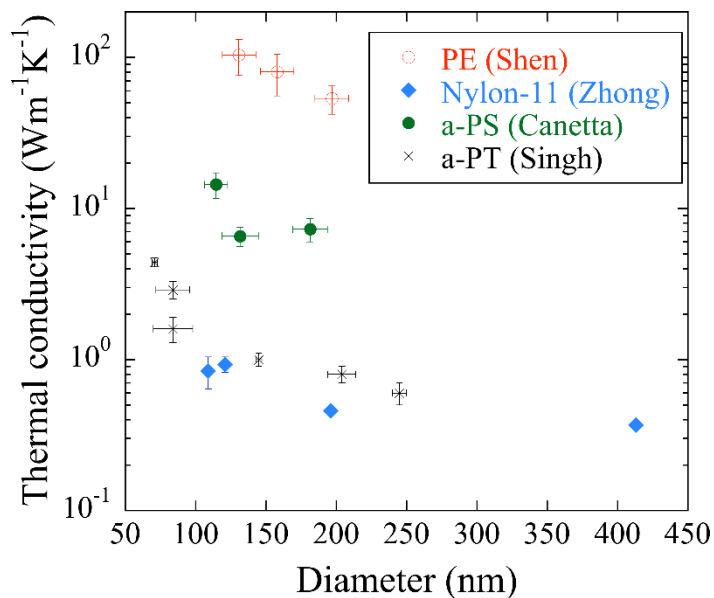
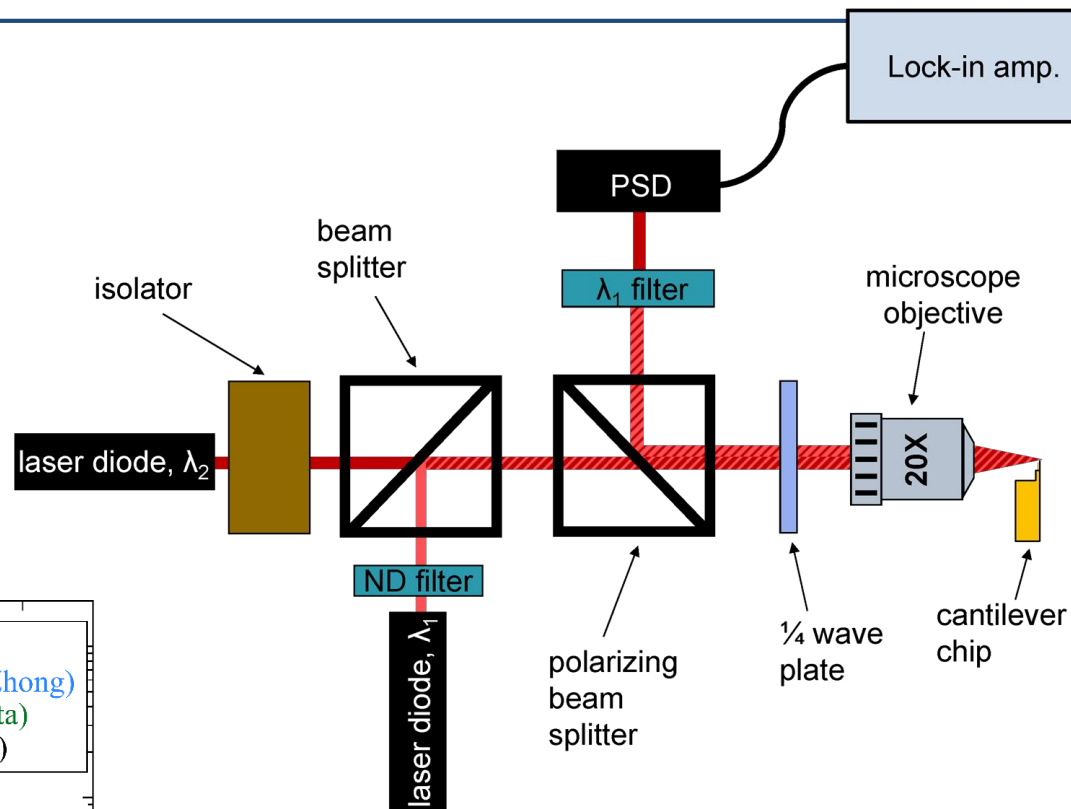
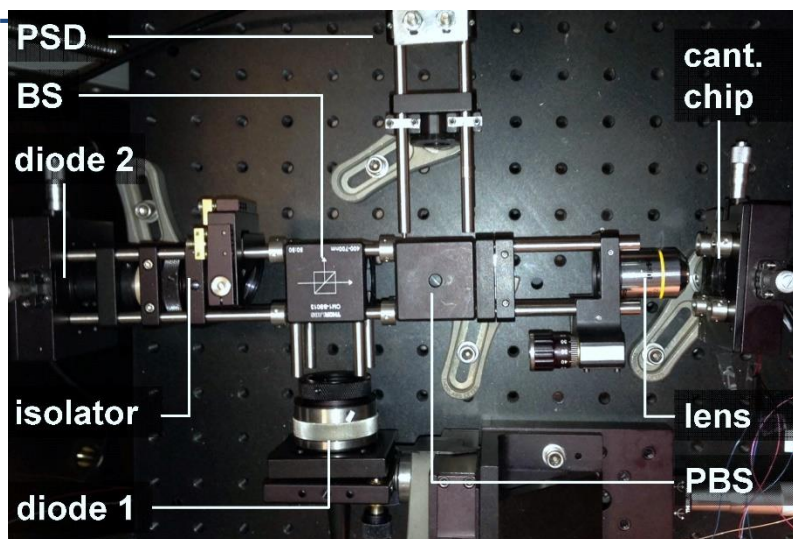


- G_{ns} – nanostructure conductance
- G_{stray} - stray conductance
- $G_{c,1}, G_{c,2}$ – cantilever conductances. Usually $G_{c,1} \approx G_{c,2}$

C. Canetta and A. Narayanaswamy, Rev. Sci. Instrum., 84, 105002 (2013)

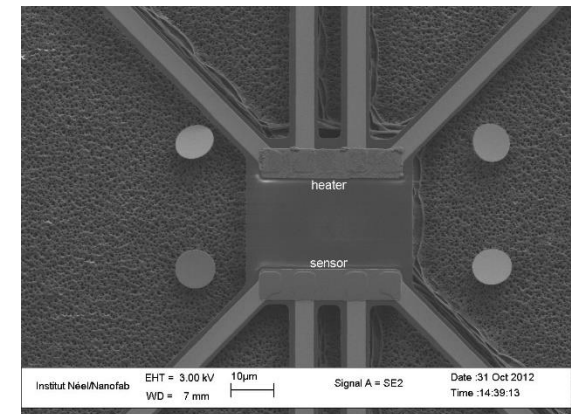
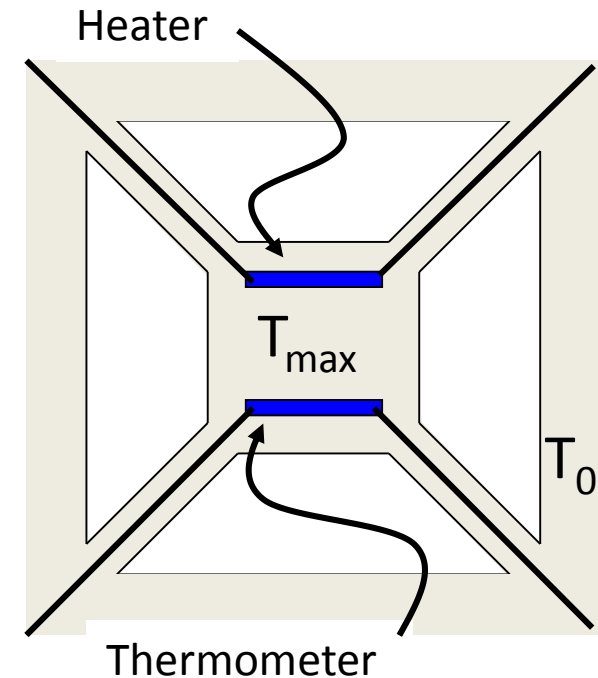


Polystyrene fiber, diameter < 200 nm

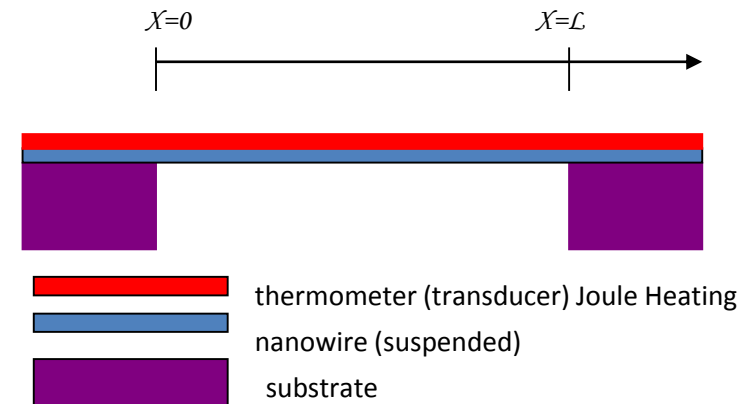
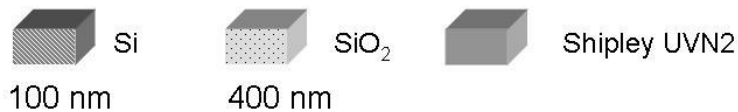
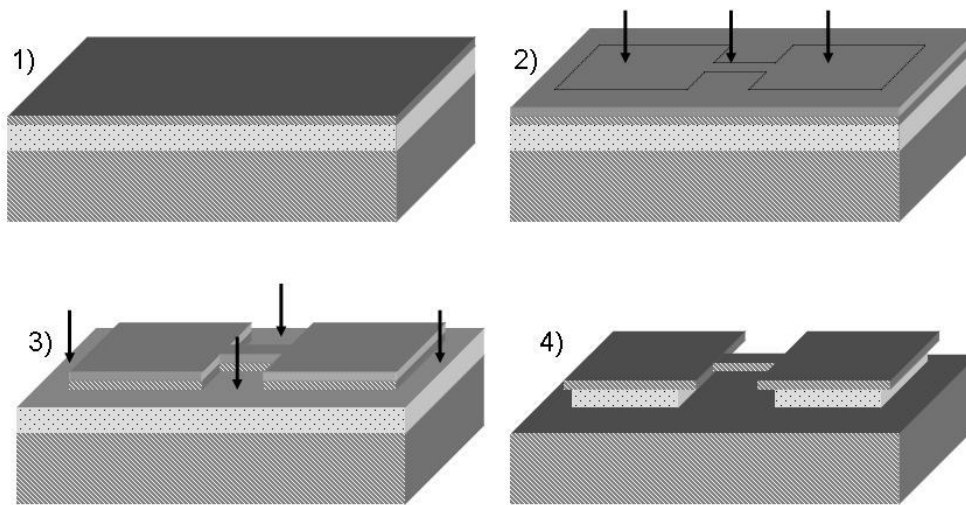


Micro and Nanofabrication

- A need for thermally isolated samples
- Suspended objects (difficult)
- Optical photolithography (UV light, monochromatic)
- Laser lithography (UV laser)
- E-beam lithography (electron beam)
- Chemical etching (vapour or liquid), HF, KOH, XeF₂, CH₃CF₄



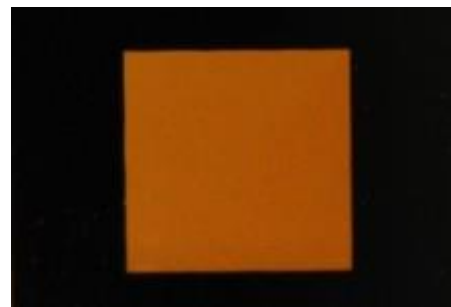
- SOI: silicon on insulator
- The fabrication of the silicon nanowire are realized by e-beam lithography on SOI substrate.
- Spinning e-beam resist
- e-beam isolation (structuration)
- Reactive Ion Etching (RIE)
- HF etching, nanowire suspended
- Deposition of thermometer



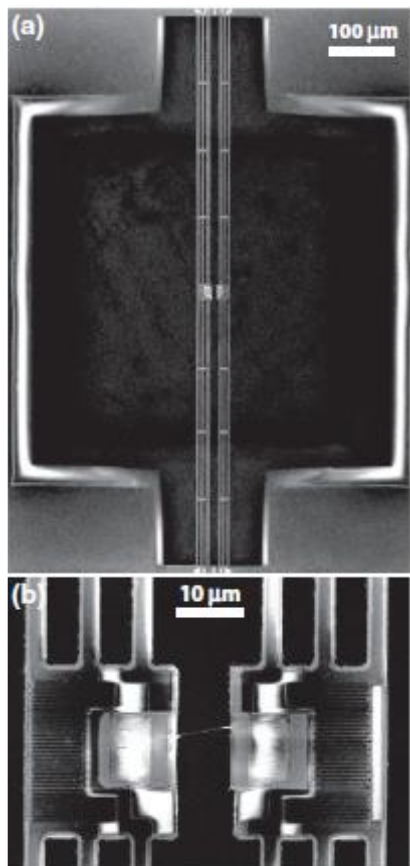
- KOH (liquid) need critical point drying, super-critic CO₂
- XeF₂ (vapour) avoid sticking effect



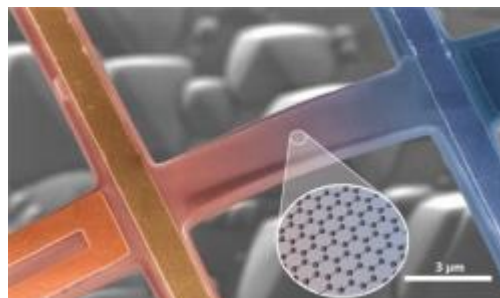
Si low stress membrane (VTT, Finland)



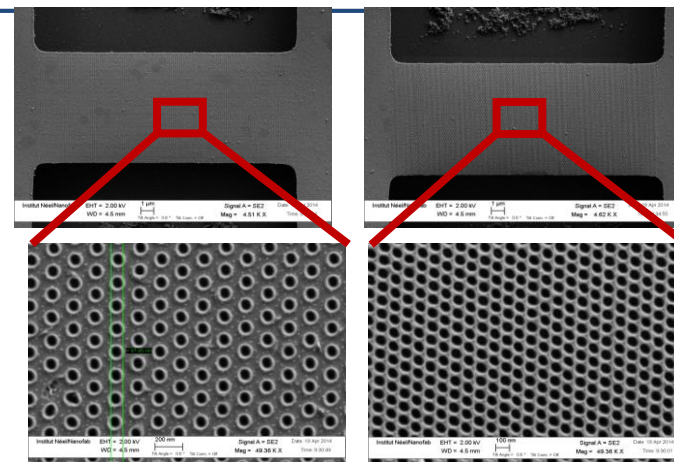
Si membrane stressed by SiN (VTT, Finland)
Chavez, APL Mat 2014



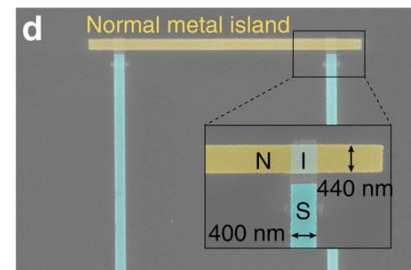
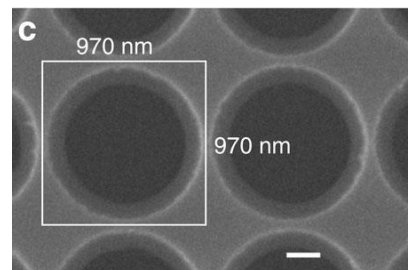
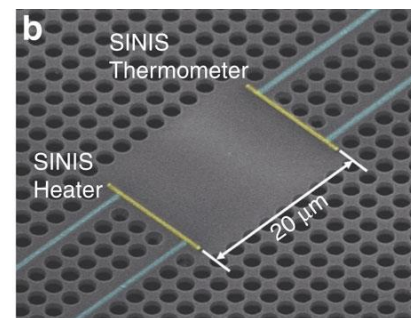
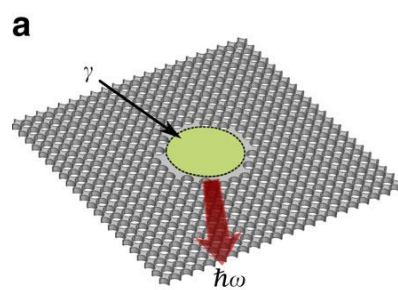
SiN structure from Group of Li Shi,
Univ of Texas at Austin



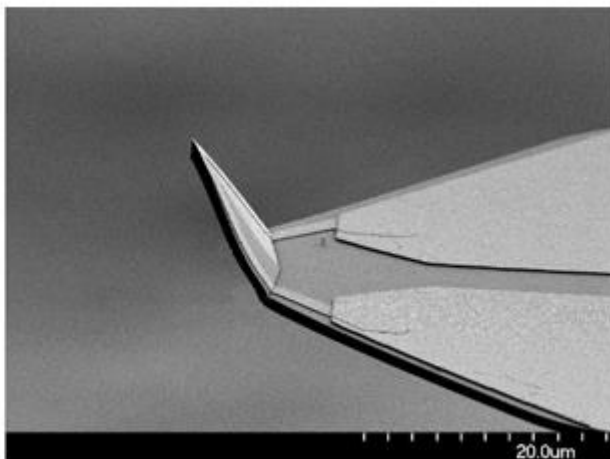
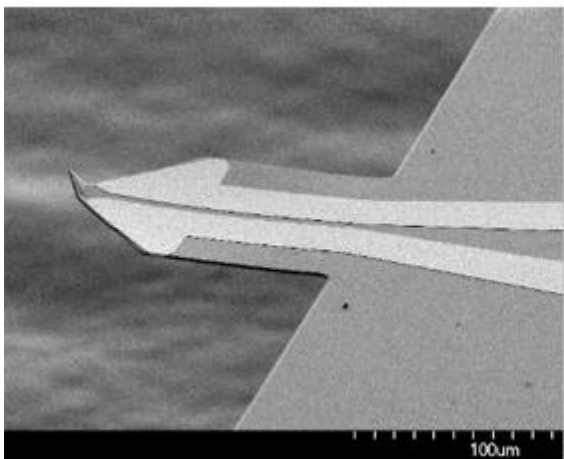
L. Shi Science 2010



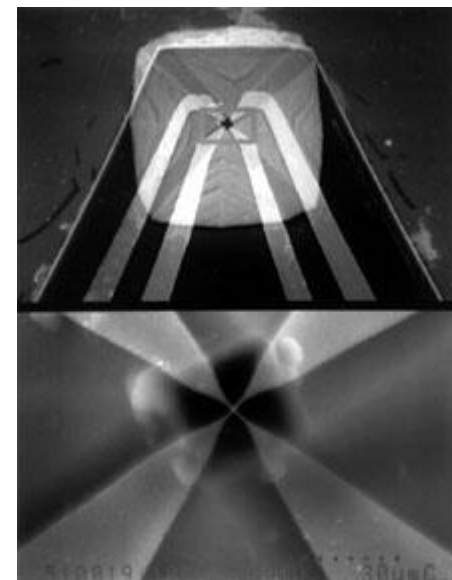
Germanium structure O.B. group Néel CNRS



SiN from Group of Maasilta Jyvaskyla Univ., Nature Com 2014

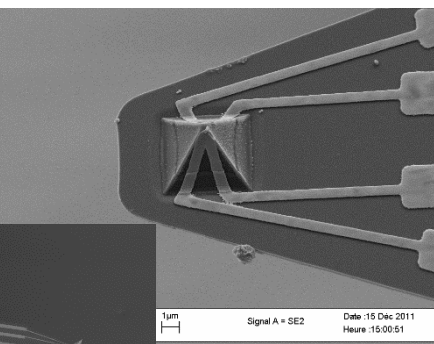
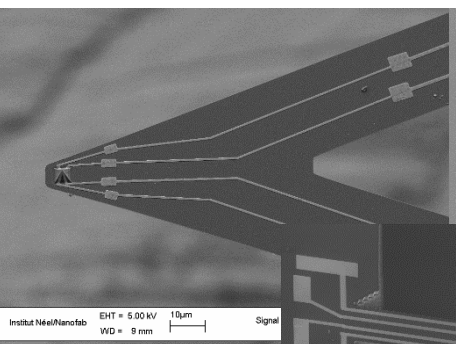
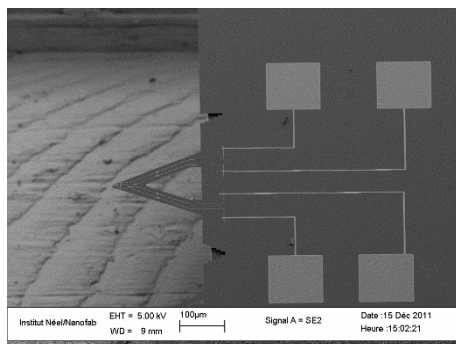


Kelvin probe

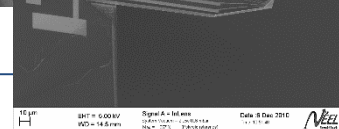


<http://web.eng.gla.ac.uk/groups/nano/afm/TCouplePage.html>

AFM tip: First test
with NbN
thermometer

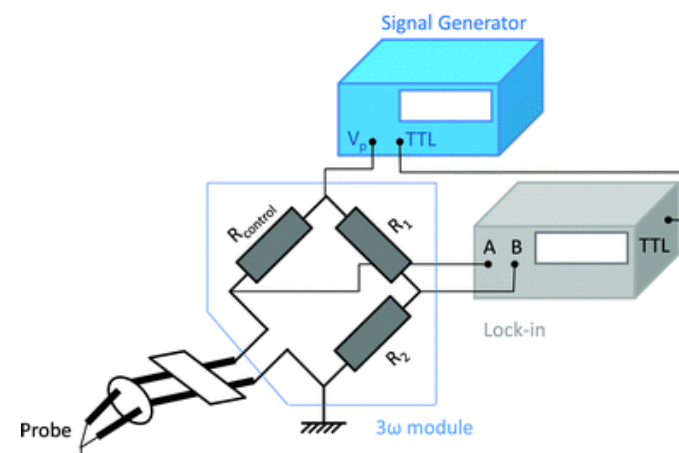
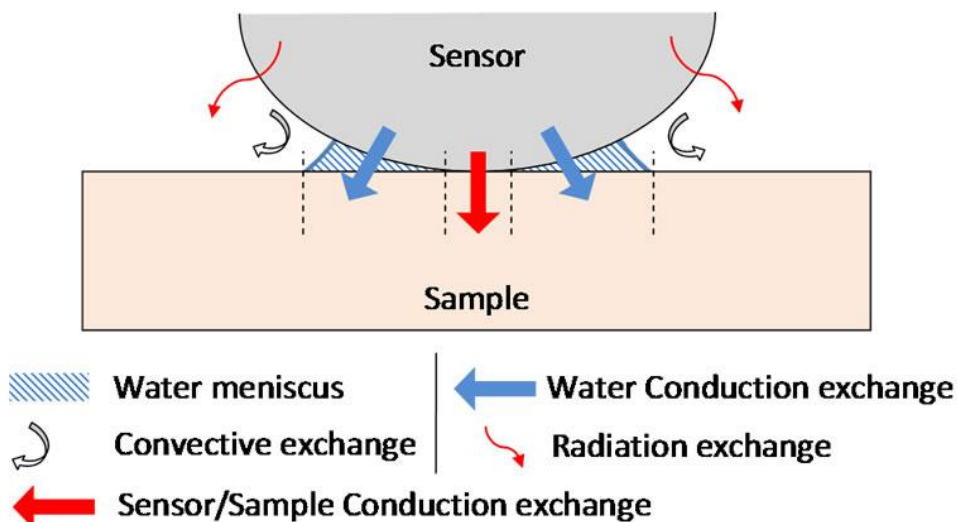
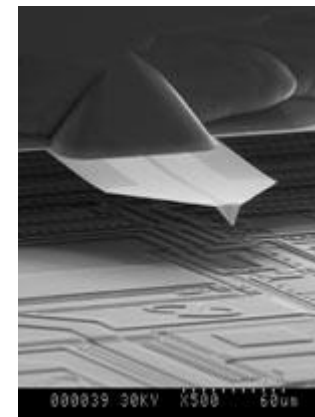


O.B. group , Institut Néel, CNRS



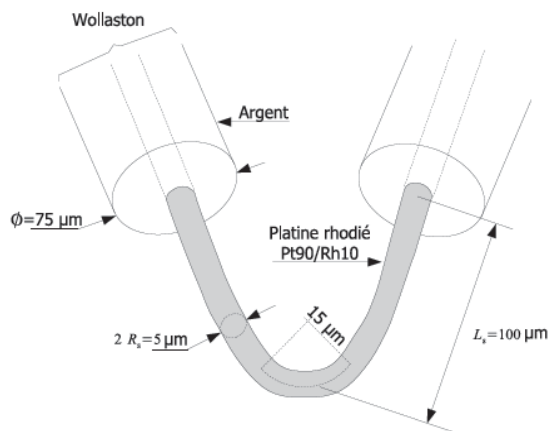
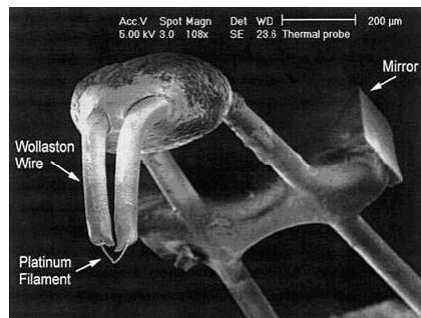
Near field Thermal measurement

- Allows local thermal characterization
- Mapping of surface (temperature or by 3 omega the thermal conductance of the surface)
- Need an elaborated thermal model
 - Radiation
 - Convection if not under vacuum
 - Contribution of the contact
 - Conduction through the tip itself to the heat bath
 - Estimation of the thermal contact

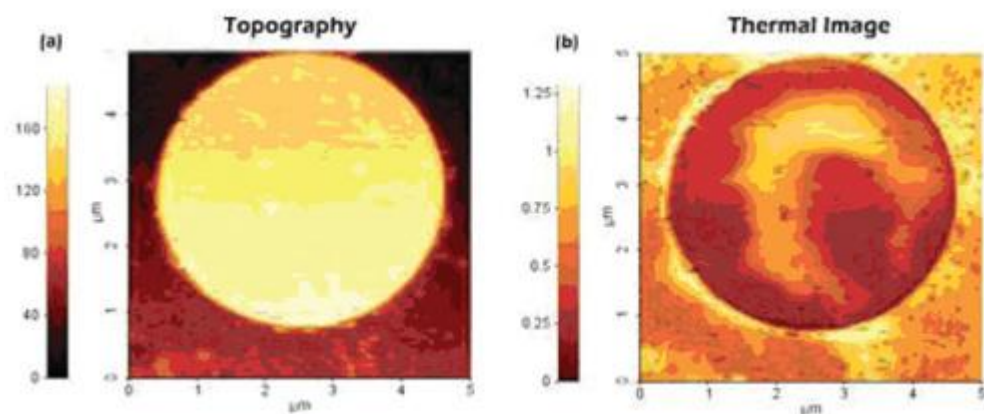
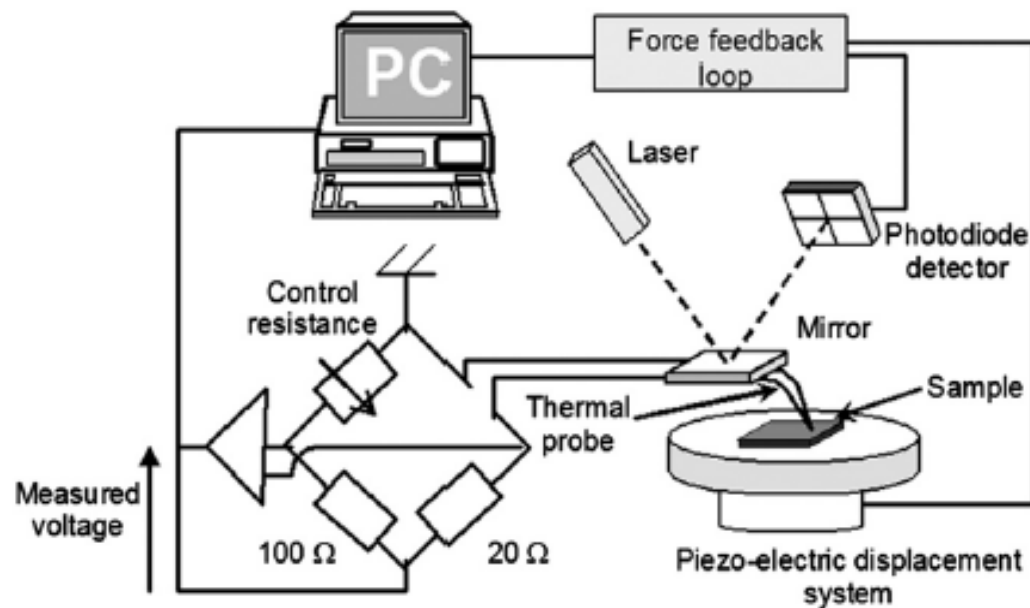


Nanoscale, 2012,4, 4799-4829

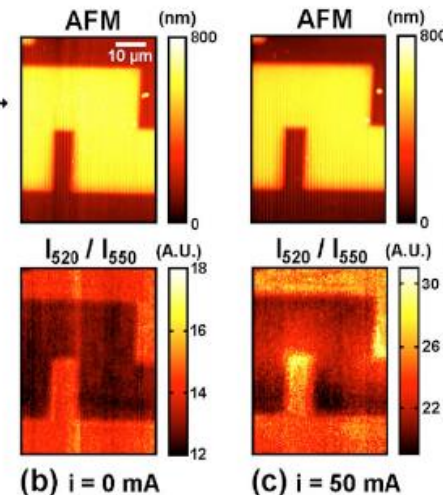
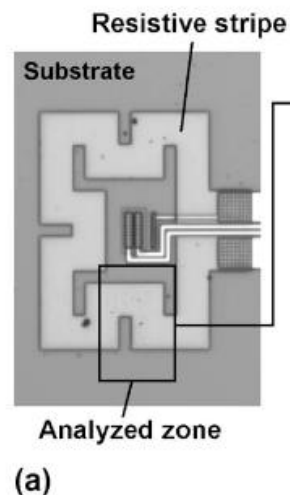
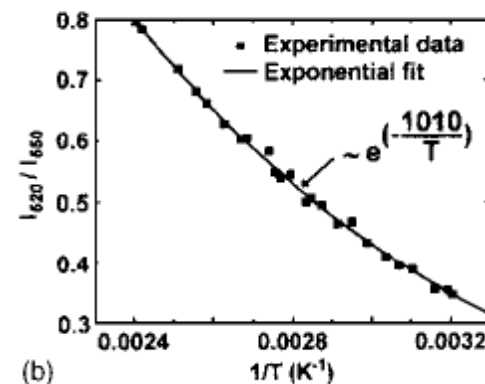
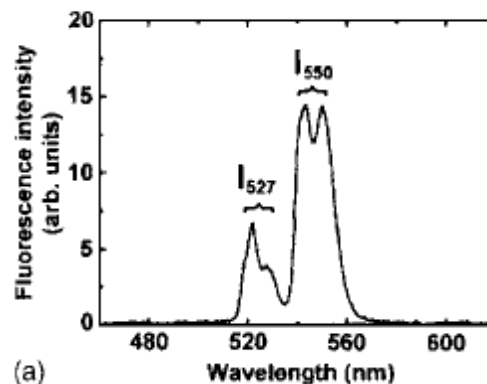
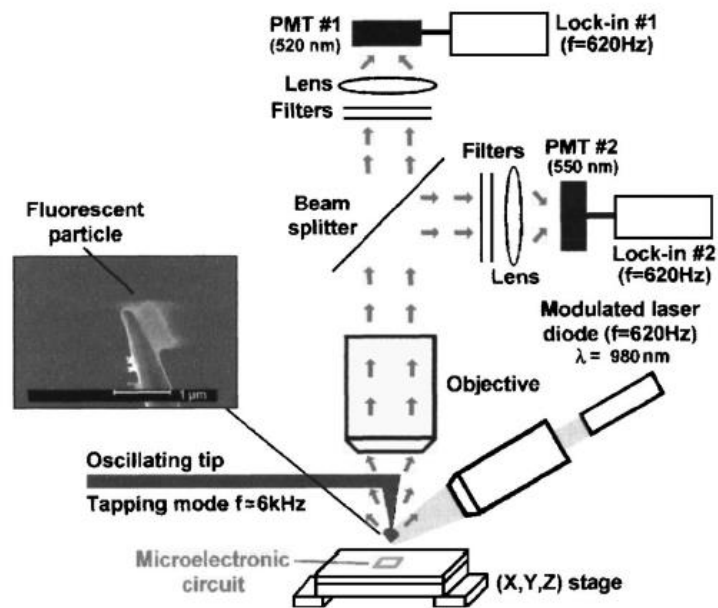
Wollaston tip



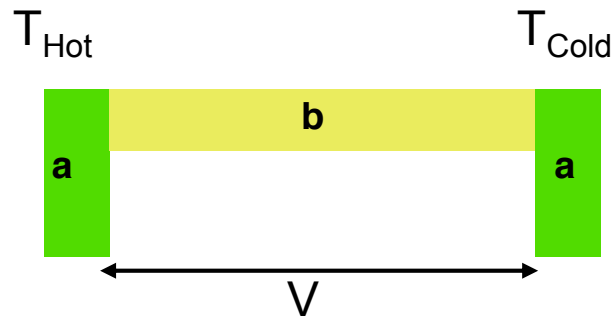
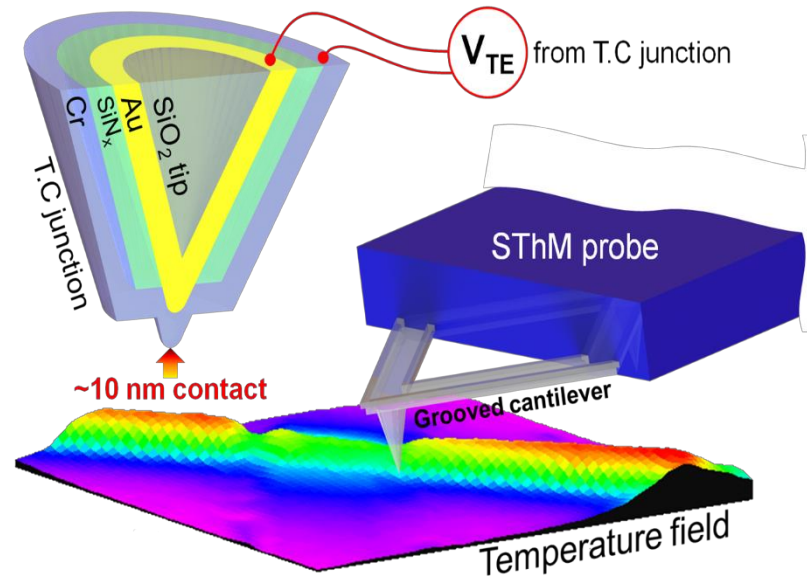
Lefèvre thesis 2004, Ali Assi thesis 2014



- Fluorescence of nanoparticles of Erbium/Ytterbium

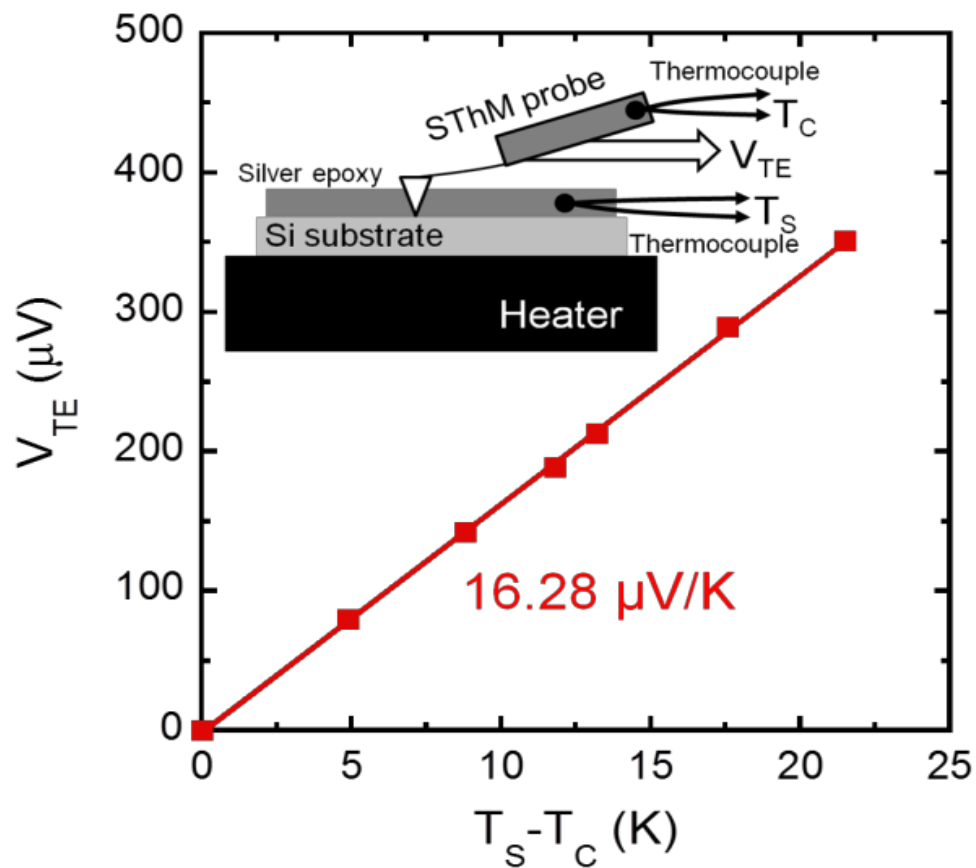


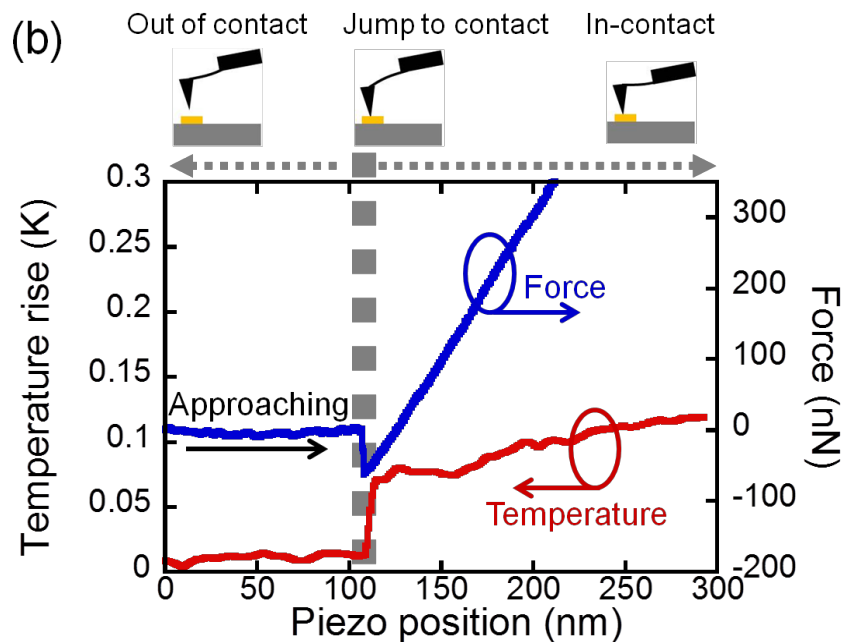
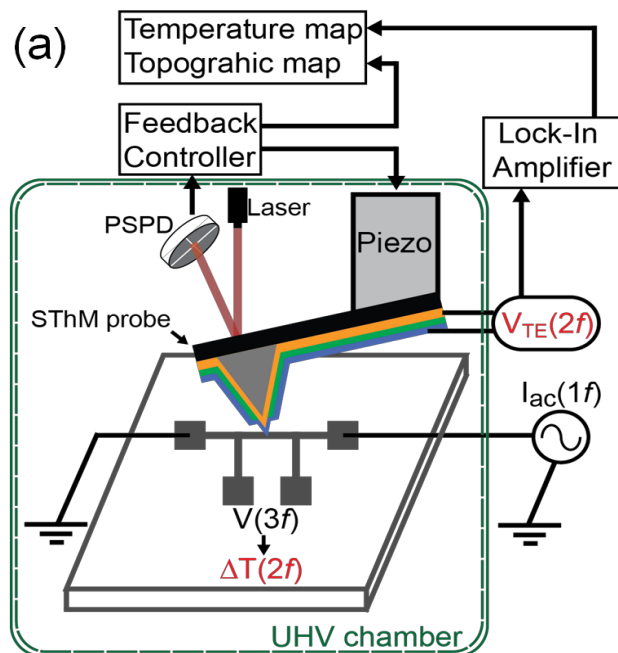
- Couple Au/Cr: $20\mu\text{V/K}$
- Another junction serves as references
- Pramod Reddy Univ. Michigan

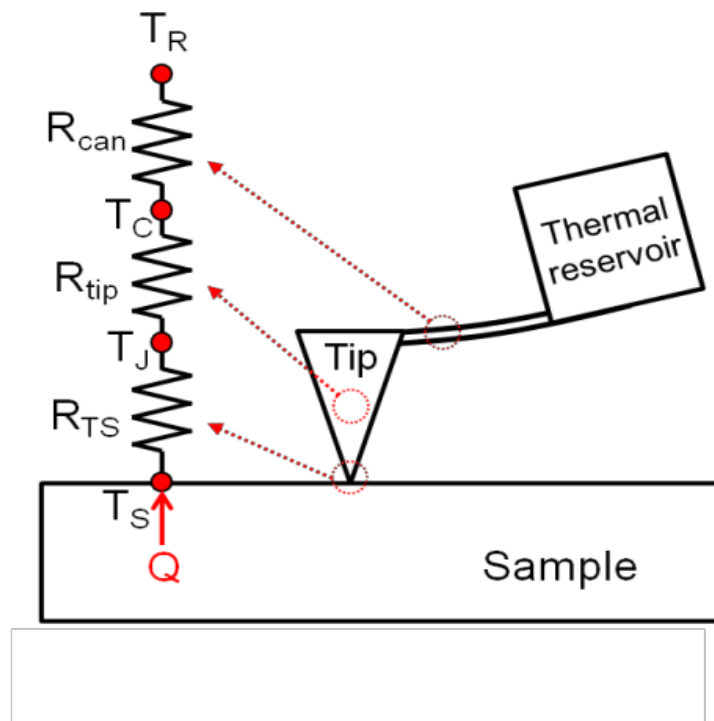


Thermopower, $S = V/\Delta T$

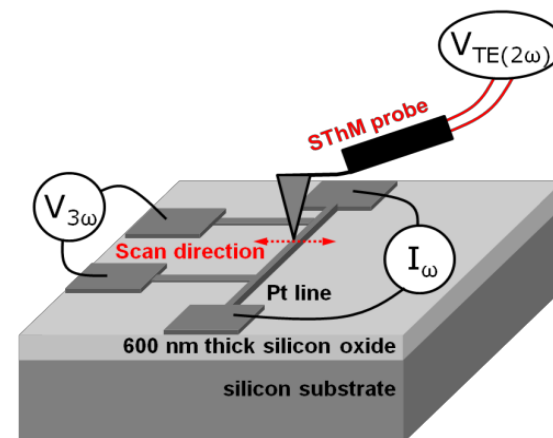
Metal	Seebeck Coefficient ($\mu\text{V/K}$)
Al	-1.66
Au	1.94
Cr	21.8
Ni	-19.5



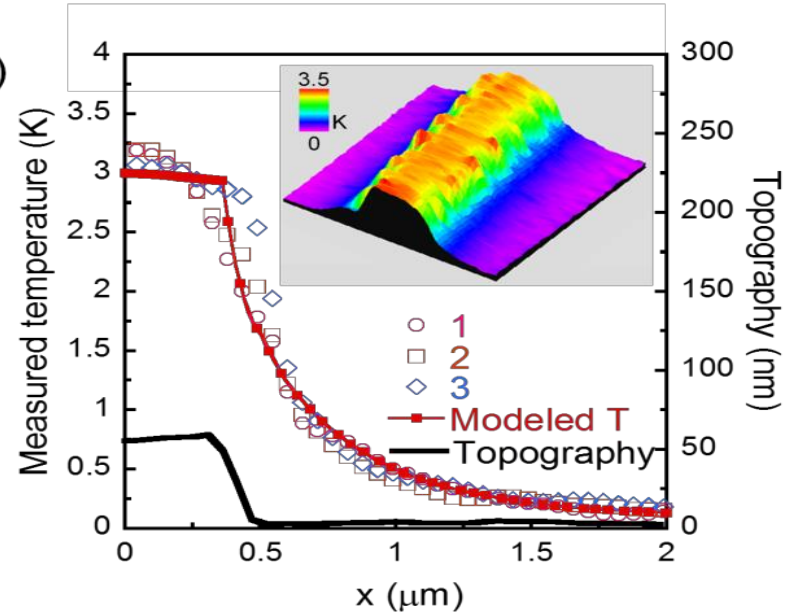




(a)



(b)



Optical methods: Raman thermometry and thermoreflectance

Advantage of contact less method for fragile membranes

- Interaction between light and matter
- Elastic scattering Rayleigh
- What is Raman scattering ? Inelastic scattering
- Brillouin scattering ?

L. N. Brillouin



1889 – 1969

Main achievements

1. Brillouin Scattering (1922)
2. Brillouin Zones (Solids)
3. WKB method (diff. eqs.)
4. Perturbation Theory

C. V. Raman



1888 – 1970

Main achievements

1. Raman effect
28 of February 1928
Nobel Prize (1930)

L. I. Mandelstam



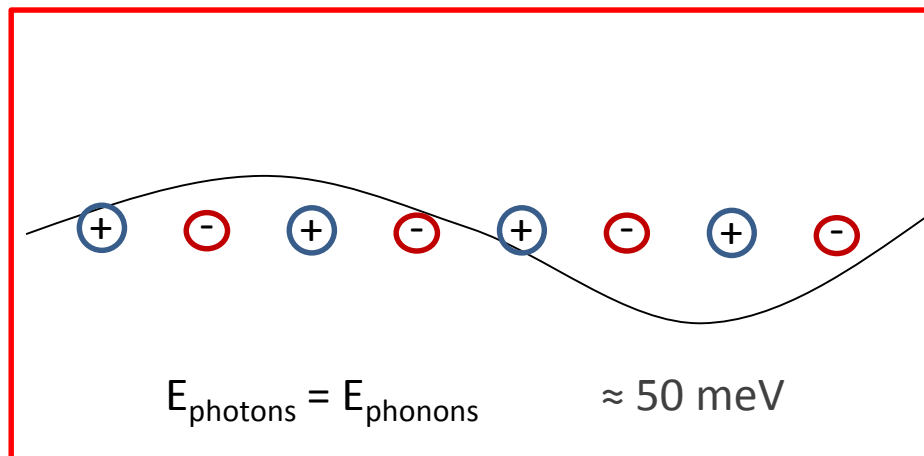
1879 – 1944

Main achievements

1. Inelastic Combinatorial Scattering
21 February 1928

IR ABSORPTION

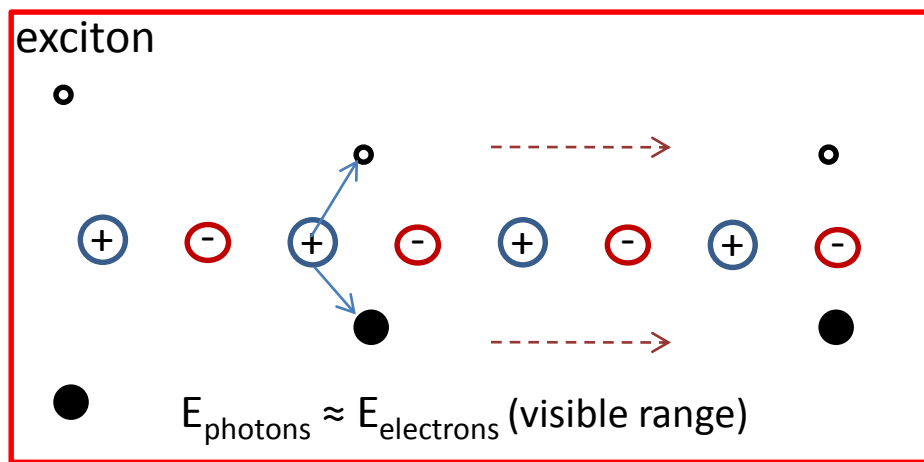
Incident photon
→
 E_i



scattered photon
→

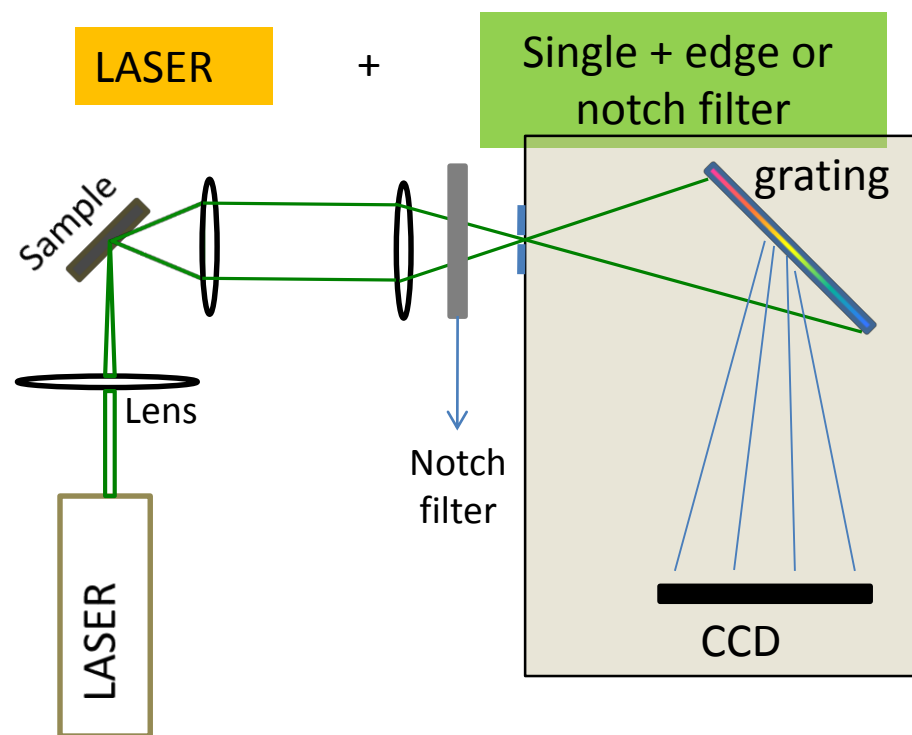
RAMAN EFFECT

Incident photon
→
 E_i

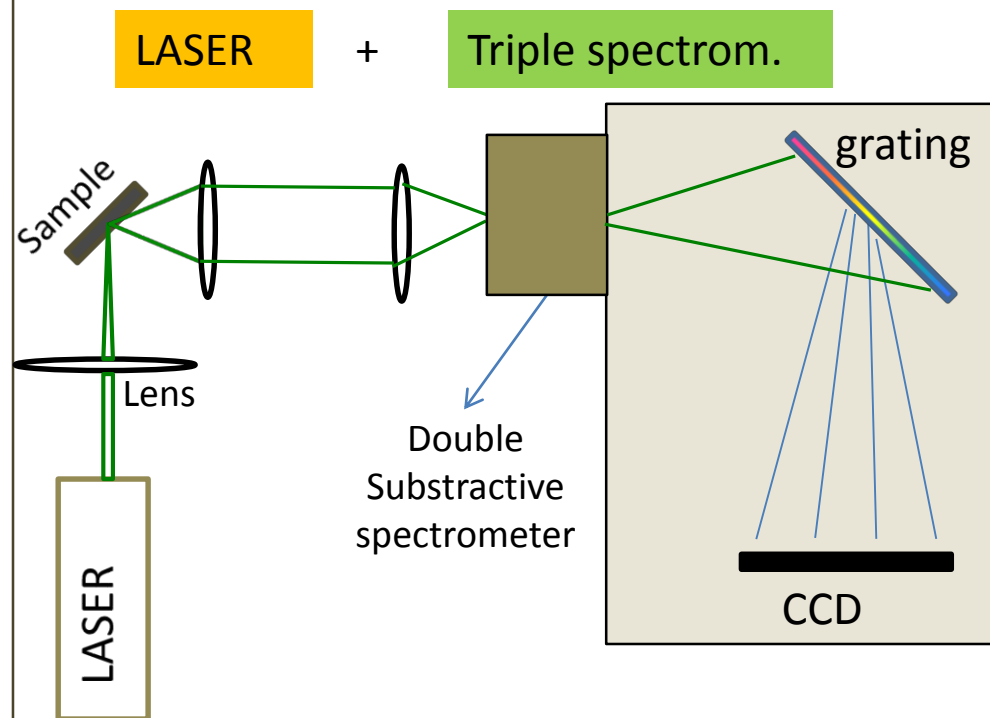


scattered photon
→
 E_f

$$E_i - E_f = E_{\text{phonon}}$$



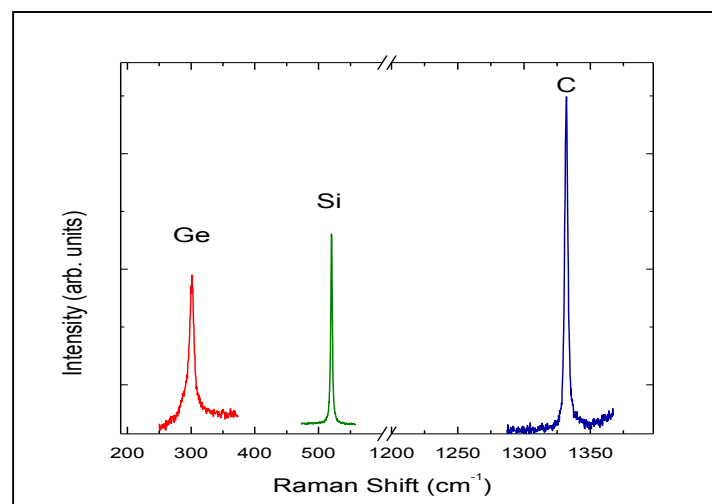
- i) High luminosity.
- ii) Capable to achieve 100 cm^{-1} from the incident laser.
- iii) Suitable for **optical** phonons.
- iv) Usually only Stokes capable.
- v) Extremely *user friendly*.

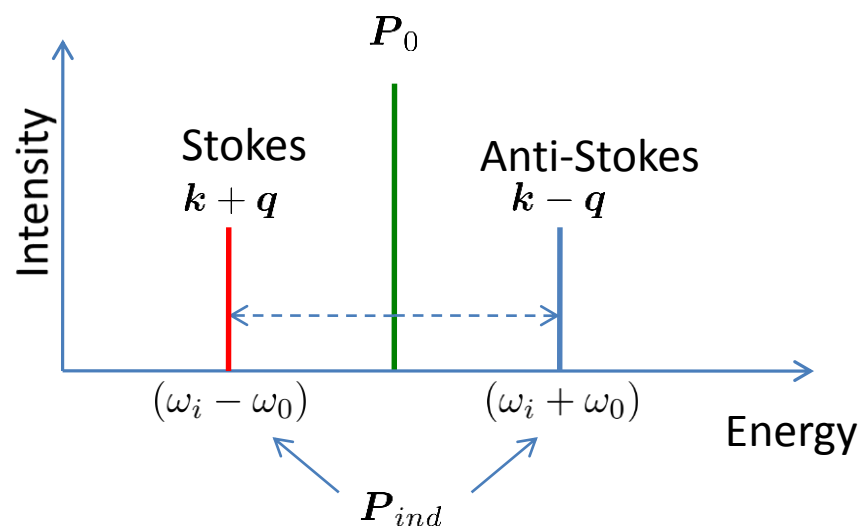
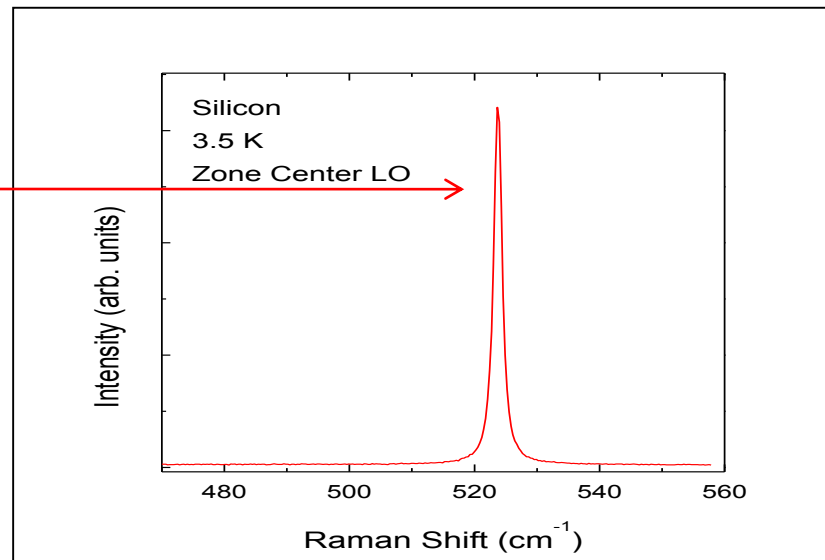
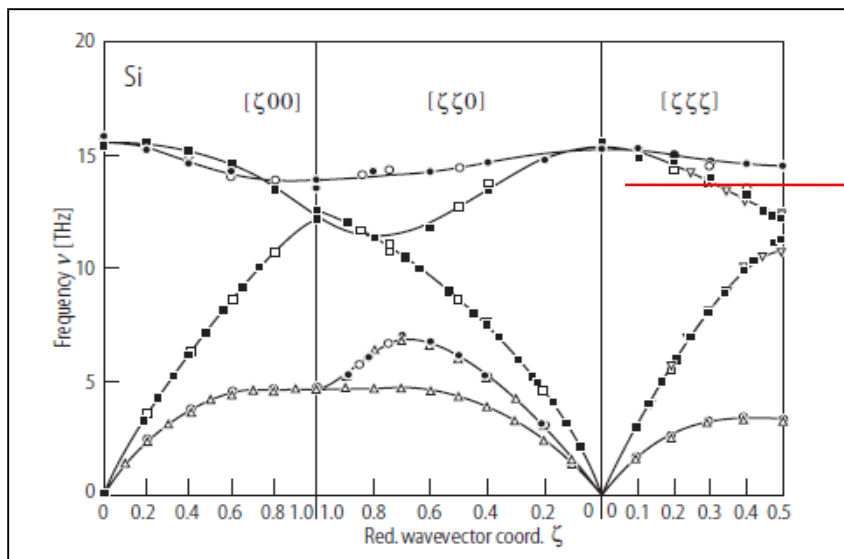


- i) Lower luminosity.
- ii) Capable to achieve 10 cm^{-1} from the incident laser.
- iii) Suitable for **acoustic or optical** phonons.
- iv) Stokes and anti-Stokes

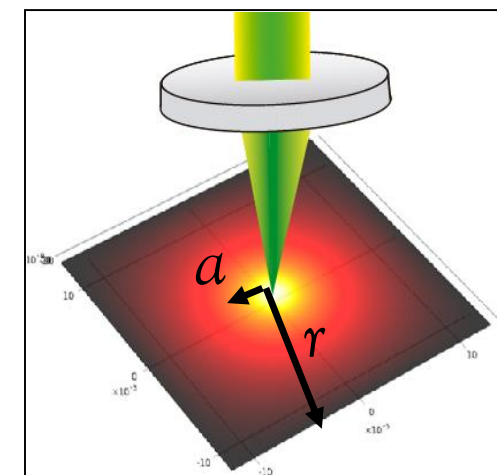
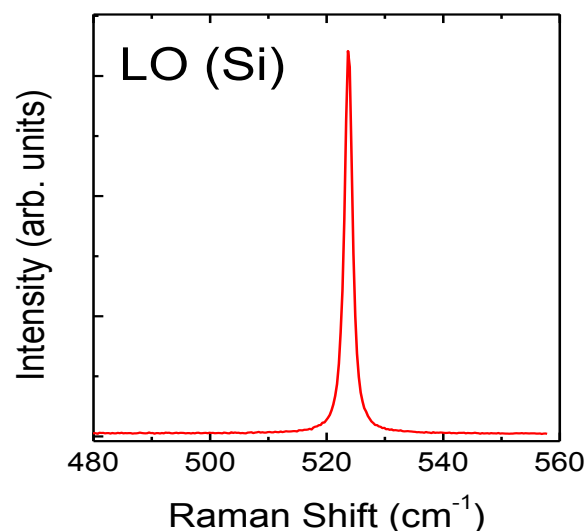
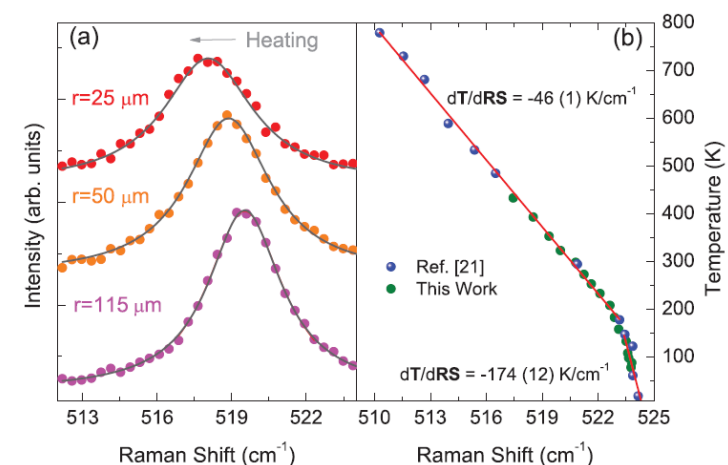
The Raman process takes the following steps:

- 1) The incident photon excites the semiconductor creating an electron-hole pair (exciton).
- 2) The exciton is scattered to a different state through the interaction with a phonon.
- 3) The exciton recombines radiatively with the emission of a photon.



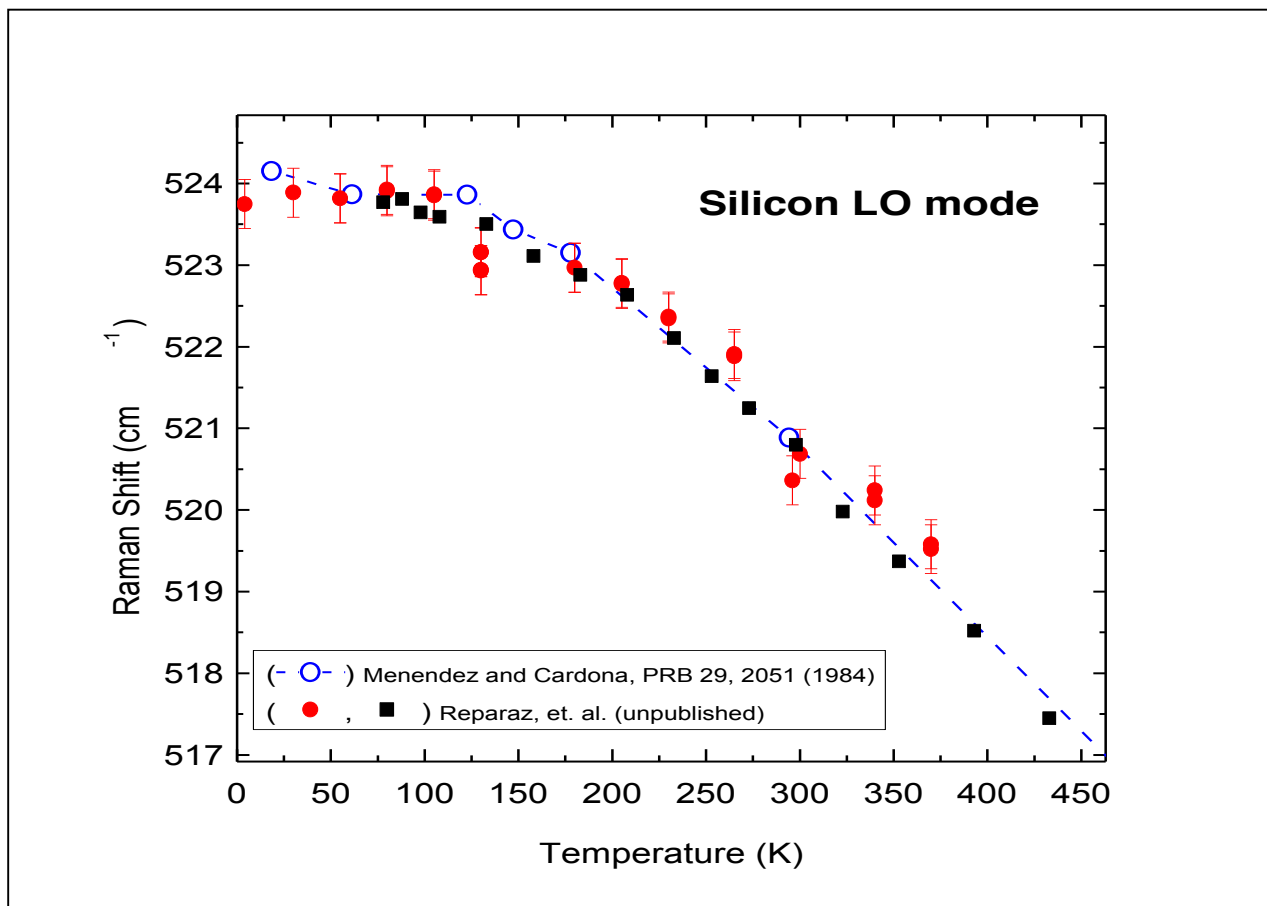


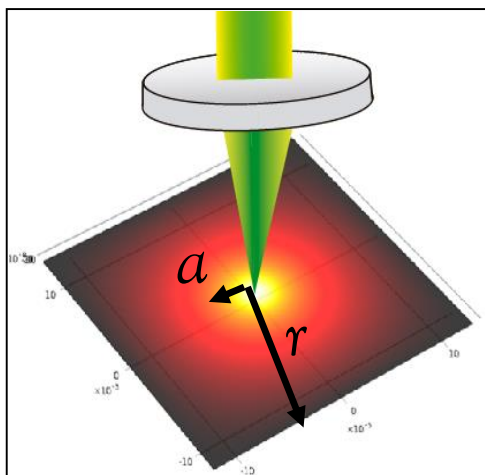
- 1) Accurate definition of the absorption coefficient A by measuring incident (P_i), reflected (P_r) and transmitted (P_t) power
- 2) Measuring the Raman shift of the Si LO phonons as function of the absorbed power
- 3) Calibration of the T dependence of the Si LO Raman mode
- 4) Solving the 2D heat equation using FE simulations with T and P_A as known parameters



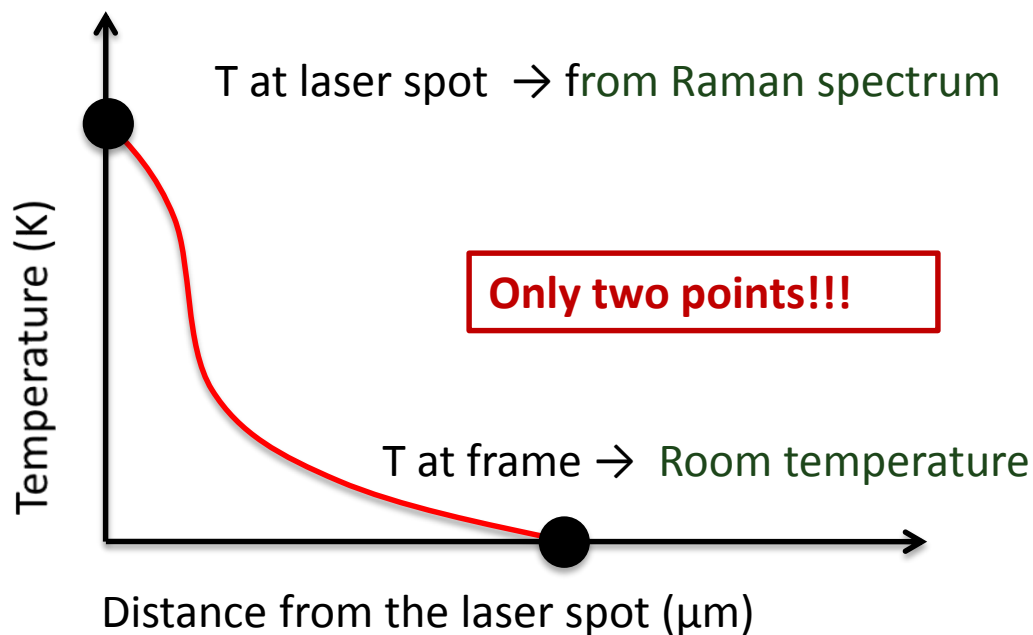
$$\nabla^2 T = \frac{P_{abs}}{\kappa \pi a^2 d} \exp(-r^2/a^2)$$

J. S. Reparaz et al., *Rev. Sci Instrum.* **85**, 034901 (2014)





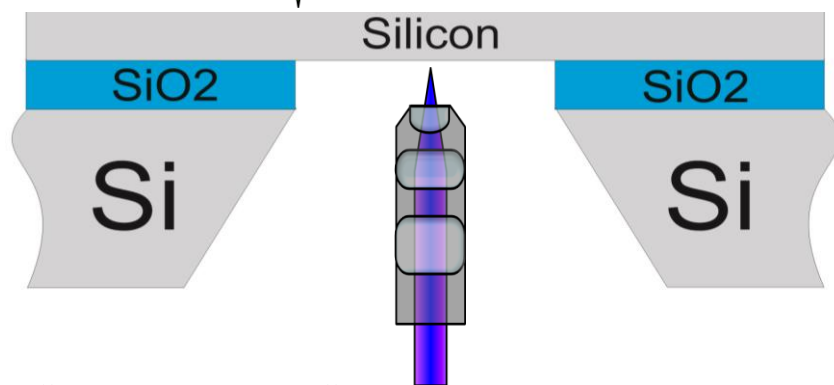
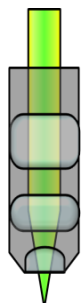
$$\nabla^2 T = \frac{P_{abs}}{\kappa \pi a^2 d} \exp(-r^2/a^2)$$



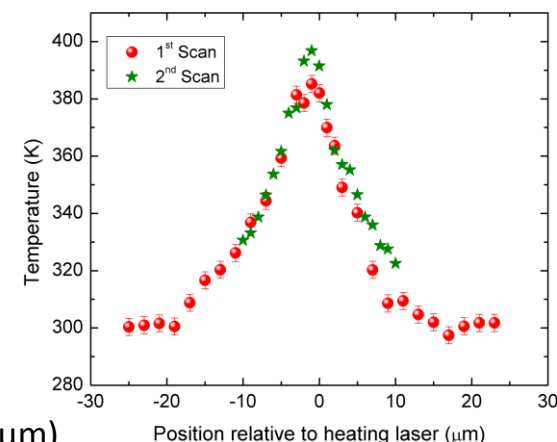
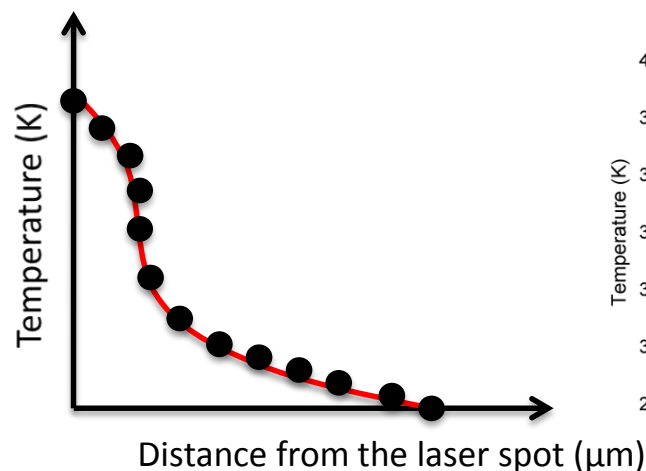
- Temperature profile is highly non-linear
- No information of heat transport regime

"2-LASER RAMAN THERMOMETRY"

Scanning
"Thermometer"
(low power laser probe)

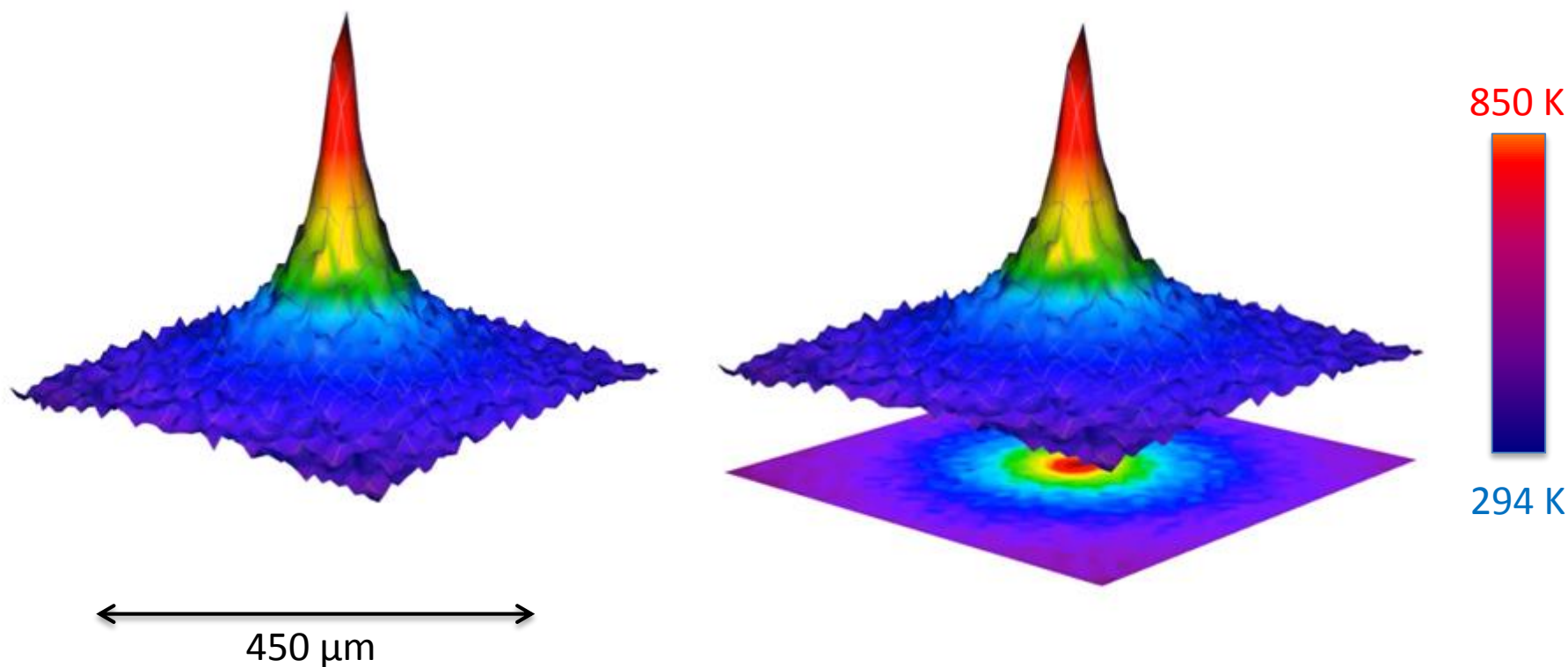


"Heating Laser" (High power fixed laser)



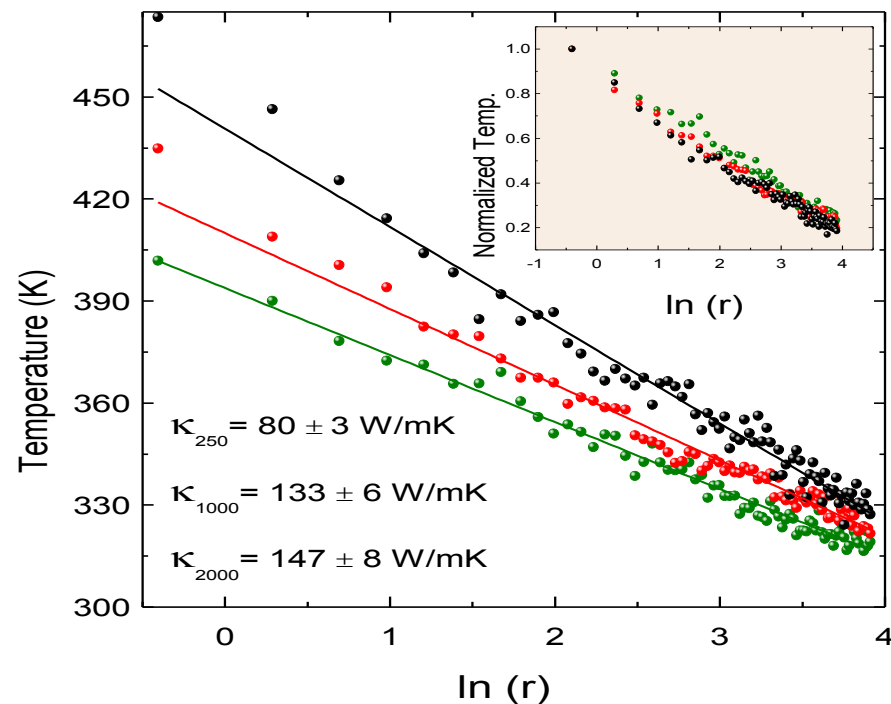
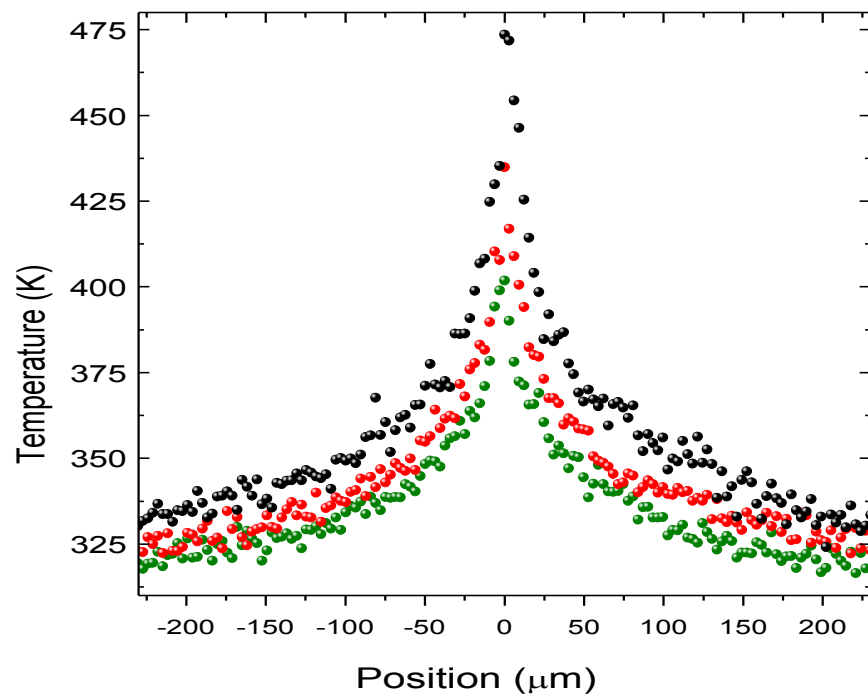
Solution:

Scan of the heat distribution profile by independent heating and probing lasers!



- The temperature distribution on the membrane is accurately probed
- The thermal field is isotropic since Si is isotropic.

J. S. Reparaz *et al.*, Rev. Sci. Instr. 85, 034901 (2014)



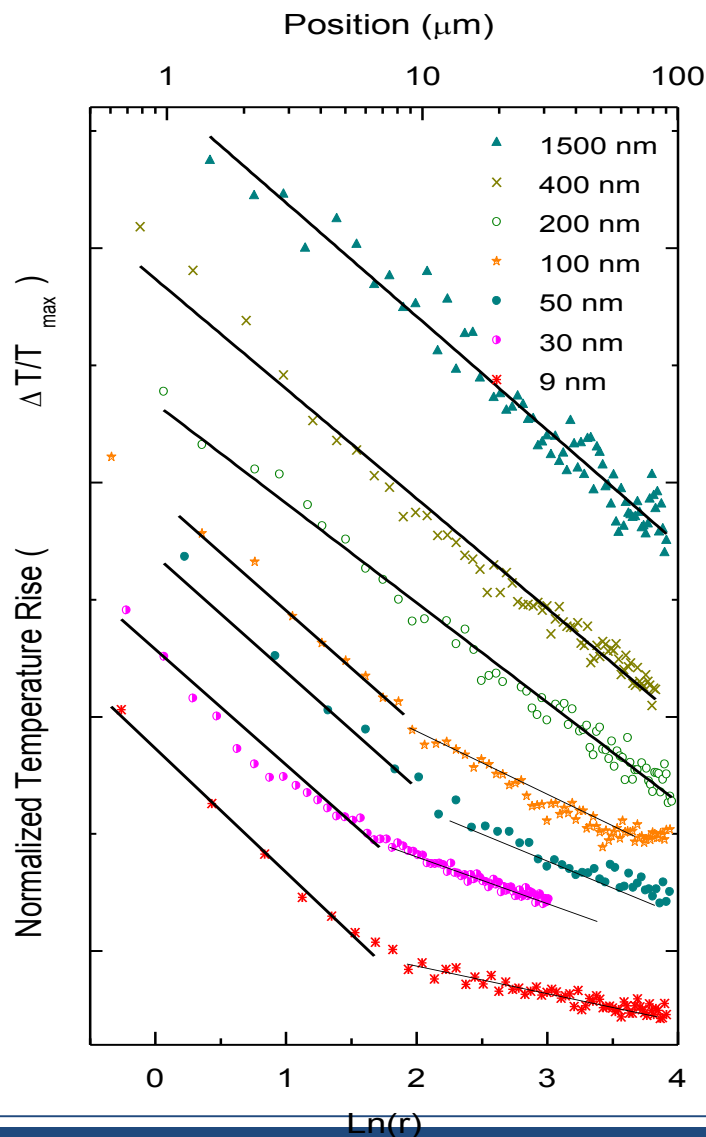
$$Q/A = -\kappa \nabla T$$

$$(A = 2\pi r d)$$

$$T(r) = T_0 - \frac{Q}{2\pi d \kappa_0} \ln(r/r_0) \rightarrow \kappa = \kappa_0$$

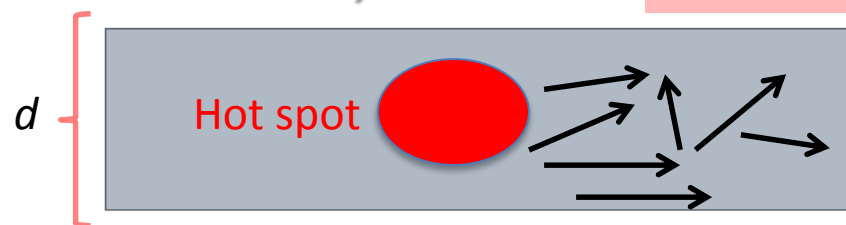
$$T(r) = T_0 \left(\frac{r}{r_0} \right)^{-Q/2\pi d a} \rightarrow \kappa = \frac{a}{T}$$

EXAMPLE 2: SIZE DEPENDENCE OF THERMAL TRANSPORT IN SILICON MEMBRANES

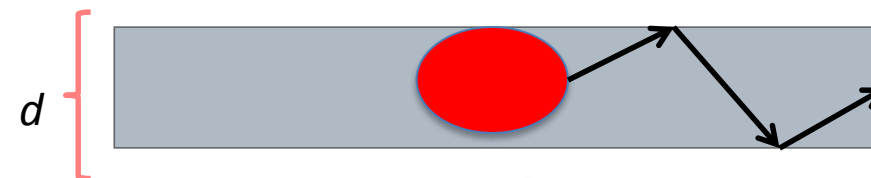


i) $\Lambda \ll d$

Diffusive

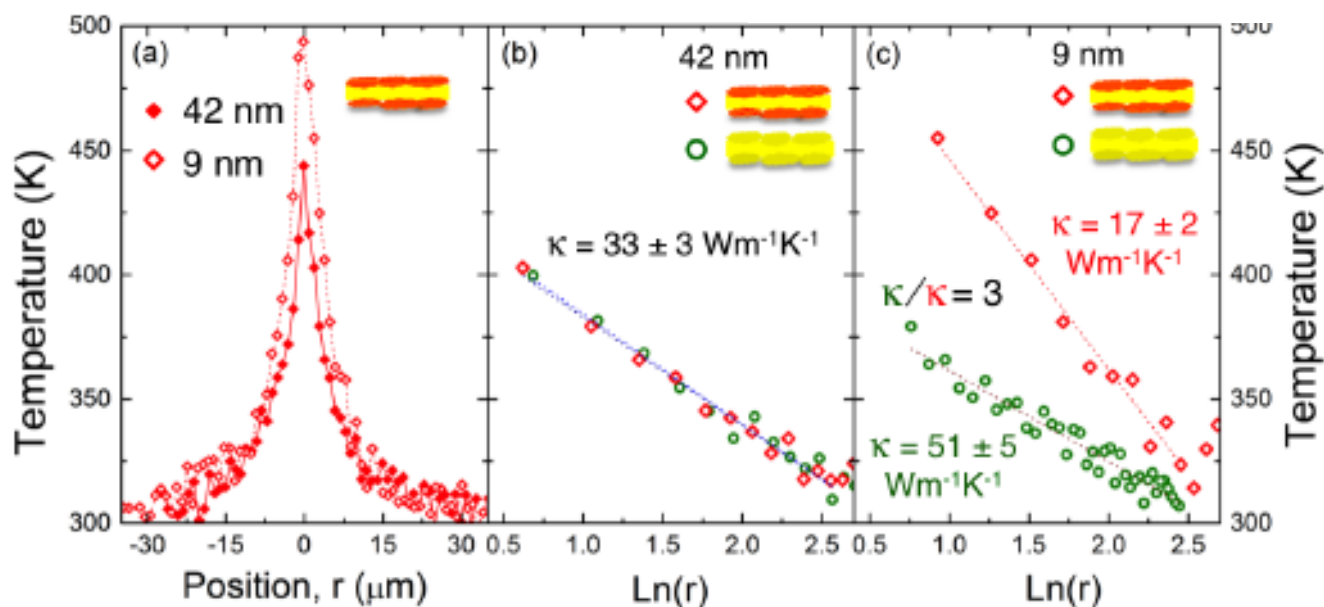
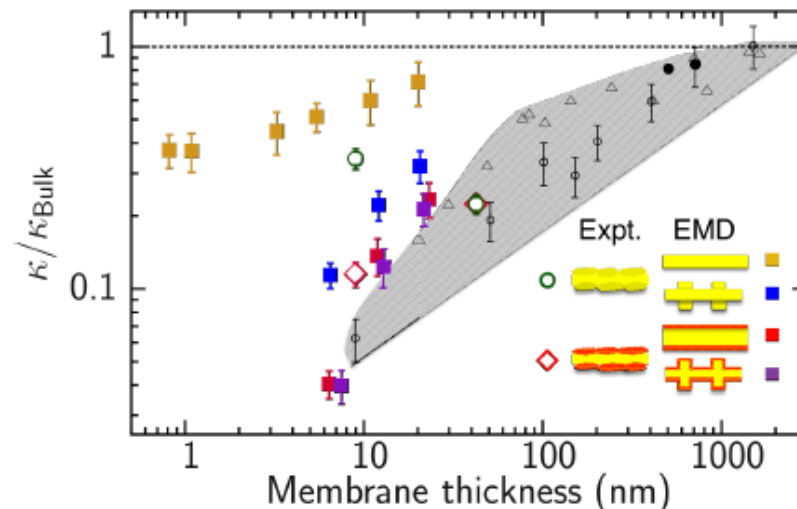
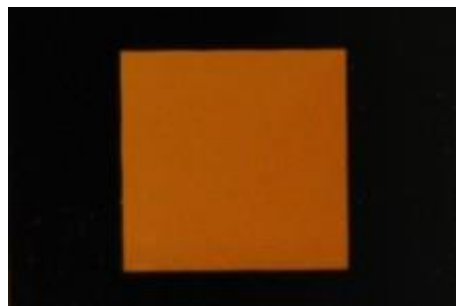


ii) $\Lambda \gg d$



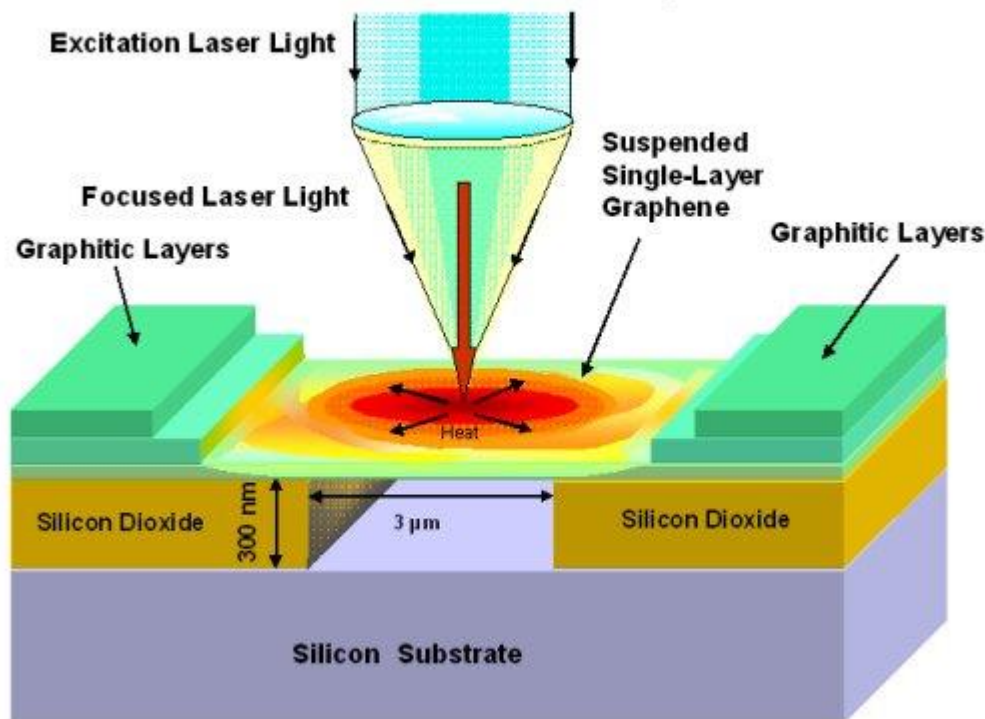
Phonon-Phonon scattering suppression

- Suppression of phonon-phonon scattering due to size effects.
- Role of surface roughness?



Group of Clivia Sotomayor-Torres in ICN (Barcelona, Spain)

Schematic of the Experiment

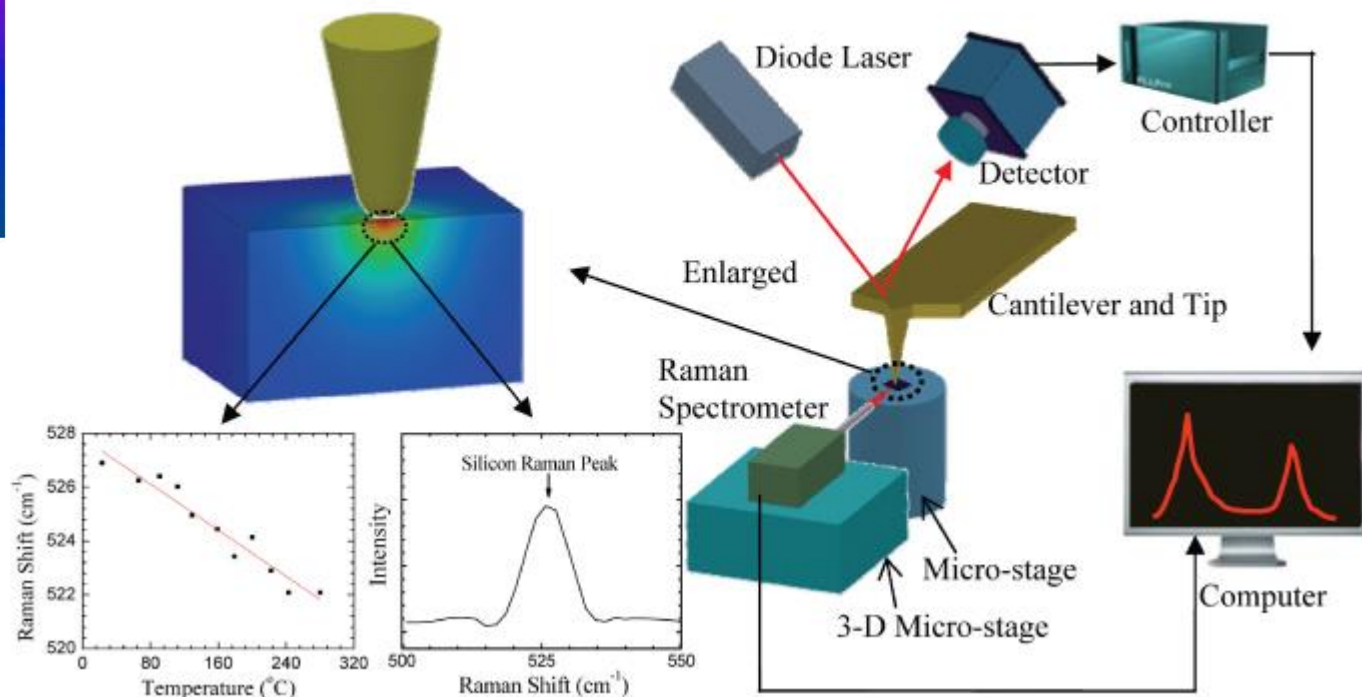
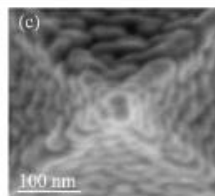
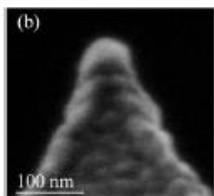
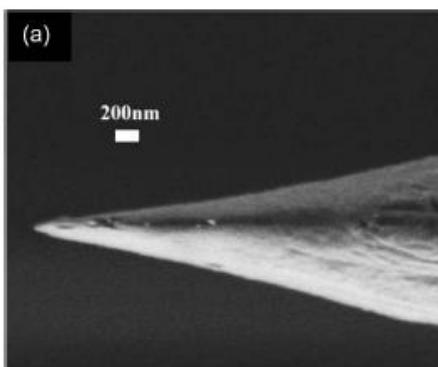
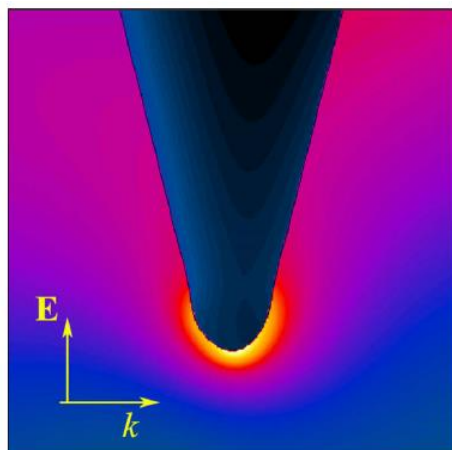


A.A. Balandin et al. APL, Nature Nano., PRB etc...



Graphene sheet

- A way to improve the resolution
- Tip enhance Raman Scattering (TERS)



Nano Reviews, Vol 3 (2012)

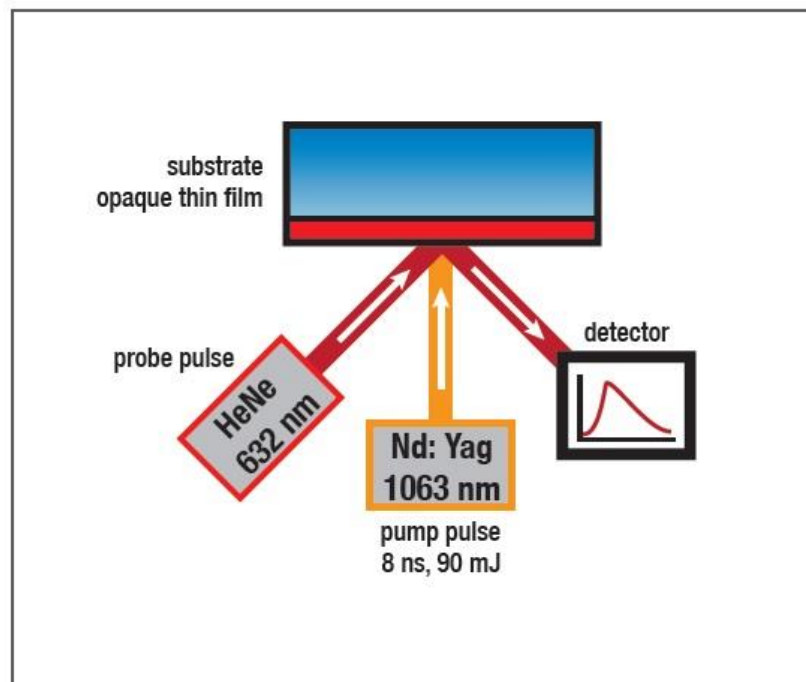
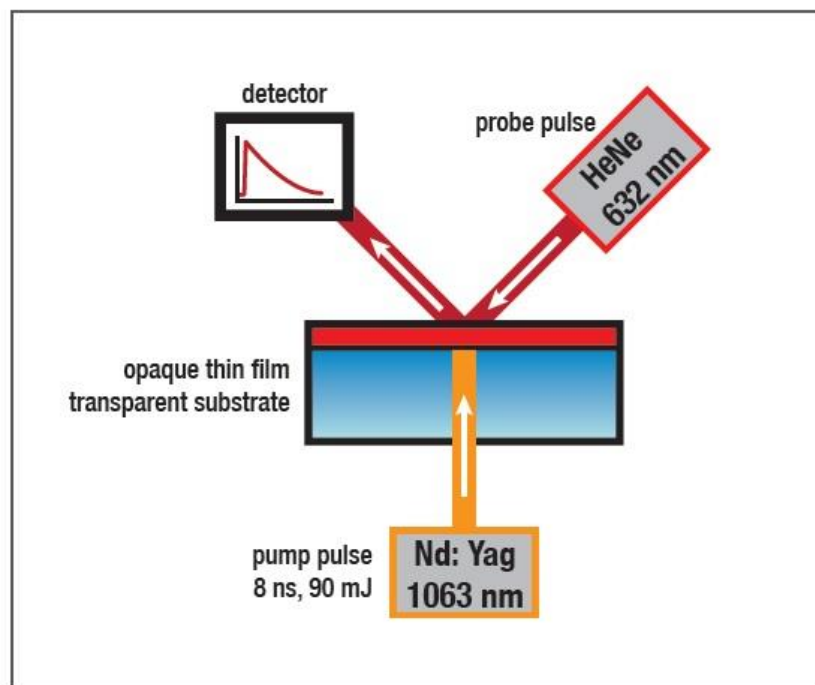
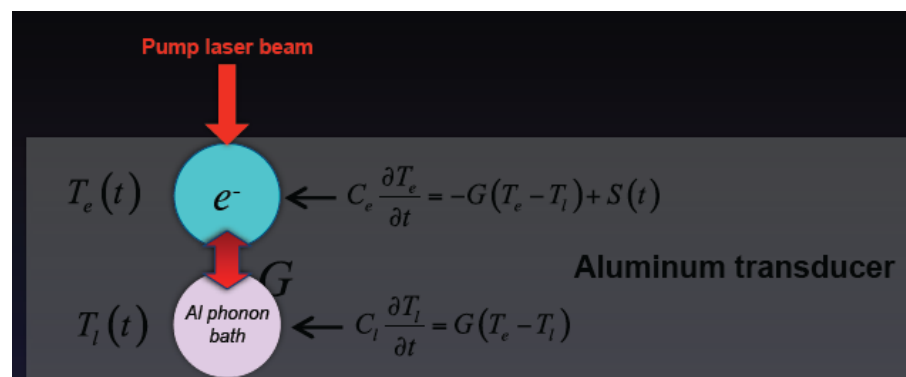
J. Wessel

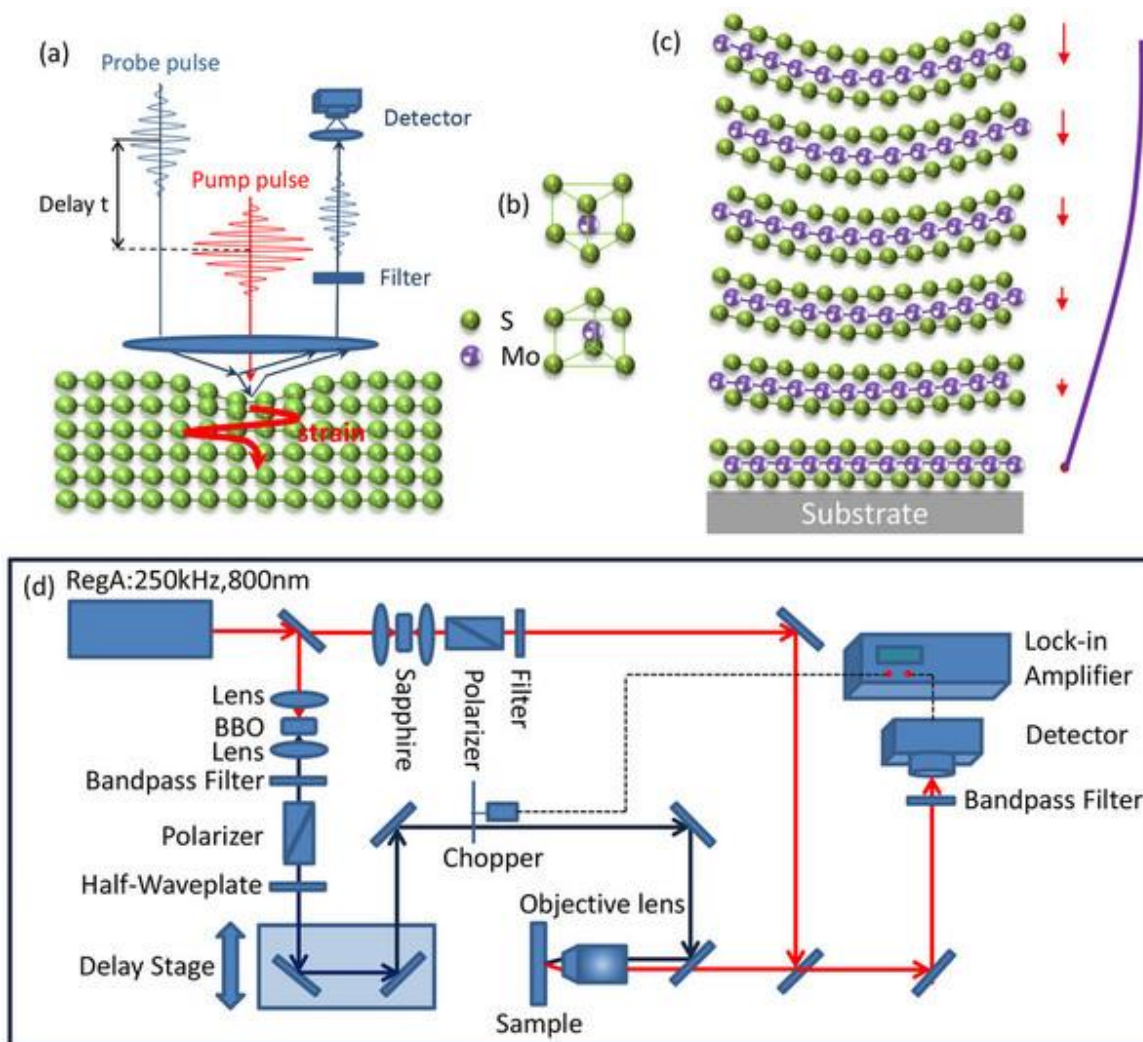
J. Opt. Soc. Am. B **2**, 1538 (1985)

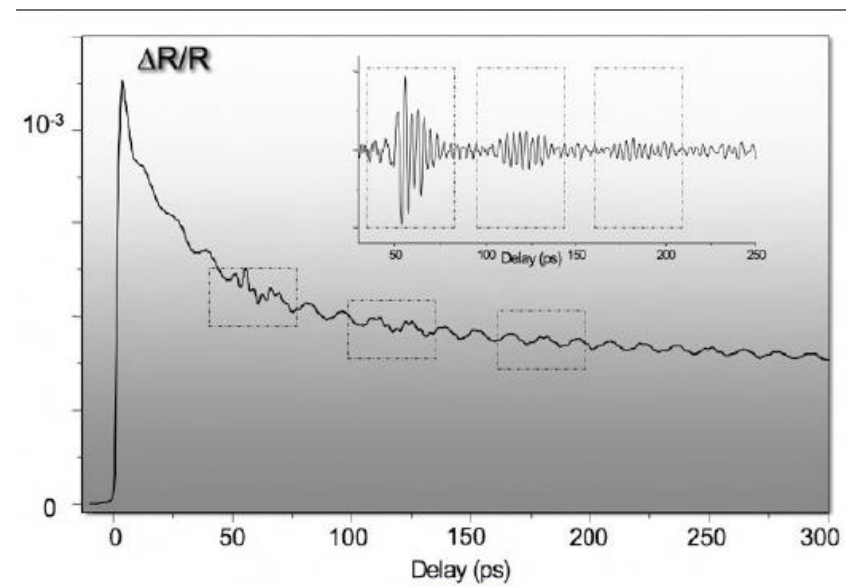
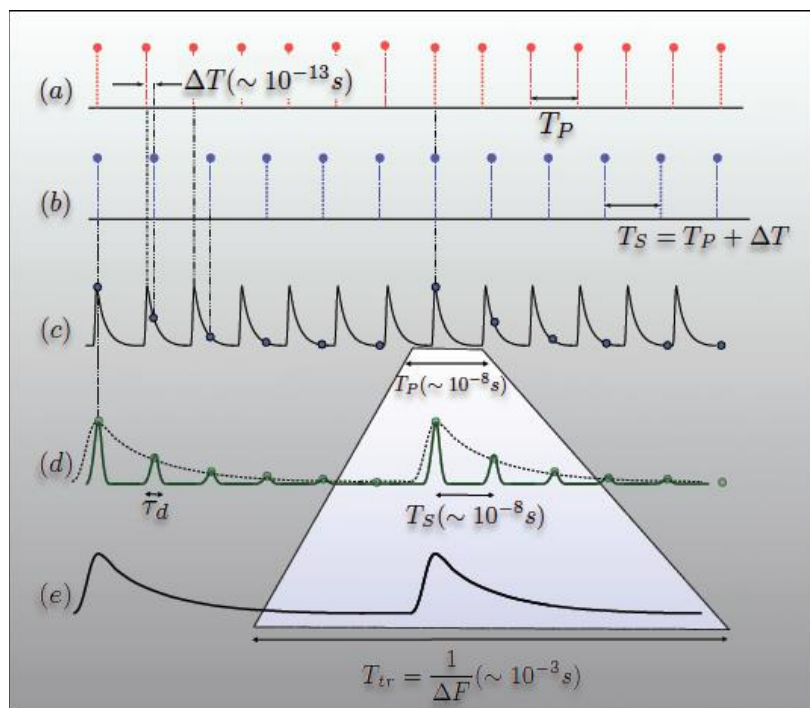
Time domain thermorefectance

Experts: Bernard Perrin (INSP, acoustic properties), Stefan Dilhaire and co. w (thermal properties, Univ. Bordeaux, LOMA), David Cahill (thermal properties, Univ. Illinois at Urbana Champ.),

- Thermometry: temperature variation of the coefficient of reflection of the materials
- Aluminium: $\Delta R/R = 10^{-5}$







Performances Picosecond Thermoreflectance

- Temperature sensitivity **$100 \mu\text{K}$**
- Thermal Lateral resolution **$1 \mu\text{m}$**
- Time resolution **100 fs**

Taken from Stefan Dilhaire (LOMA)

- Accuracy is typically limited to several percent due to uncertainties in the many experimental TDTR parameters
 - Metal film thickness
 - Heat capacity of the sample if film is thick
- But many experimental advantages
 - No need for electrical insulation
 - Can separate the metal/film interface thermal conductance from the thermal conductivity
 - High spatial resolution
 - Only need optical access: high pressures, high magnetic fields, high temperatures

See papers by Cahill Univ. Illinois Urb. Champ.

Conclusions

Measurement at the nanoscale : comparison and numbers

	Work T	ΔT	Has to be suspended	Thin films	membrane	nanowire	$1/x \, dX/dT$ at RT	ΔK	$\Delta E/\Delta P$	$\Delta K/K$
Differential	0K-400K	<1mK	Yes	No	Yes	Yes	10^{-2}	nW/K	pW	0.1/1%
3 omega 1D/2D	0K-400K	<1mK	Yes	Yes	Yes	Yes	10^{-2}	pW/K	fW	0.1%
3 omega Semi-infinite	0K-400K	<10mK	No	Yes	No	Yes/No	10^{-2}	nW/K	nW	1 %
SThM resis.	RT	Few K	/	Yes	?	Y/N	10^{-3}	μ W/K	?	1/10%
Fluoresc. SThM	RT	1K	/	Yes	Yes	Yes	10^{-5}	μ W/K	?	10 %
Bimetal	RT	<1mK	Yes	No	No	Yes	10^{-3}	10 nW/K	pW	10 %
Raman	100k<T	20K	Yes	?	Yes	No	10^{-5}	??	??	??
TDTR	4K-300K		Y/N	Yes	Yes	No	10^{-5}	??	??	??

Thermal conductivity of single biological cells and relation with cell viability

Byoung Kyoo Park,¹ Namwoo Yi,¹ Jaesung Park,² and Dongsik Kim^{1,a)}

¹Department of Mechanical Engineering, POSTECH, Pohang, 790-784, South Korea

²School of Interdisciplinary Bioscience and Bioengineering, POSTECH, Pohang, 790-784, South Korea

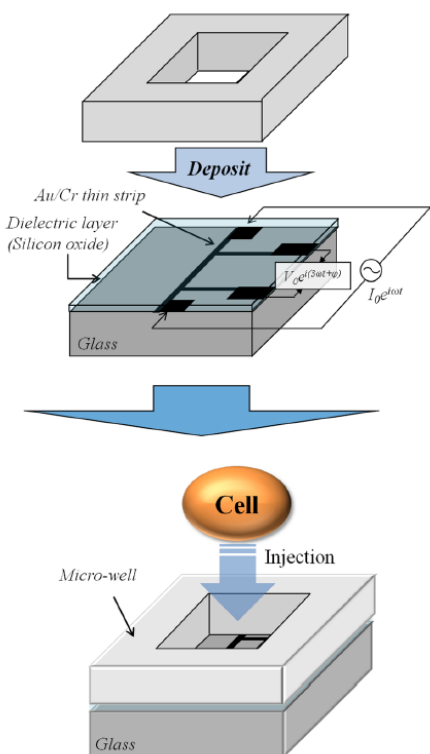


FIG. 1. Schematic design of the instrument.

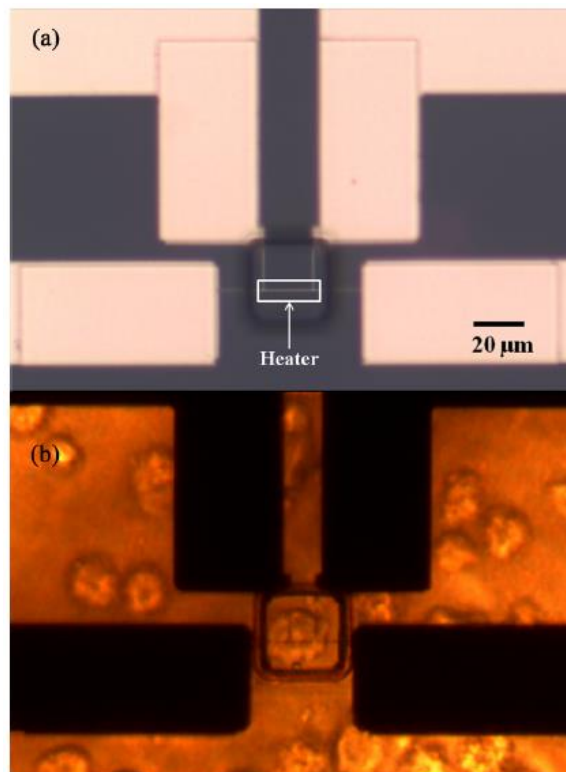


FIG. 2. Photographs of deposited NIH-3T3 J2 cell on sensor surface.

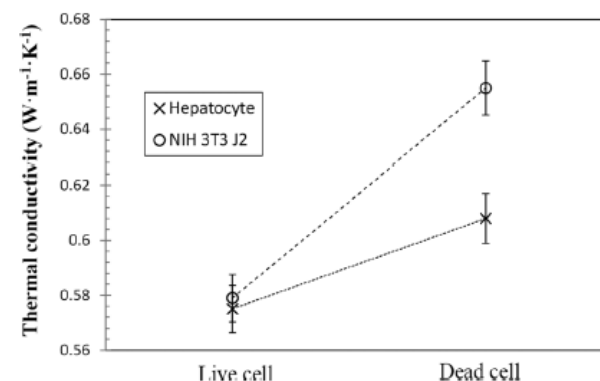


FIG. 4. Thermal conductivities of live and dead cells.

The thermal transport is strongly affected by the denaturation of the DNA strands

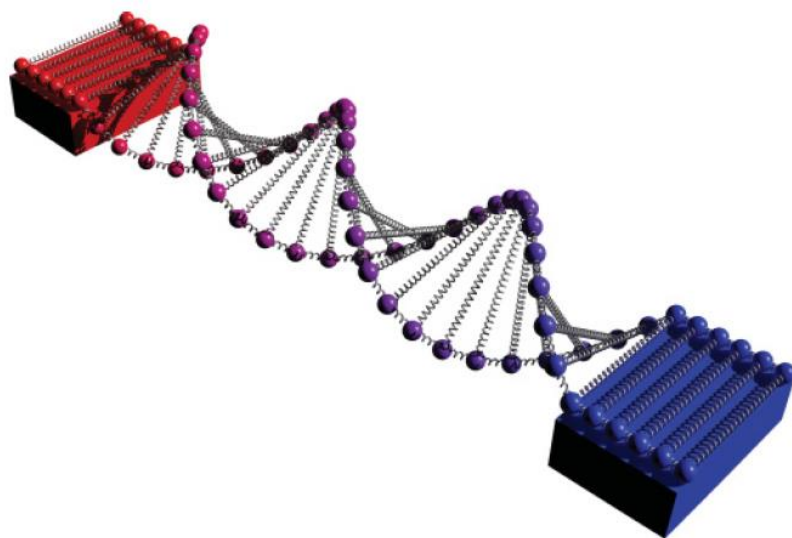
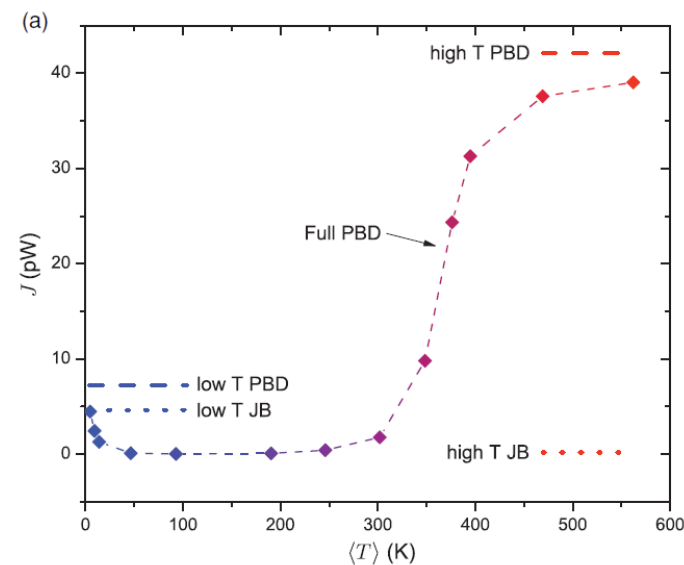
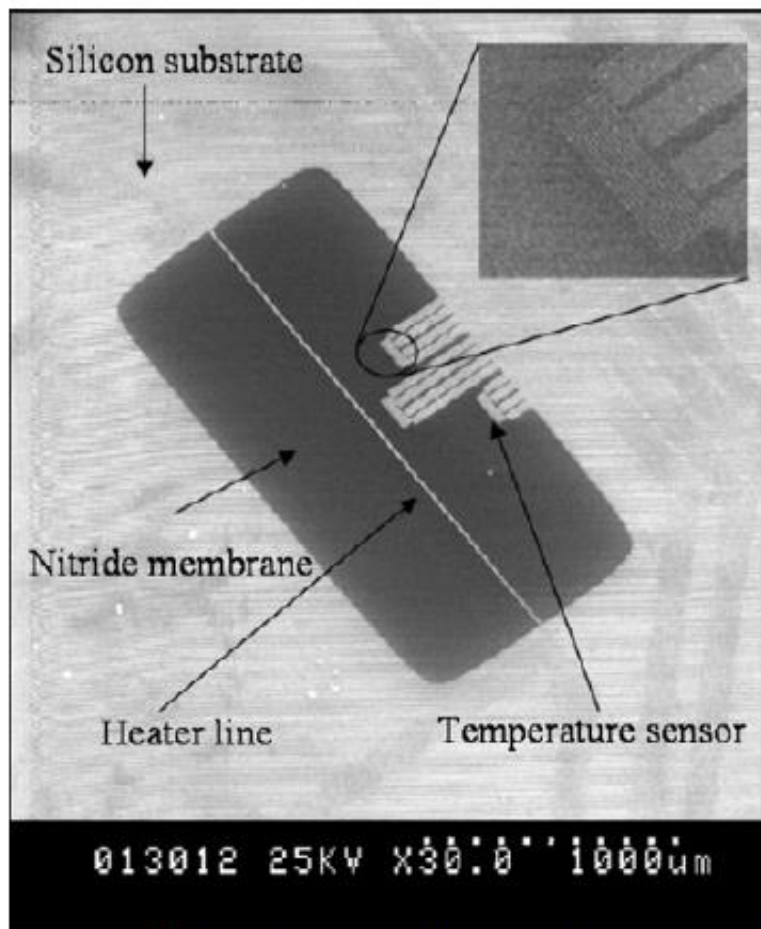


FIG. 1. (Color online) Schematic of DNA between two heat reservoirs that probe its structure via an energy current.





- Technique used to duplicated DNA

Figure 5. SEM of a microheater device used for studying the effect of thermal gradients on nerve cells [Jain, *et al.* (2009)].



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Nanometer-scale heat-conductivity measurements on biological samples

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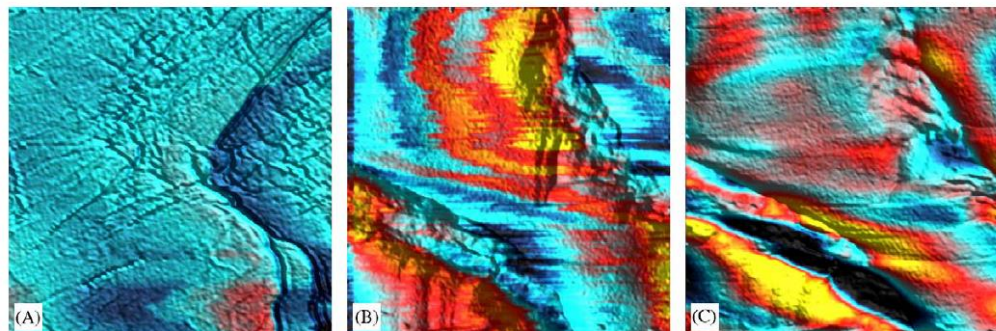


Fig. 4. Image A depicts a 2.2- μm scan on a human hair that was bleached and pretreated with strong detergents. The color texture corresponds to variations in the heat flux of about 100 nW from dark blue to violet, with decreasing heat conductance towards violet. Images B and C depict 8.8 μm scans of an untreated hair. The texture in B shows heat flux differences whereas in C it shows differences in friction. All pictures were made with the cantilever at 300 °C.

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